

# XMC4300

Microcontroller Series  
for Industrial Applications

XMC4000 Family

ARM<sup>®</sup> Cortex<sup>®</sup>-M4  
32-bit processor core

Data Sheet

V1.2 2023-04

Microcontrollers

**Edition 2023-04**

**Published by  
Infineon Technologies AG  
81726 Munich, Germany**

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## XMC4300 Data Sheet

### Revision History: V1.2 2023-04

V1.1 2018-09

V1.0 2016-02

| Page         | Subjects                                   |
|--------------|--------------------------------------------|
| V1.2 2023-04 |                                            |
| <b>10</b>    | Updated number of breakpoints from 8 to 6. |
| <b>99</b>    | Added PG-LQFP-100-29 details in Table 60.  |
| <b>102</b>   | Added package diagram: PG-LQFP-100-29.     |

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## About this Document

This Data Sheet is addressed to embedded hardware and software developers. It provides the reader with detailed descriptions about the ordering designations, available features, electrical and physical characteristics of the XMC4[12]00 series devices.

The document describes the characteristics of a superset of the XMC4[12]00 series devices. For simplicity, the various device types are referred to by the collective term XMC4[12]00 throughout this manual.

### XMC4000 Family User Documentation

The set of user documentation includes:

- **Reference Manual**
  - describes the functionality of the superset of devices.
- **Data Sheets**
  - list the complete ordering designations, available features and electrical characteristics of derivative devices.
- **Errata Sheets**
  - list deviations from the specifications given in the related Reference Manual or Data Sheets. Errata Sheets are provided for the superset of devices.

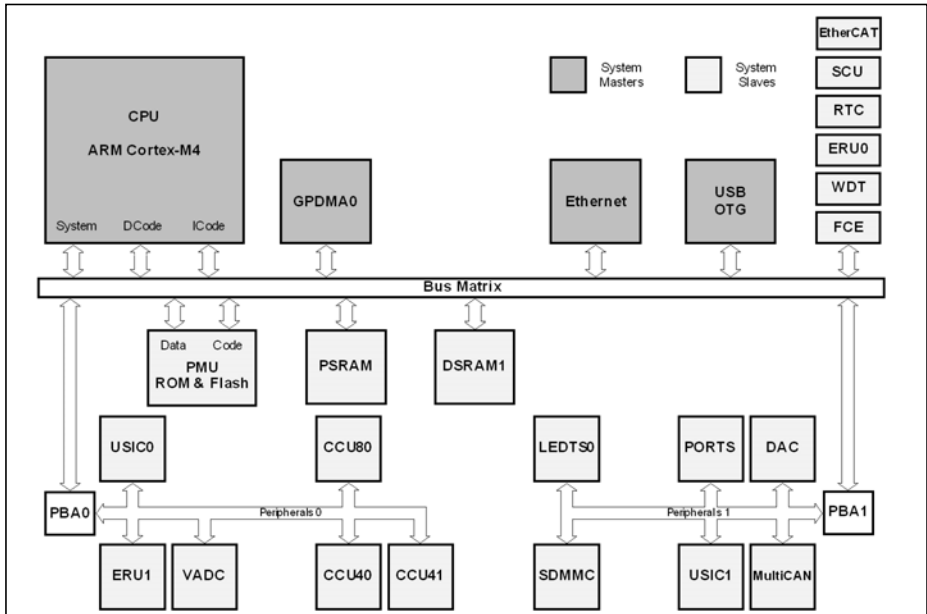
***Attention: Please consult all parts of the documentation set to attain consolidated knowledge about your device.***

Application related guidance is provided by **Users Guides** and **Application Notes**.

Please refer to <http://www.infineon.com/xmc4000> to get access to the latest versions of those documents.

## 1 Summary of Features

The XMC4300 devices are members of the XMC4000 Family of microcontrollers based on the ARM Cortex-M4 processor core. The XMC4000 is a family of high performance and energy efficient microcontrollers optimized for Industrial Connectivity, Industrial Control, Power Conversion, Sense & Control.



**Figure 1 System Block Diagram**

### CPU Subsystem

- CPU Core
  - High Performance 32-bit ARM Cortex-M4 CPU
  - 16-bit and 32-bit Thumb2 instruction set
  - DSP/MAC instructions
  - System timer (SysTick) for Operating System support
- Floating Point Unit
- Memory Protection Unit
- Nested Vectored Interrupt Controller
- General Purpose DMA with up-to 8 channels
- Event Request Unit (ERU) for programmable processing of external and internal service requests
- Flexible CRC Engine (FCE) for multiple bit error detection

**On-Chip Memories**

- 16 KB on-chip boot ROM
- 64 KB on-chip high-speed program memory
- 64 KB on-chip high speed data memory
- 256 KB on-chip Flash Memory with 8 KB instruction cache

**Communication Peripherals**

- Ethernet MAC module capable of 10/100 Mbit/s transfer rates
- EtherCATslave interface (ECAT) capable of 100 Mbit/s transfer rates with 2 MII ports, 8 Fieldbus Memory Management Units (FMMU), 8 Sync Manager, 64 bit distributed clocks
- Universal Serial Bus, USB 2.0 host, Full-Speed OTG, with integrated PHY
- Controller Area Network interface (MultiCAN), Full-CAN/Basic-CAN with 2 nodes, 64 message objects (MO), data rate up to 1 Mbaud
- Four Universal Serial Interface Channels (USIC), providing 4 serial channels, usable as UART, double-SPI, quad-SPI, IIC, IIS and LIN interfaces
- LED and Touch-Sense Controller (LEDTS) for Human-Machine interface
- SD and Multi-Media Card interface (SDMMC) for data storage memory cards

**Analog Frontend Peripherals**

- Two Analog-Digital Converters (VADC) of 12-bit resolution, 8 channels each, with input out-of-range comparators
- Digital-Analog Converter (DAC) with two channels of 12-bit resolution

**Industrial Control Peripherals**

- One Capture/Compare Units 8 (CCU8) for motor control and power conversion
- Two Capture/Compare Units 4 (CCU4) for use as general purpose timers
- Window Watchdog Timer (WDT) for safety sensitive applications
- Die Temperature Sensor (DTS)
- Real Time Clock module with alarm support
- System Control Unit (SCU) for system configuration and control

**Input/Output Lines**

- Programmable port driver control module (PORTS)
- Individual bit addressability
- Tri-stated in input mode
- Push/pull or open drain output mode
- Boundary scan test support over JTAG interface

## On-Chip Debug Support

- Full support for debug features: 6 breakpoints, CoreSight, trace
- Various interfaces: ARM-JTAG, SWD, single wire trace

## 1.1 Ordering Information

The ordering code for an Infineon microcontroller provides an exact reference to a specific product. The code "XMC4<DDD>-<Z><PPP><T><FFFF>" identifies:

- <DDD> the derivatives function set
- <Z> the package variant
  - E: LFBGA
  - F: LQFP
  - Q: VQFN
- <PPP> package pin count
- <T> the temperature range:
  - F: -40°C to 85°C
  - K: -40°C to 125°C
- <FFFF> the Flash memory size.

For ordering codes for the XMC4300 please contact your sales representative or local distributor.

This document describes several derivatives of the XMC4300 series, some descriptions may not apply to a specific product. Please see [Table 1](#).

For simplicity the term **XMC4300** is used for all derivatives throughout this document.

## 1.2 Device Types

These device types are available and can be ordered through Infineon's direct and/or distribution channels.

**Table 1 Synopsis of XMC4300 Device Types**

| Derivative <sup>1)</sup> | Package     | Flash Kbytes | SRAM Kbytes |
|--------------------------|-------------|--------------|-------------|
| XMC4300-F100x256         | PG-LQFP-100 | 256          | 128         |

1) x is a placeholder for the supported temperature range.

## Summary of Features

### 1.3 Device Type Features

The following table lists the available features per device type.

**Table 2 Features of XMC4300 Device Types**

| Derivative <sup>1)</sup> | LED<br>TS<br>Intf. | SD<br>MMC<br>Intf. | ETH<br>Intf. | ECAT<br>Slave<br>Intf. | USB<br>Intf. | USIC<br>Chan. | MultiCAN<br>Nodes, MO |
|--------------------------|--------------------|--------------------|--------------|------------------------|--------------|---------------|-----------------------|
| XMC4300-F100x256         | 1                  | 1                  | RMII         | 2 x MII                | 1            | 2 x 2         | N0, N1<br>MO[0..63]   |

1) x is a placeholder for the supported temperature range.

**Table 3 Features of XMC4300 Device Types**

| Derivative <sup>1)</sup> | ADC Chan. | DAC Chan. | CCU4 Slice | CCU8 Slice |
|--------------------------|-----------|-----------|------------|------------|
| XMC4300-F100x256         | 16        | 2         | 2 x 4      | 1 x 4      |

1) x is a placeholder for the supported temperature range.

### 1.4 Definition of Feature Variants

The XMC4300 types are offered with several memory sizes and number of available VADC channels. [Table 4](#) describes the location of the available Flash memory, [Table 5](#) describes the location of the available SRAMs, [Table 6](#) the available VADC channels.

**Table 4 Flash Memory Ranges**

| Total Flash Size | Cached Range                                       | Uncached Range                                     |
|------------------|----------------------------------------------------|----------------------------------------------------|
| 256 Kbytes       | 0800 0000 <sub>H</sub> –<br>0803 FFFF <sub>H</sub> | 0C00 0000 <sub>H</sub> –<br>0C03 FFFF <sub>H</sub> |

**Table 5 SRAM Memory Ranges**

| Total SRAM Size | Program SRAM                                       | System Data SRAM                                   |
|-----------------|----------------------------------------------------|----------------------------------------------------|
| 128 Kbytes      | 1FFF 0000 <sub>H</sub> –<br>1FFF FFFF <sub>H</sub> | 2000 0000 <sub>H</sub> –<br>2000 FFFF <sub>H</sub> |

**Table 6 ADC Channels<sup>1)</sup>**

| Package     | VADC G0  | VADC G1  |
|-------------|----------|----------|
| PG-LQFP-100 | CH0..CH7 | CH0..CH7 |

1) Some pins in a package may be connected to more than one channel. For the detailed mapping see the Port I/O Function table.

## 1.5 Identification Registers

The identification registers allow software to identify the marking.

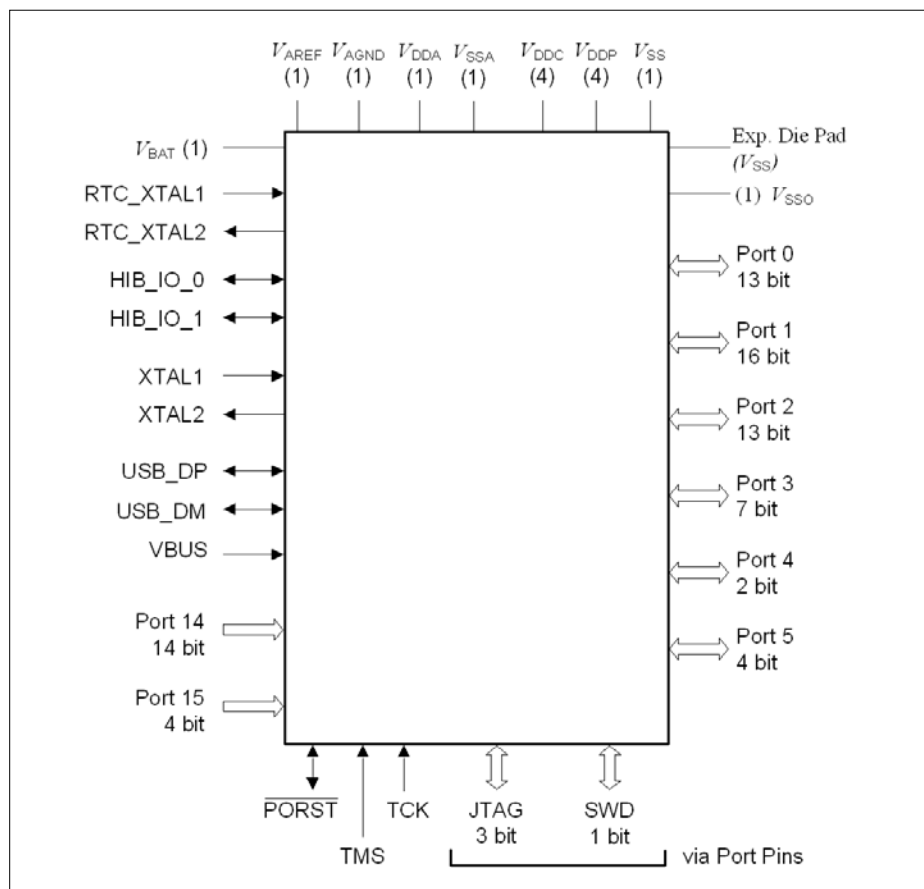
**Table 7 XMC4300 Identification Registers**

| Register Name | Value                  | Marking |
|---------------|------------------------|---------|
| SCU_IDCHIP    | 0004 3001 <sub>H</sub> | AA      |
| JTAG IDCODE   | 101D F083 <sub>H</sub> | AA      |

## 2 General Device Information

This section summarizes the logic symbols and package pin configurations with a detailed list of the functional I/O mapping.

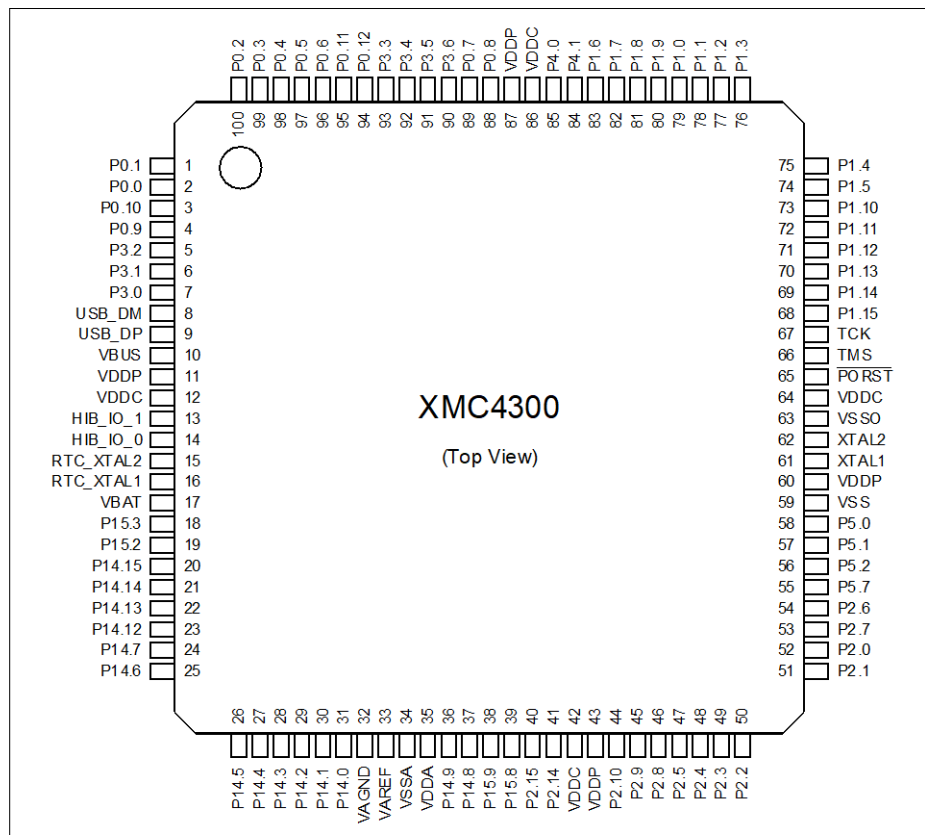
### 2.1 Logic Symbols



**Figure 2 XMC4300 Logic Symbol PG-LQFP-100**

## 2.2 Pin Configuration and Definition

The following figures summarize all pins, showing their locations on the four sides of the different packages.



**Figure 3 XMC4300 PG-LQFP-100 Pin Configuration (top view)**

## 2.2.1 Package Pin Summary

The following general scheme is used to describe each pin:

**Table 8 Package Pin Mapping Description**

| Function | Package A | Package B | ... | Pad Type | Notes |
|----------|-----------|-----------|-----|----------|-------|
| Name     | N         | Ax        | ... | A2       |       |

The table is sorted by the “Function” column, starting with the regular Port pins (Px.y), followed by the dedicated pins (i.e.  $\overline{\text{PORST}}$ ) and supply pins.

The following columns, titled with the supported package variants, lists the package pin number to which the respective function is mapped in that package.

The “Pad Type” indicates the employed pad type (A1, A1+, A2, special=special pad, In=input pad, AN/DIG\_IN=analog and digital input, Power=power supply). Details about the pad properties are defined in the Electrical Parameters.

In the “Notes”, special information to the respective pin/function is given, i.e. deviations from the default configuration after reset. Per default the regular Port pins are configured as direct input with no internal pull device active.

**Table 9 Package Pin Mapping**

| Function | LQFP-100 | Pad Type | Notes                                                                                                                     |
|----------|----------|----------|---------------------------------------------------------------------------------------------------------------------------|
| P0.0     | 2        | A1+      |                                                                                                                           |
| P0.1     | 1        | A1+      |                                                                                                                           |
| P0.2     | 100      | A2       |                                                                                                                           |
| P0.3     | 99       | A2       |                                                                                                                           |
| P0.4     | 98       | A2       |                                                                                                                           |
| P0.5     | 97       | A2       |                                                                                                                           |
| P0.6     | 96       | A2       |                                                                                                                           |
| P0.7     | 89       | A2       | After a system reset, via HWSEL this pin selects the DB.TDI function.                                                     |
| P0.8     | 88       | A2       | After a system reset, via HWSEL this pin selects the DB. $\overline{\text{TRST}}$ function, with a weak pull-down active. |
| P0.9     | 4        | A2       |                                                                                                                           |
| P0.10    | 3        | A1+      |                                                                                                                           |
| P0.11    | 95       | A1+      |                                                                                                                           |
| P0.12    | 94       | A1+      |                                                                                                                           |

**General Device Information**
**Table 9 Package Pin Mapping (cont'd)**

| Function | LQFP-100 | Pad Type | Notes                                                                 |
|----------|----------|----------|-----------------------------------------------------------------------|
| P1.0     | 79       | A1+      |                                                                       |
| P1.1     | 78       | A1+      |                                                                       |
| P1.2     | 77       | A2       |                                                                       |
| P1.3     | 76       | A2       |                                                                       |
| P1.4     | 75       | A1+      |                                                                       |
| P1.5     | 74       | A1+      |                                                                       |
| P1.6     | 83       | A2       |                                                                       |
| P1.7     | 82       | A2       |                                                                       |
| P1.8     | 81       | A2       |                                                                       |
| P1.9     | 80       | A2       |                                                                       |
| P1.10    | 73       | A1+      |                                                                       |
| P1.11    | 72       | A1+      |                                                                       |
| P1.12    | 71       | A2       |                                                                       |
| P1.13    | 70       | A2       |                                                                       |
| P1.14    | 69       | A2       |                                                                       |
| P1.15    | 68       | A2       |                                                                       |
| P2.0     | 52       | A2       |                                                                       |
| P2.1     | 51       | A2       | After a system reset, via HWSEL this pin selects the DB.TDO function. |
| P2.2     | 50       | A2       |                                                                       |
| P2.3     | 49       | A2       |                                                                       |
| P2.4     | 48       | A2       |                                                                       |
| P2.5     | 47       | A2       |                                                                       |
| P2.6     | 54       | A1+      |                                                                       |
| P2.7     | 53       | A1+      |                                                                       |
| P2.8     | 46       | A2       |                                                                       |
| P2.9     | 45       | A2       |                                                                       |
| P2.10    | 44       | A2       |                                                                       |
| P2.14    | 41       | A2       |                                                                       |
| P2.15    | 40       | A2       |                                                                       |
| P3.0     | 7        | A2       |                                                                       |
| P3.1     | 6        | A2       |                                                                       |

**General Device Information**
**Table 9 Package Pin Mapping (cont'd)**

| Function | LQFP-100 | Pad Type      | Notes |
|----------|----------|---------------|-------|
| P3.2     | 5        | A2            |       |
| P3.3     | 93       | A1+           |       |
| P3.4     | 92       | A1+           |       |
| P3.5     | 91       | A2            |       |
| P3.6     | 90       | A2            |       |
| P4.0     | 85       | A2            |       |
| P4.1     | 84       | A2            |       |
| P5.0     | 58       | A1+           |       |
| P5.1     | 57       | A1+           |       |
| P5.2     | 56       | A1+           |       |
| P5.7     | 55       | A1+           |       |
| P14.0    | 31       | AN/DIG_IN     |       |
| P14.1    | 30       | AN/DIG_IN     |       |
| P14.2    | 29       | AN/DIG_IN     |       |
| P14.3    | 28       | AN/DIG_IN     |       |
| P14.4    | 27       | AN/DIG_IN     |       |
| P14.5    | 26       | AN/DIG_IN     |       |
| P14.6    | 25       | AN/DIG_IN     |       |
| P14.7    | 24       | AN/DIG_IN     |       |
| P14.8    | 37       | AN/DAC/DIG_IN |       |
| P14.9    | 36       | AN/DAC/DIG_IN |       |
| P14.12   | 23       | AN/DIG_IN     |       |
| P14.13   | 22       | AN/DIG_IN     |       |
| P14.14   | 21       | AN/DIG_IN     |       |
| P14.15   | 20       | AN/DIG_IN     |       |
| P15.2    | 19       | AN/DIG_IN     |       |
| P15.3    | 18       | AN/DIG_IN     |       |
| P15.8    | 39       | AN/DIG_IN     |       |
| P15.9    | 38       | AN/DIG_IN     |       |

**General Device Information**
**Table 9 Package Pin Mapping (cont'd)**

| Function  | LQFP-100 | Pad Type   | Notes                                                                                                                                                                         |
|-----------|----------|------------|-------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| HIB_IO_0  | 14       | A1 special | At the first power-up and with every reset of the hibernate domain this pin is configured as open-drain output and drives "0".<br>As output the medium driver mode is active. |
| HIB_IO_1  | 13       | A1 special | At the first power-up and with every reset of the hibernate domain this pin is configured as input with no pull device active.<br>As output the medium driver mode is active. |
| USB_DP    | 9        | special    |                                                                                                                                                                               |
| USB_DM    | 8        | special    |                                                                                                                                                                               |
| TCK       | 67       | A1         | Weak pull-down active.                                                                                                                                                        |
| TMS       | 66       | A1+        | Weak pull-up active.<br>As output the strong-soft driver mode is active.                                                                                                      |
| PORST     | 65       | special    | Weak pull-up permanently active, strong pull-down controlled by EVR.                                                                                                          |
| XTAL1     | 61       | clock_IN   |                                                                                                                                                                               |
| XTAL2     | 62       | clock_O    |                                                                                                                                                                               |
| RTC_XTAL1 | 16       | clock_IN   |                                                                                                                                                                               |
| RTC_XTAL2 | 15       | clock_O    |                                                                                                                                                                               |
| VBAT      | 17       | Power      | When VDDP is supplied VBAT has to be supplied as well.                                                                                                                        |
| VBUS      | 10       | special    |                                                                                                                                                                               |
| VAREF     | 33       | AN_Ref     |                                                                                                                                                                               |
| VAGND     | 32       | AN_Ref     |                                                                                                                                                                               |
| VDDA      | 35       | AN_Power   |                                                                                                                                                                               |
| VSSA      | 34       | AN_Power   |                                                                                                                                                                               |
| VDDC      | 12       | Power      |                                                                                                                                                                               |
| VDDC      | 42       | Power      |                                                                                                                                                                               |
| VDDC      | 64       | Power      |                                                                                                                                                                               |
| VDDC      | 86       | Power      |                                                                                                                                                                               |
| VDDP      | 11       | Power      |                                                                                                                                                                               |

**General Device Information**

**Table 9      Package Pin Mapping (cont'd)**

| Function | LQFP-100 | Pad Type | Notes                                                                                                                                                                                                                                                                                                   |
|----------|----------|----------|---------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| VDDP     | 43       | Power    |                                                                                                                                                                                                                                                                                                         |
| VDDP     | 60       | Power    |                                                                                                                                                                                                                                                                                                         |
| VDDP     | 87       | Power    |                                                                                                                                                                                                                                                                                                         |
| VSS      | 59       | Power    |                                                                                                                                                                                                                                                                                                         |
| VSSO     | 63       | Power    |                                                                                                                                                                                                                                                                                                         |
| VSS      | Exp. Pad | Power    | <b>Exposed Die Pad</b><br>The exposed die pad is connected internally to VSS. For proper operation, it is mandatory to connect the exposed pad directly to the common ground on the board. For thermal aspects, please refer to the Data Sheet. Board layout examples are given in an application note. |



## 2.2.2.1 Port I/O Function Table

**Table 11 Port I/O Functions**

| Function | Output                |                  |                   |                     | Input              |                |                |              |              |                |       |                      |
|----------|-----------------------|------------------|-------------------|---------------------|--------------------|----------------|----------------|--------------|--------------|----------------|-------|----------------------|
|          | ALT1                  | ALT2             | ALT3              | ALT4                | HWO0               | HWI0           | Input          | Input        | Input        | Input          | Input | Input                |
| P0.0     | ECAT0.<br>PHY_RST     | CAN.<br>NO_TXD   | CCU00.<br>OUT21   | LEDT00.<br>COL2     |                    |                | UIC1.<br>DIXD  | ERU0.<br>080 |              |                |       | ETH0.<br>CLKRXB      |
| P0.1     | USB.<br>DRIVE/VEL     | UIC1.<br>DOU70   |                   | LEDT00.<br>COL3     |                    |                |                | ERU0.<br>0A0 |              |                |       | ETH0.<br>RXDV0       |
| P0.2     | ECAT0.<br>PL_TXD2     | UIC1.<br>SEL01   | CCU00.<br>OUT01   |                     | UIC0.<br>DOU73     | UIC0.<br>HWIN3 | ETH0.<br>RXDV0 | ERU0.<br>383 |              |                |       |                      |
| P0.3     | ECAT0.<br>PL_TXD3     |                  | CCU00.<br>OUT20   |                     | UIC0.<br>DOU72     | UIC0.<br>HWIN2 | ETH0.<br>RADT0 |              | ERU1.<br>380 |                |       |                      |
| P0.4     | ETH0.<br>TX_EN        |                  | CCU00.<br>OUT10   |                     | UIC0.<br>DOU71     | UIC0.<br>HWIN1 | UIC0.<br>DIXA  | ERU0.<br>2B3 |              |                |       | ECAT0.<br>PL_RXD0A   |
| P0.5     | ETH0.<br>TXD0         | UIC0.<br>DOU70   | CCU00.<br>OUT00   |                     | UIC0.<br>DOU70     | UIC0.<br>HWIN0 | UIC0.<br>DIXB  | ERU1.<br>3A0 |              |                |       | ECAT0.<br>PL_RXD2A   |
| P0.6     | ETH0.<br>TXD1         | UIC0.<br>SEL00   | CCU00.<br>OUT30   |                     |                    |                | UIC0.<br>DIXA  | ERU0.<br>382 |              | CCU00.<br>IN0B |       | ECAT0.<br>PL_RXD1A   |
| P0.7     | WWDT.<br>SERVICE_OUT  | UIC0.<br>SEL00   | ECAT0.<br>LED_ERR |                     | DB.<br>TDI         |                | UIC0.<br>DIXB  | ERU0.<br>2B1 |              | CCU00.<br>IN0A |       | CCU00.<br>IN3A       |
| P0.8     | SCU.<br>EXTCLK        | UIC0.<br>SELKOUT | ECAT0.<br>LED_RUN |                     | DB.<br>FRST        |                | UIC0.<br>DIXB  | ERU0.<br>2A1 |              | CCU00.<br>IN1B |       |                      |
| P0.9     |                       | UIC1.<br>SEL00   | CCU00.<br>OUT12   | LEDT00.<br>COL0     | ETH0.<br>MD0       | ETH0.<br>MD1A  | UIC1.<br>DIXA  | ERU0.<br>1B0 |              |                |       | ECAT0.<br>PL_RX_DVA  |
| P0.10    | ETH0.<br>MD0          | UIC1.<br>SELKOUT | CCU00.<br>OUT02   | LEDT00.<br>COL1     |                    |                | UIC1.<br>DIXA  | ERU0.<br>1A0 |              |                |       | ECAT0.<br>PL_TX_CLKA |
| P0.11    | ECAT0.<br>PL_LINK_ACT | UIC0.<br>SELKOUT | CCU00.<br>OUT31   | SDMMC.<br>RST       |                    |                | ETH0.<br>RXERB | ERU0.<br>3A2 |              |                |       | ECAT0.<br>PL_RXD0A   |
| P0.12    |                       | UIC1.<br>SEL00   | CCU00.<br>OUT3    | ECAT0.<br>MD0       | ECAT0.<br>MD0      |                | UIC1.<br>DIXB  | ERU0.<br>2B2 |              |                |       |                      |
| P1.0     |                       | UIC0.<br>SEL00   | CCU00.<br>OUT3    | ERU1.<br>PROUT3     |                    |                | UIC0.<br>DIXA  | ERU0.<br>380 |              | CCU00.<br>IN3A |       | ECAT0.<br>PL_TX_CLKA |
| P1.1     |                       | UIC0.<br>SELKOUT | CCU00.<br>OUT2    | ERU1.<br>PROUT2     | SDMMC.<br>SDWC     |                | UIC0.<br>DIXA  | ERU0.<br>3A0 |              | CCU00.<br>IN2A |       | ECAT0.<br>PL_TX_CLKA |
| P1.2     | ECAT0.<br>PQ_TXD3     |                  | CCU00.<br>OUT1    | ERU1.<br>PROUT1     | UIC0.<br>DOU73     | UIC0.<br>HWIN3 |                |              |              | CCU00.<br>IN1A |       |                      |
| P1.3     | ECAT0.<br>PQ_TX_ENA   | UIC0.<br>SELKOUT | CCU00.<br>OUT0    | ERU1.<br>PROUT0     | UIC0.<br>DOU72     | UIC0.<br>HWIN2 |                |              | ERU1.<br>2A0 | CCU00.<br>IN0A |       |                      |
| P1.4     | WWDT.<br>SERVICE_OUT  | CAN.<br>NO_TXD   | CCU00.<br>OUT33   |                     | UIC0.<br>DOU71     | UIC0.<br>HWIN1 | UIC0.<br>DIXB  | ERU0.<br>2B0 |              | CCU01.<br>IN0C |       | ECAT0.<br>PQ_RXD0A   |
| P1.5     | CAN.<br>NO_TXD        | UIC0.<br>DOU70   | CCU00.<br>OUT23   |                     | UIC0.<br>DOU70     | UIC0.<br>HWIN0 | UIC0.<br>DIXA  | ERU1.<br>0A0 |              | CCU01.<br>IN1C |       | ECAT0.<br>PQ_RXD1A   |
| P1.6     | ECAT0.<br>PQ_TXD0     | UIC0.<br>SELKOUT |                   | SDMMC.<br>DATA1_OUT | SDMMC.<br>DATA1_IN |                |                |              |              |                |       |                      |

**Table 11** Port I/O Functions (cont'd)

| Function | Output                      |                   |      |                       | Input                |                    |      |               |              |       |                |                      |
|----------|-----------------------------|-------------------|------|-----------------------|----------------------|--------------------|------|---------------|--------------|-------|----------------|----------------------|
|          | ALT1                        | ALT2              | ALT3 | ALT4                  | HWO0                 | HW00               | HW00 | Input         | Input        | Input | Input          | Input                |
| P1.7     | ECAT0.<br>P0_TX01           | U0C0.<br>DOUT0    |      | U1C1.<br>SEL02        | SDMMC.<br>DATA2_OUT  | SDMMC.<br>DATA2_IN |      |               |              |       |                |                      |
| P1.8     | ECAT0.<br>P0_TX02           | U0C0.<br>SEL01    |      |                       | SDMMC.<br>DATA1_OUT  | SDMMC.<br>DATA1_IN |      |               |              |       |                |                      |
| P1.9     | U0C0.<br>SCLKOUT            |                   |      | U1C1.<br>DOUT0        | SDMMC.<br>DATA5_OUT  | SDMMC.<br>DATA5_IN |      |               |              |       |                | ECAT0.<br>P0_RX_DVA  |
| P1.10    | ETH0.<br>MDC                | U0C0.<br>SCLKOUT  |      | ECAT0.<br>LED_ERR     |                      | SDMMC.<br>SDIO0    |      |               |              |       | CCU41.<br>IN2C | ECAT0.<br>P0_RXD2A   |
| P1.11    | ECAT0.<br>LED_STATE_R<br>UN | U0C0.<br>SEL03    |      | ECAT0.<br>LED_RUN     | ETH0.<br>MIO0        | ETH0.<br>MIO1C     |      |               |              |       | CCU41.<br>IN3C | ECAT0.<br>P0_RXD3A   |
| P1.12    | ETH0.<br>TX_EN              | CAN.<br>M1_TX0    |      | ECAT0.<br>P0_LINK_ACT | SDMMC.<br>DATA3_OUT  | SDMMC.<br>DATA3_IN |      |               |              |       |                |                      |
| P1.13    | ETH0.<br>TX00               | U0C1.<br>SEL03    |      | ECAT0.<br>PHY_CLK25   | SDMMC.<br>DATA7_OUT  | CAN.<br>M1_RX0C    |      |               |              |       |                |                      |
| P1.14    | ETH0.<br>TX01               | U0C1.<br>SEL02    |      | ECAT0.<br>SYNC0       |                      | U1C0.<br>DX0E      |      |               |              |       |                |                      |
| P1.15    | SQU.<br>EXTCLK              |                   |      | U1C0.<br>DOUT0        |                      |                    |      |               | ERU1.<br>1A0 |       |                | ECAT0.<br>P0_LINKB   |
| P2.0     | CAN.<br>M0_TX0              |                   |      | LEDTS0.<br>COL1       | ETH0.<br>MIO0        | ETH0.<br>MIO1B     |      |               | ERU0.<br>0B3 |       | CCU40.<br>IN1C |                      |
| P2.1     |                             |                   |      | LEDTS0.<br>COL0       | D8.TD0/<br>TRACESWO  | ETH0.<br>CLK_RMIIA |      |               | ERU1.<br>0B0 |       | CCU40.<br>IN0C | ETH0.<br>CLKRXA      |
| P2.2     | VAOC.<br>EMU000             |                   |      | LEDTS0.<br>LINE9      | LEDTS0.<br>EXTENDED0 | ETH0.<br>TSN0A     |      | U0C1.<br>DX0A | ERU0.<br>1B2 |       | CCU41.<br>IN3A |                      |
| P2.3     | VAOC.<br>EMU001             | U0C1.<br>SEL00    |      | LEDTS0.<br>LINE1      | LEDTS0.<br>EXTENDED1 | ETH0.<br>TSN1A     |      | U0C1.<br>DX1A | ERU0.<br>1A2 |       | CCU41.<br>IN3A |                      |
| P2.4     | VAOC.<br>EMU002             | U0C1.<br>SCLKOUT  |      | LEDTS0.<br>LINE2      | LEDTS0.<br>EXTENDED2 | ETH0.<br>TSN2A     |      | U0C1.<br>DX1A | ERU0.<br>0B2 |       | CCU41.<br>IN1A |                      |
| P2.5     | ETH0.<br>TX_EN              | U0C1.<br>DOUT0    |      | LEDTS0.<br>LINE3      | LEDTS0.<br>EXTENDED3 | ETH0.<br>TSN3A     |      | U0C1.<br>DX0B | ERU0.<br>0A2 |       | CCU41.<br>IN3A | ETH0.<br>CRS_DVA     |
| P2.6     |                             | ERU1.<br>P0OUT3   |      | LEDTS0.<br>COL3       |                      | CAN.<br>M1_RX0A    |      |               | ERU0.<br>1B3 |       | CCU40.<br>IN3C | ECAT0.<br>P0_RX_ERRB |
| P2.7     | ETH0.<br>MDC                | CAN.<br>M1_TX0    |      | LEDTS0.<br>COL2       |                      |                    |      |               | ERU1.<br>1B0 |       | CCU40.<br>IN2C |                      |
| P2.8     | ETH0.<br>TX00               | ERU1.<br>P0OUT1   |      | LEDTS0.<br>LINE4      | LEDTS0.<br>EXTENDED4 | DAC.<br>TSN4A      |      |               |              |       | CCU40.<br>IN0B | CCU40.<br>IN3B       |
| P2.9     | ETH0.<br>TX01               | ERU1.<br>P0OUT2   |      | LEDTS0.<br>LINE5      | LEDTS0.<br>EXTENDED5 | DAC.<br>TRIGGERS   |      |               |              |       | CCU41.<br>IN0B | CCU41.<br>IN3B       |
| P2.10    | VAOC.<br>EMU010             | ERU1.<br>P0OUT0   |      | ECAT0.<br>PHY_FAST    |                      |                    |      |               |              |       |                |                      |
| P2.14    | VAOC.<br>EMU011             | U1C0.<br>DOUT0    |      |                       |                      |                    |      | U1C0.<br>DX0D |              |       |                |                      |
| P2.15    | VAOC.<br>EMU012             | ECAT0.<br>P1_TX03 |      | LEDTS0.<br>LINE6      | LEDTS0.<br>EXTENDED6 | ETH0.<br>COLA      |      | U1C0.<br>DX0C |              |       |                |                      |

**Table 11** Port I/O Functions (cont'd)

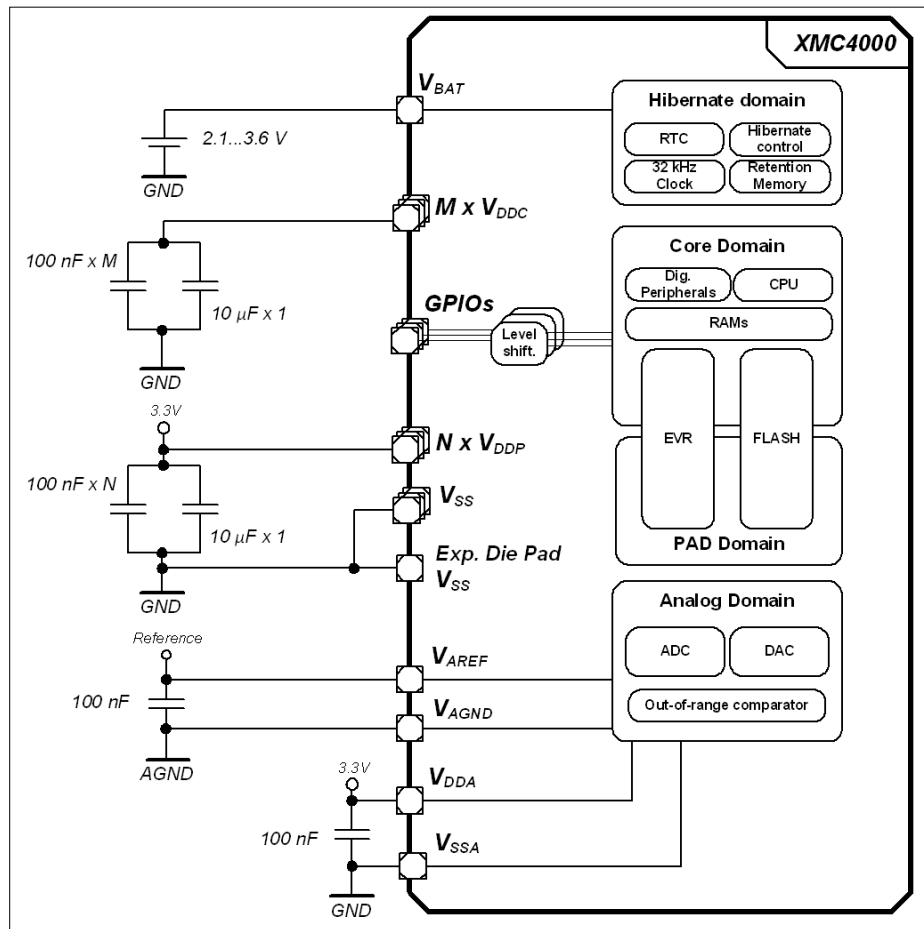
| Function | Output         |                    |               |                 | Input           |      |            |              |           |                   |                |                   |
|----------|----------------|--------------------|---------------|-----------------|-----------------|------|------------|--------------|-----------|-------------------|----------------|-------------------|
|          | ALT1           | ALT2               | ALT3          | ALT4            | HWO0            | HWI0 | Input      | Input        | Input     | Input             | Input          | Input             |
| P3.0     |                | UIC1_SCLKOUT       |               | ECAT0_P1_TX_ENA |                 |      | UIC1_DX1B  |              |           | CCU80_IN2C        |                |                   |
| P3.1     |                | UIC1_SEL00         | ECAT0_P1_TXD0 |                 |                 |      | UIC1_D02B  |              | ERU0_0A1  | CCU80_IN1C        |                |                   |
| P3.2     | USB_DRIVE/VSUS | GAN_NO_TXD         | ECAT0_P1_TXD1 | LEDTS0_COLA     |                 |      |            |              | ERU0_0A1  | CCU80_IN0C        |                |                   |
| P3.3     |                | UIC1_SEL01         |               | ECAT0_MCLK      | SDMMC_LED       |      |            |              |           | CCU80_IN3B        |                |                   |
| P3.4     |                | UIC1_SEL02         |               |                 | SDMMC_BUS_POWER |      |            |              |           | CCU80_IN3B        | ECAT0_P1_LIN_A |                   |
| P3.5     |                | UIC1_SEL03         |               | UIC1_DOUT0      | SDMMC_CMD_IN    |      |            |              | ERU0_3A1  | ECAT0_P1_RX_ERR_A |                |                   |
| P3.6     |                | UIC1_SEL04         |               | UIC1_SCLKOUT    | SDMMC_CLK_IN    |      |            |              | ERU0_3A1  |                   |                |                   |
| P4.0     |                | ECAT0_PHY_CLK25    |               | UIC0_SCLKOUT    | SDMMC_DATA0_IN  |      | UIC1_DX1C  |              | UIC1_DX0E |                   |                | ECAT0_P0_RX_ERR_A |
| P4.1     |                | UIC1_MCLKOUT       |               | UIC1_SEL00      | SDMMC_DATA1_IN  |      |            |              |           |                   |                | ECAT0_P0_LIN_A    |
| P5.0     |                |                    |               | ERU1_P0OUT0     |                 |      |            | ETH0_RXD0D   | UIC0_DX0D | ECAT0_P0_RXD0B    |                |                   |
| P5.1     | UIC0_DOUT0     |                    |               | ERU1_P0OUT1     |                 |      |            | ETH0_RXD1D   |           | ECAT0_P0_RXD1B    |                |                   |
| P5.2     |                | ECAT0_P0_LIN_A_ACT |               | ERU1_P0OUT2     |                 |      |            | ETH0_GRS_DVD |           | ECAT0_P0_RXD2B    |                | ETH0_RXD2D        |
| P5.7     | ECAT0_SYNC0    |                    |               | LEDTS0_COLA     |                 |      |            |              |           | ECAT0_P0_RXD3B    |                |                   |
| P14.0    |                |                    |               |                 |                 |      | VADC_G0CH0 |              |           |                   |                |                   |
| P14.1    |                |                    |               |                 |                 |      | VADC_G0CH1 |              |           |                   |                |                   |
| P14.2    |                |                    |               |                 |                 |      | VADC_G0CH2 |              |           |                   |                |                   |
| P14.3    |                |                    |               |                 |                 |      | VADC_G0CH3 |              |           | CAN_NO_RX0B       |                |                   |
| P14.4    |                |                    |               |                 |                 |      | VADC_G0CH4 |              |           |                   |                | ECAT0_LATCH1A     |
| P14.5    |                |                    |               |                 |                 |      | VADC_G0CH5 |              |           |                   |                | ECAT0_LATCH1A     |
| P14.6    |                |                    |               |                 |                 |      | VADC_G0CH6 |              |           |                   |                | ECAT0_P1_RX_CLKB  |
| P14.7    |                |                    |               |                 |                 |      | VADC_G0CH7 |              |           |                   |                | ECAT0_P1_RXD0B    |
| P14.8    |                |                    |               |                 | DAC_OUT_0       |      |            |              |           |                   |                |                   |
| P14.9    |                |                    |               |                 | DAC_OUT_1       |      |            |              |           | ETH0_RXD0C        |                |                   |
|          |                |                    |               |                 |                 |      |            |              |           | ETH0_RXD0C        |                |                   |

**Table 11** Port I/O Functions (cont'd)

| Function  | Output |                       |      |      | Input |                  |                  |                |                     |               |                      |
|-----------|--------|-----------------------|------|------|-------|------------------|------------------|----------------|---------------------|---------------|----------------------|
|           | ALT1   | ALT2                  | ALT3 | ALT4 | HWO0  | HWO0             | HWI0             | Input          | Input               | Input         | Input                |
| P14.12    |        |                       |      |      |       |                  |                  | VADC:<br>G1CH4 |                     |               | ECAT0:<br>P1_RXD1B   |
| P14.13    |        |                       |      |      |       |                  |                  | VADC:<br>G1CH5 |                     |               | ECAT0:<br>P1_RXD2B   |
| P14.14    |        |                       |      |      |       |                  |                  | VADC:<br>G1CH6 |                     |               | ECAT0:<br>P1_RXD3B   |
| P14.15    |        |                       |      |      |       |                  |                  | VADC:<br>G1CH7 |                     |               | ECAT0:<br>P1_RX_DVB  |
| P15.2     |        |                       |      |      |       |                  |                  |                |                     |               | ECAT0:<br>P1_RX_ERRB |
| P15.3     |        |                       |      |      |       |                  |                  |                |                     |               | ECAT0:<br>P1_LINKB   |
| P15.8     |        |                       |      |      |       |                  |                  |                | ETH0:<br>CLK_RMIIIC |               | ETH0:<br>CLK_RXC     |
| P15.9     |        |                       |      |      |       |                  |                  |                | ETH0:<br>CRS_DVC    |               | ETH0:<br>RXDVC       |
| HIB_IO_0  | HIBOUT | WWDOT:<br>SERVICE_OUT |      |      |       |                  |                  | WAKEUPA        |                     |               |                      |
| HIB_IO_1  | HIBOUT | WWDOT:<br>SERVICE_OUT |      |      |       |                  |                  | WAKEUPB        |                     |               |                      |
| USB_DP    |        |                       |      |      |       |                  |                  |                |                     |               |                      |
| USB_DM    |        |                       |      |      |       |                  |                  |                |                     |               |                      |
| TX0       |        |                       |      |      |       |                  | DB_TCK/<br>SWCLK |                |                     |               |                      |
| TMS       |        |                       |      |      |       | DB_TMS/<br>SWDIO |                  |                |                     |               |                      |
| PORST     |        |                       |      |      |       |                  |                  |                |                     |               |                      |
| XTAL1     |        |                       |      |      |       |                  |                  | UIC0:<br>DX0F  | UIC0:<br>DX0F       | UIC1:<br>DX0F |                      |
| XTAL2     |        |                       |      |      |       |                  |                  |                |                     |               |                      |
| RTC_XTAL1 |        |                       |      |      |       |                  |                  |                | ERU0:<br>IB1        |               |                      |
| RTC_XTAL2 |        |                       |      |      |       |                  |                  |                |                     |               |                      |

## 2.3 Power Connection Scheme

**Figure 5** shows a reference power connection scheme for the XMC4300.



**Figure 5 Power Connection Scheme**

Every power supply pin needs to be connected. Different pins of the same supply need also to be externally connected. As example, all V<sub>DDP</sub> pins must be connected externally to one V<sub>DDP</sub> net. In this reference scheme one 100 nF capacitor is connected at each supply pin against V<sub>SS</sub>. An additional 10  $\mu$ F capacitor is connected to the V<sub>DDP</sub> nets and an additional 10  $\mu$ F capacitor to the V<sub>DDC</sub> nets.

The XMC4300 has a common ground concept, all  $V_{SS}$ ,  $V_{SSA}$  and  $V_{SSO}$  pins share the same ground potential. In packages with an exposed die pad it must be connected to the common ground as well.

$V_{AGND}$  is the low potential to the analog reference  $V_{AREF}$ . Depending on the application it can share the common ground or have a different potential. In devices with shared  $V_{DDA}/V_{AREF}$  and  $V_{SSA}/V_{AGND}$  pins the reference is tied to the supply. Some analog channels can optionally serve as “Alternate Reference”; further details on this operating mode are described in the Reference Manual.

When  $V_{DDP}$  is supplied,  $V_{BAT}$  must be supplied as well. If no other supply source (e.g. battery) is connected to  $V_{BAT}$ , the  $V_{BAT}$  pin can also be connected directly to  $V_{DDP}$ .

## **3 Electrical Parameters**

*Attention: All parameters in this chapter are preliminary target values and may change based on characterization results.*

### **3.1 General Parameters**

#### **3.1.1 Parameter Interpretation**

The parameters listed in this section partly represent the characteristics of the XMC4300 and partly its requirements on the system. To aid interpreting the parameters easily when evaluating them for a design, they are marked with a two-letter abbreviation in column “Symbol”:

- **CC**  
Such parameters indicate **C**ontroller **C**haracteristics, which are a distinctive feature of the XMC4300 and must be regarded for system design.
- **SR**  
Such parameters indicate **S**ystem **R**equirements, which must be provided by the application system in which the XMC4300 is designed in.

### 3.1.2 Absolute Maximum Ratings

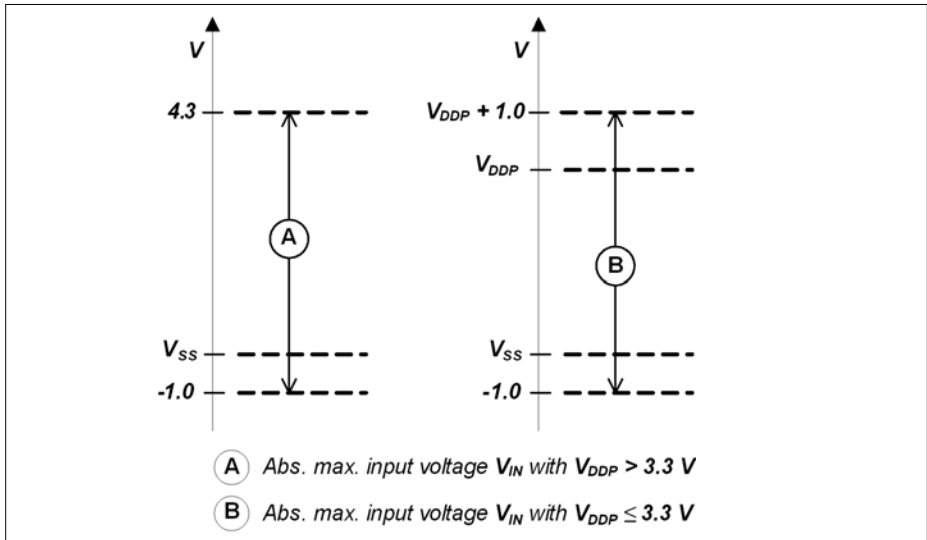
Stresses above the values listed under “Absolute Maximum Ratings” may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions may affect device reliability.

**Table 12 Absolute Maximum Rating Parameters**

| Parameter                                                                                                     | Symbol                  |    | Values |      |                             | Unit | Note / Test Condition |
|---------------------------------------------------------------------------------------------------------------|-------------------------|----|--------|------|-----------------------------|------|-----------------------|
|                                                                                                               |                         |    | Min.   | Typ. | Max.                        |      |                       |
| Storage temperature                                                                                           | $T_{ST}$                | SR | -65    | –    | 150                         | °C   | –                     |
| Junction temperature                                                                                          | $T_J$                   | SR | -40    | –    | 150                         | °C   | –                     |
| Voltage at 3.3 V power supply pins with respect to $V_{SS}$                                                   | $V_{DDP}$               | SR | –      | –    | 4.3                         | V    | –                     |
| Voltage on any Class A and dedicated input pin with respect to $V_{SS}$                                       | $V_{IN}$                | SR | -1.0   | –    | $V_{DDP} + 1.0$ or max. 4.3 | V    | whichever is lower    |
| Voltage on any analog input pin with respect to $V_{AGND}$                                                    | $V_{AIN}$<br>$V_{AREF}$ | SR | -1.0   | –    | $V_{DDP} + 1.0$ or max. 4.3 | V    | whichever is lower    |
| Input current on any pin during overload condition                                                            | $I_{IN}$                | SR | -10    | –    | +10                         | mA   |                       |
| Absolute maximum sum of all input circuit currents for one port group during overload condition <sup>1)</sup> | $\Sigma I_{IN}$         | SR | -25    | –    | +25                         | mA   |                       |
| Absolute maximum sum of all input circuit currents during overload condition                                  | $\Sigma I_{IN}$         | SR | -100   | –    | +100                        | mA   |                       |

1) The port groups are defined in [Table 16](#).

**Figure 6** explains the input voltage ranges of  $V_{IN}$  and  $V_{AIN}$  and its dependency to the supply level of  $V_{DDP}$ . The input voltage must not exceed 4.3 V, and it must not be more than 1.0 V above  $V_{DDP}$ . For the range up to  $V_{DDP} + 1.0$  V also see the definition of the overload conditions in **“Pin Reliability in Overload”**.



**Figure 6 Absolute Maximum Input Voltage Ranges**

### 3.1.3 Pin Reliability in Overload

When receiving signals from higher voltage devices, low-voltage devices experience overload currents and voltages that go beyond their own IO power supplies specification.

**Table 13** defines overload conditions that will not cause any negative reliability impact if all the following conditions are met:

- full operation life-time is not exceeded
- **“Operating Conditions”** are met for
  - pad supply levels ( $V_{DDP}$  or  $V_{DDA}$ )
  - temperature

If a pin current is outside of the **“Operating Conditions”** but within the overload conditions, then the parameters of this pin as stated in the Operating Conditions can no longer be guaranteed. Operation is still possible in most cases but with relaxed parameters.

*Note: An overload condition on one or more pins does not require a reset.*

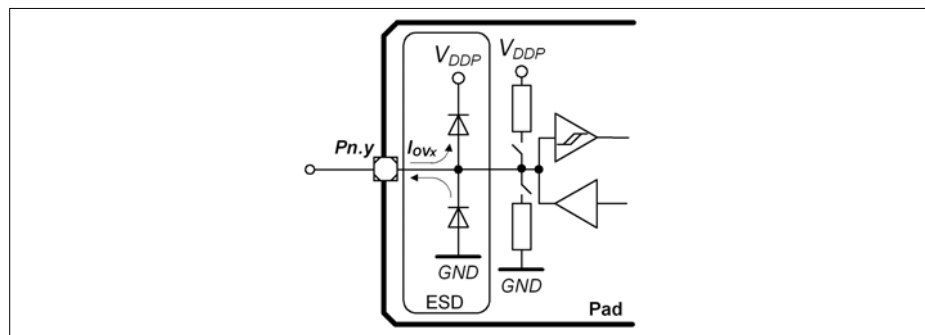
*Note: A series resistor at the pin to limit the current to the maximum permitted overload current is sufficient to handle failure situations like short to battery.*

**Table 13      Overload Parameters**

| Parameter                                                                                             | Symbol    |    | Values |      |      | Unit | Note / Test Condition                         |
|-------------------------------------------------------------------------------------------------------|-----------|----|--------|------|------|------|-----------------------------------------------|
|                                                                                                       |           |    | Min.   | Typ. | Max. |      |                                               |
| Input current on any port pin during overload condition                                               | $I_{OV}$  | SR | -5     | —    | 5    | mA   |                                               |
| Absolute sum of all input circuit currents for one port group during overload condition <sup>1)</sup> | $I_{OVG}$ | SR | —      | —    | 20   | mA   | $\Sigma  I_{OVx} $ , for all $I_{OVx} < 0$ mA |
|                                                                                                       |           |    | —      | —    | 20   | mA   | $\Sigma  I_{OVx} $ , for all $I_{OVx} > 0$ mA |
| Absolute sum of all input circuit currents during overload condition                                  | $I_{OVS}$ | SR | —      | —    | 80   | mA   | $\Sigma I_{OVG}$                              |

1) The port groups are defined in [Table 16](#).

**Figure 7** shows the path of the input currents during overload via the ESD protection structures. The diodes against  $V_{DDP}$  and ground are a simplified representation of these ESD protection structures.



**Figure 7      Input Overload Current via ESD structures**

**Table 14** and **Table 15** list input voltages that can be reached under overload conditions. Note that the absolute maximum input voltages as defined in the “**Absolute Maximum Ratings**” must not be exceeded during overload.

**Electrical Parameters**

**Table 14 PN-Junction Characterisitcs for positive Overload**

| Pad Type  | $I_{OV} = 5 \text{ mA}, T_J = -40 \text{ }^{\circ}\text{C}$ | $I_{OV} = 5 \text{ mA}, T_J = 150 \text{ }^{\circ}\text{C}$ |
|-----------|-------------------------------------------------------------|-------------------------------------------------------------|
| A1 / A1+  | $V_{IN} = V_{DDP} + 1.0 \text{ V}$                          | $V_{IN} = V_{DDP} + 0.75 \text{ V}$                         |
| A2        | $V_{IN} = V_{DDP} + 0.7 \text{ V}$                          | $V_{IN} = V_{DDP} + 0.6 \text{ V}$                          |
| AN/DIG_IN | $V_{IN} = V_{DDP} + 1.0 \text{ V}$                          | $V_{IN} = V_{DDP} + 0.75 \text{ V}$                         |

**Table 15 PN-Junction Characterisitcs for negative Overload**

| Pad Type  | $I_{OV} = 5 \text{ mA}, T_J = -40 \text{ }^{\circ}\text{C}$ | $I_{OV} = 5 \text{ mA}, T_J = 150 \text{ }^{\circ}\text{C}$ |
|-----------|-------------------------------------------------------------|-------------------------------------------------------------|
| A1 / A1+  | $V_{IN} = V_{SS} - 1.0 \text{ V}$                           | $V_{IN} = V_{SS} - 0.75 \text{ V}$                          |
| A2        | $V_{IN} = V_{SS} - 0.7 \text{ V}$                           | $V_{IN} = V_{SS} - 0.6 \text{ V}$                           |
| AN/DIG_IN | $V_{IN} = V_{DDP} - 1.0 \text{ V}$                          | $V_{IN} = V_{DDP} - 0.75 \text{ V}$                         |

**Table 16 Port Groups for Overload and Short-Circuit Current Sum Parameters**

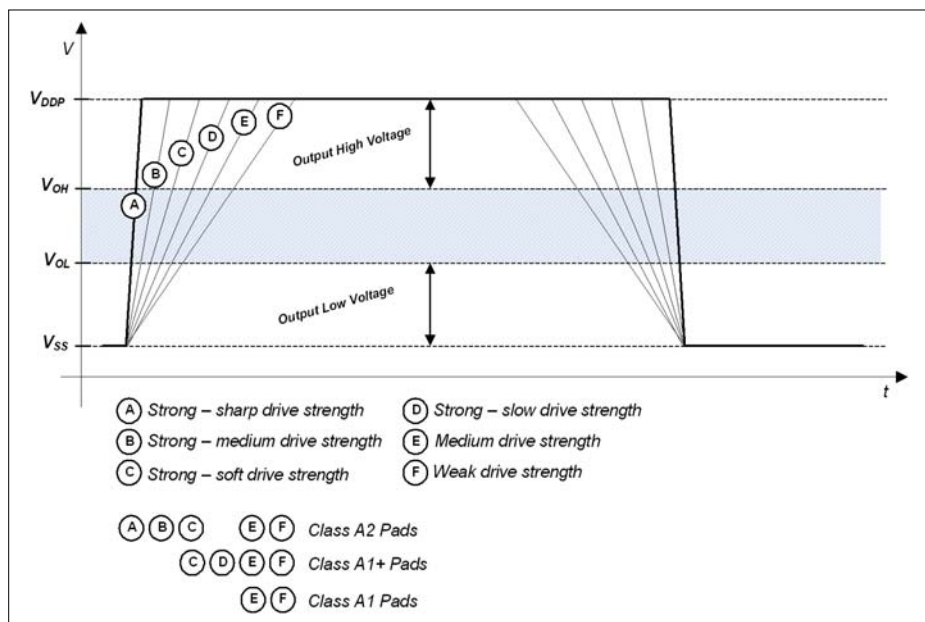
| Group | Pins                  |
|-------|-----------------------|
| 1     | P0.[12:0], P3.[6:0]   |
| 2     | P14.[15:0], P15.[9:2] |
| 3     | P2.[15:0], P5.[7:0]   |
| 4     | P1.[15:0], P4.[1:0]   |

### 3.1.4 Pad Driver and Pad Classes Summary

This section gives an overview on the different pad driver classes and their basic characteristics.

**Table 17 Pad Driver and Pad Classes Overview**

| Class    | Power Supply | Type       | Sub-Class                        | Speed Grade | Load   | Termination                    |
|----------|--------------|------------|----------------------------------|-------------|--------|--------------------------------|
| <b>A</b> | 3.3 V        | LVTTTL I/O | <b>A1</b><br>(e.g. GPIO)         | 6 MHz       | 100 pF | No                             |
|          |              |            | <b>A1+</b><br>(e.g. serial I/Os) | 25 MHz      | 50 pF  | Series termination recommended |
|          |              |            | <b>A2</b><br>(e.g. ext. Bus)     | 80 MHz      | 15 pF  | Series termination recommended |



**Figure 8 Output Slopes with different Pad Driver Modes**

**Figure 8** is a qualitative display of the resulting output slope performance with different output driver modes. The detailed input and output characteristics are listed in **“Input/Output Pins”**.

### 3.1.5 Operating Conditions

The following operating conditions must not be exceeded in order to ensure correct operation and reliability of the XMC4300. All parameters specified in the following sections refer to these operating conditions, unless noted otherwise.

**Table 18 Operating Conditions Parameters**

| Parameter                                                          | Symbol                 | Values             |      |                    | Unit | Note / Test Condition                                            |
|--------------------------------------------------------------------|------------------------|--------------------|------|--------------------|------|------------------------------------------------------------------|
|                                                                    |                        | Min.               | Typ. | Max.               |      |                                                                  |
| Ambient Temperature                                                | $T_A$ SR               | -40                | —    | 85                 | °C   | Temp. Range F                                                    |
|                                                                    |                        | -40                | —    | 125                | °C   | Temp. Range K                                                    |
| Digital supply voltage                                             | $V_{DDP}$ SR           | 3.13 <sup>1)</sup> | 3.3  | 3.63 <sup>2)</sup> | V    |                                                                  |
| Core Supply Voltage                                                | $V_{DDC}$ CC           | — <sup>1)</sup>    | 1.3  | —                  | V    | Generated internally                                             |
| Digital ground voltage                                             | $V_{SS}$ SR            | 0                  | —    | —                  | V    |                                                                  |
| ADC analog supply voltage                                          | $V_{DDA}$ SR           | 3.0                | 3.3  | 3.6 <sup>2)</sup>  | V    |                                                                  |
| Analog ground voltage for $V_{DDA}$                                | $V_{SSA}$ SR           | -0.1               | 0    | 0.1                | V    |                                                                  |
| Battery Supply Voltage for Hibernate Domain                        | $V_{BAT}$ SR           | 1.95 <sup>3)</sup> | —    | 3.63               | V    | When $V_{DDP}$ is supplied $V_{BAT}$ has to be supplied as well. |
| System Frequency                                                   | $f_{SYS}$ SR           | —                  | —    | 144                | MHz  |                                                                  |
| Short circuit current of digital outputs                           | $I_{SC}$ SR            | -5                 | —    | 5                  | mA   |                                                                  |
| Absolute sum of short circuit currents per pin group <sup>4)</sup> | $\Sigma I_{SC\_PG}$ SR | —                  | —    | 20                 | mA   |                                                                  |
| Absolute sum of short circuit currents of the device               | $\Sigma I_{SC\_D}$ SR  | —                  | —    | 100                | mA   |                                                                  |

1) See also the Supply Monitoring thresholds, “**Power-Up and Supply Monitoring**”.

2) Voltage overshoot to 4.0 V is permissible at Power-Up and  $\overline{PORST}$  low, provided the pulse duration is less than 100  $\mu$ s and the cumulated sum of the pulses does not exceed 1 h over lifetime.

3) To start the hibernate domain it is required that  $V_{BAT} \geq 2.1$  V, for a reliable start of the oscillation of RTC\_XTAL in crystal mode it is required that  $V_{BAT} \geq 3.0$  V.

4) The port groups are defined in [Table 16](#).

## 3.2 DC Parameters

### 3.2.1 Input/Output Pins

The digital input stage of the shared analog/digital input pins is identical to the input stage of the standard digital input/output pins.

The Pull-up on the  $\overline{\text{PORST}}$  pin is identical to the Pull-up on the standard digital input/output pins.

*Note: These parameters are not subject to production test, but verified by design and/or characterization.*

**Table 19 Standard Pad Parameters**

| Parameter                                                            | Symbol                | Values                      |      | Unit          | Note / Test Condition                              |
|----------------------------------------------------------------------|-----------------------|-----------------------------|------|---------------|----------------------------------------------------|
|                                                                      |                       | Min.                        | Max. |               |                                                    |
| Pin capacitance (digital inputs/outputs)                             | $C_{\text{IO}}$ CC    | –                           | 10   | pF            |                                                    |
| Pull-down current                                                    | $ I_{\text{PDL}} $ SR | 150                         | –    | $\mu\text{A}$ | $^1)V_{\text{IN}} \geq 0.6 \times V_{\text{DDP}}$  |
|                                                                      |                       | –                           | 10   | $\mu\text{A}$ | $^2)V_{\text{IN}} \leq 0.36 \times V_{\text{DDP}}$ |
| Pull-Up current                                                      | $ I_{\text{PUH}} $ SR | –                           | 10   | $\mu\text{A}$ | $^2)V_{\text{IN}} \geq 0.6 \times V_{\text{DDP}}$  |
|                                                                      |                       | 100                         | –    | $\mu\text{A}$ | $^1)V_{\text{IN}} \leq 0.36 \times V_{\text{DDP}}$ |
| Input Hysteresis for pads of all A classes <sup>3)</sup>             | $H_{\text{YSA}}$ CC   | $0.1 \times V_{\text{DDP}}$ | –    | V             |                                                    |
| $\overline{\text{PORST}}$ spike filter always blocked pulse duration | $t_{\text{SF1}}$ CC   | –                           | 10   | ns            |                                                    |
| $\overline{\text{PORST}}$ spike filter pass-through pulse duration   | $t_{\text{SF2}}$ CC   | 100                         | –    | ns            |                                                    |
| $\overline{\text{PORST}}$ pull-down current                          | $ I_{\text{PPD}} $ CC | 13                          | –    | mA            | $V_{\text{IN}} = 1.0 \text{ V}$                    |

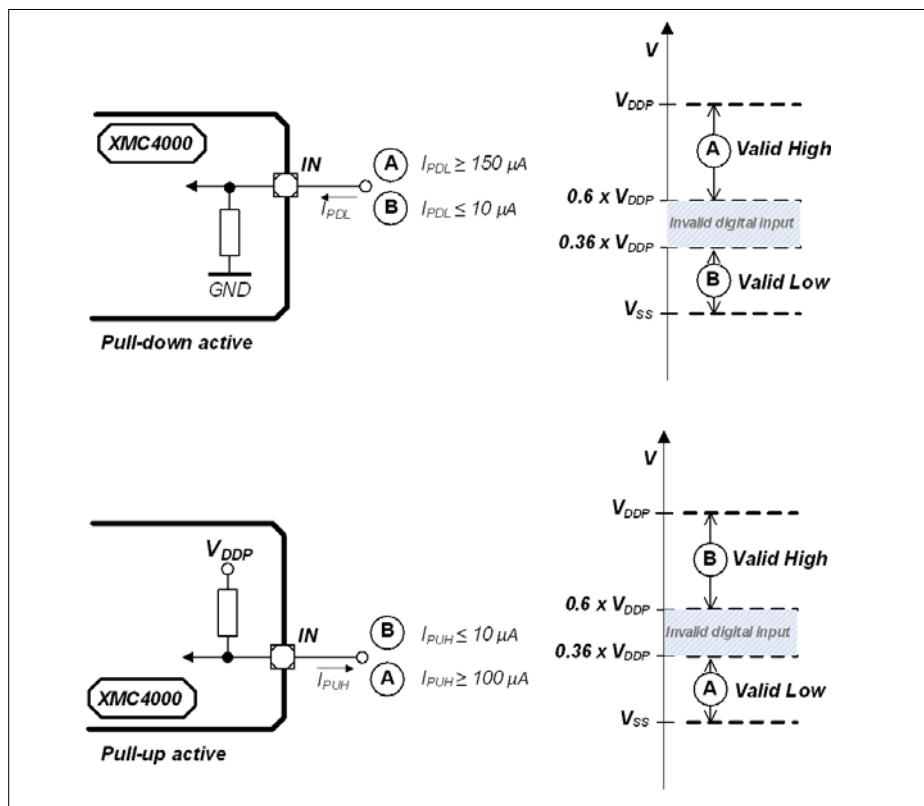
1) Current required to override the pull device with the opposite logic level ("force current").

With active pull device, at load currents between force and keep current the input state is undefined.

2) Load current at which the pull device still maintains the valid logic level ("keep current").

With active pull device, at load currents between force and keep current the input state is undefined.

3) Hysteresis is implemented to avoid metastable states and switching due to internal ground bounce. It can not be guaranteed that it suppresses switching due to external system noise.



**Figure 9 Pull Device Input Characteristics**

**Figure 9** visualizes the input characteristics with an active internal pull device:

- in the cases "A" the internal pull device is overridden by a strong external driver;
- in the cases "B" the internal pull device defines the input logical state against a weak external load.

**Electrical Parameters**
**Table 20 Standard Pads Class\_A1**

| Parameter                                          | Symbol           | Values               |                       | Unit | Note /<br>Test Condition                                           |
|----------------------------------------------------|------------------|----------------------|-----------------------|------|--------------------------------------------------------------------|
|                                                    |                  | Min.                 | Max.                  |      |                                                                    |
| Input leakage current                              | $I_{OZA1}$ CC    | -500                 | 500                   | nA   | $0\text{ V} \leq V_{IN} \leq V_{DDP}$                              |
| Input high voltage                                 | $V_{IHA1}$ SR    | $0.6 \times V_{DDP}$ | $V_{DDP} + 0.3$       | V    | max. 3.6 V                                                         |
| Input low voltage                                  | $V_{ILA1}$ SR    | -0.3                 | $0.36 \times V_{DDP}$ | V    |                                                                    |
| Output high voltage,<br>POD <sup>1)</sup> = weak   | $V_{OHA1}$<br>CC | $V_{DDP} - 0.4$      | –                     | V    | $I_{OH} \geq -400\text{ }\mu\text{A}$                              |
|                                                    |                  | 2.4                  | –                     | V    | $I_{OH} \geq -500\text{ }\mu\text{A}$                              |
| Output high voltage,<br>POD <sup>1)</sup> = medium |                  | $V_{DDP} - 0.4$      | –                     | V    | $I_{OH} \geq -1.4\text{ mA}$                                       |
|                                                    |                  | 2.4                  | –                     | V    | $I_{OH} \geq -2\text{ mA}$                                         |
| Output low voltage                                 | $V_{OLA1}$<br>CC | –                    | 0.4                   | V    | $I_{OL} \leq 500\text{ }\mu\text{A}$ ;<br>POD <sup>1)</sup> = weak |
|                                                    |                  | –                    | 0.4                   | V    | $I_{OL} \leq 2\text{ mA}$ ;<br>POD <sup>1)</sup> = medium          |
| Fall time                                          | $t_{FA1}$ CC     | –                    | 150                   | ns   | $C_L = 20\text{ pF}$ ;<br>POD <sup>1)</sup> = weak                 |
|                                                    |                  | –                    | 50                    | ns   | $C_L = 50\text{ pF}$ ;<br>POD <sup>1)</sup> = medium               |
| Rise time                                          | $t_{RA1}$ CC     | –                    | 150                   | ns   | $C_L = 20\text{ pF}$ ;<br>POD <sup>1)</sup> = weak                 |
|                                                    |                  | –                    | 50                    | ns   | $C_L = 50\text{ pF}$ ;<br>POD <sup>1)</sup> = medium               |

1) POD = Pin Out Driver

**Table 21 Standard Pads Class\_A1+**

| Parameter             | Symbol         | Values               |                       | Unit          | Note / Test Condition                 |
|-----------------------|----------------|----------------------|-----------------------|---------------|---------------------------------------|
|                       |                | Min.                 | Max.                  |               |                                       |
| Input leakage current | $I_{OZA1+}$ CC | -1                   | 1                     | $\mu\text{A}$ | $0\text{ V} \leq V_{IN} \leq V_{DDP}$ |
| Input high voltage    | $V_{IHA1+}$ SR | $0.6 \times V_{DDP}$ | $V_{DDP} + 0.3$       | V             | max. 3.6 V                            |
| Input low voltage     | $V_{ILA1+}$ SR | -0.3                 | $0.36 \times V_{DDP}$ | V             |                                       |

**Electrical Parameters**
**Table 21 Standard Pads Class\_A1+**

| Parameter                                          | Symbol                   | Values                 |      | Unit | Note /<br>Test Condition                                               |
|----------------------------------------------------|--------------------------|------------------------|------|------|------------------------------------------------------------------------|
|                                                    |                          | Min.                   | Max. |      |                                                                        |
| Output high voltage,<br>POD <sup>1)</sup> = weak   | V <sub>OHA1+</sub><br>CC | V <sub>DDP</sub> - 0.4 | –    | V    | I <sub>OH</sub> ≥ -400 μA                                              |
|                                                    |                          | 2.4                    | –    | V    | I <sub>OH</sub> ≥ -500 μA                                              |
| Output high voltage,<br>POD <sup>1)</sup> = medium |                          | V <sub>DDP</sub> - 0.4 | –    | V    | I <sub>OH</sub> ≥ -1.4 mA                                              |
|                                                    |                          | 2.4                    | –    | V    | I <sub>OH</sub> ≥ -2 mA                                                |
| Output high voltage,<br>POD <sup>1)</sup> = strong |                          | V <sub>DDP</sub> - 0.4 | –    | V    | I <sub>OH</sub> ≥ -1.4 mA                                              |
|                                                    |                          | 2.4                    | –    | V    | I <sub>OH</sub> ≥ -2 mA                                                |
| Output low voltage                                 | V <sub>OLA1+</sub><br>CC | –                      | 0.4  | V    | I <sub>OL</sub> ≤ 500 μA;<br>POD <sup>1)</sup> = weak                  |
|                                                    |                          | –                      | 0.4  | V    | I <sub>OL</sub> ≤ 2 mA;<br>POD <sup>1)</sup> = medium                  |
|                                                    |                          | –                      | 0.4  | V    | I <sub>OL</sub> ≤ 2 mA;<br>POD <sup>1)</sup> = strong                  |
| Fall time                                          | t <sub>FA1+</sub> CC     | –                      | 150  | ns   | C <sub>L</sub> = 20 pF;<br>POD <sup>1)</sup> = weak                    |
|                                                    |                          | –                      | 50   | ns   | C <sub>L</sub> = 50 pF;<br>POD <sup>1)</sup> = medium                  |
|                                                    |                          | –                      | 28   | ns   | C <sub>L</sub> = 50 pF;<br>POD <sup>1)</sup> = strong;<br>edge = slow  |
|                                                    |                          | –                      | 16   | ns   | C <sub>L</sub> = 50 pF;<br>POD <sup>1)</sup> = strong;<br>edge = soft; |
| Rise time                                          | t <sub>RA1+</sub> CC     | –                      | 150  | ns   | C <sub>L</sub> = 20 pF;<br>POD <sup>1)</sup> = weak                    |
|                                                    |                          | –                      | 50   | ns   | C <sub>L</sub> = 50 pF;<br>POD <sup>1)</sup> = medium                  |
|                                                    |                          | –                      | 28   | ns   | C <sub>L</sub> = 50 pF;<br>POD <sup>1)</sup> = strong;<br>edge = slow  |
|                                                    |                          | –                      | 16   | ns   | C <sub>L</sub> = 50 pF;<br>POD <sup>1)</sup> = strong;<br>edge = soft  |

1) POD = Pin Out Driver

**Table 22 Standard Pads Class\_A2**

| Parameter                            | Symbol                  | Values                      |                              | Unit          | Note /<br>Test Condition                                                                                                                                |
|--------------------------------------|-------------------------|-----------------------------|------------------------------|---------------|---------------------------------------------------------------------------------------------------------------------------------------------------------|
|                                      |                         | Min.                        | Max.                         |               |                                                                                                                                                         |
| Input Leakage current                | $I_{OZA2}$<br>CC        | -6                          | 6                            | $\mu\text{A}$ | $0\text{ V} \leq V_{\text{IN}} < 0.5 \cdot V_{\text{DDP}} - 1\text{ V};$<br>$0.5 \cdot V_{\text{DDP}} + 1\text{ V} < V_{\text{IN}} \leq V_{\text{DDP}}$ |
|                                      |                         | -3                          | 3                            | $\mu\text{A}$ | $0.5 \cdot V_{\text{DDP}} - 1\text{ V} < V_{\text{IN}} < 0.5 \cdot V_{\text{DDP}} + 1\text{ V}$                                                         |
| Input high voltage                   | $V_{\text{IHA2}}$<br>SR | $0.6 \times V_{\text{DDP}}$ | $V_{\text{DDP}} + 0.3$       | V             | max. 3.6 V                                                                                                                                              |
| Input low voltage                    | $V_{\text{ILA2}}$ SR    | -0.3                        | $0.36 \times V_{\text{DDP}}$ | V             |                                                                                                                                                         |
| Output high voltage,<br>POD = weak   | $V_{\text{OHA2}}$<br>CC | $V_{\text{DDP}} - 0.4$      | —                            | V             | $I_{\text{OH}} \geq -400\text{ }\mu\text{A}$                                                                                                            |
|                                      |                         | 2.4                         | —                            | V             | $I_{\text{OH}} \geq -500\text{ }\mu\text{A}$                                                                                                            |
| Output high voltage,<br>POD = medium |                         | $V_{\text{DDP}} - 0.4$      | —                            | V             | $I_{\text{OH}} \geq -1.4\text{ mA}$                                                                                                                     |
|                                      |                         | 2.4                         | —                            | V             | $I_{\text{OH}} \geq -2\text{ mA}$                                                                                                                       |
| Output high voltage,<br>POD = strong |                         | $V_{\text{DDP}} - 0.4$      | —                            | V             | $I_{\text{OH}} \geq -1.4\text{ mA}$                                                                                                                     |
|                                      |                         | 2.4                         | —                            | V             | $I_{\text{OH}} \geq -2\text{ mA}$                                                                                                                       |
| Output low voltage,<br>POD = weak    | $V_{\text{OLA2}}$<br>CC | —                           | 0.4                          | V             | $I_{\text{OL}} \leq 500\text{ }\mu\text{A}$                                                                                                             |
| Output low voltage,<br>POD = medium  |                         | —                           | 0.4                          | V             | $I_{\text{OL}} \leq 2\text{ mA}$                                                                                                                        |
| Output low voltage,<br>POD = strong  |                         | —                           | 0.4                          | V             | $I_{\text{OL}} \leq 2\text{ mA}$                                                                                                                        |

**Electrical Parameters**
**Table 22 Standard Pads Class\_A2**

| Parameter | Symbol       | Values |      | Unit | Note / Test Condition                            |
|-----------|--------------|--------|------|------|--------------------------------------------------|
|           |              | Min.   | Max. |      |                                                  |
| Fall time | $t_{FA2}$ CC | —      | 150  | ns   | $C_L = 20$ pF;<br>POD = weak                     |
|           |              | —      | 50   | ns   | $C_L = 50$ pF;<br>POD = medium                   |
|           |              | —      | 3.7  | ns   | $C_L = 50$ pF;<br>POD = strong;<br>edge = sharp  |
|           |              | —      | 7    | ns   | $C_L = 50$ pF;<br>POD = strong;<br>edge = medium |
|           |              | —      | 16   | ns   | $C_L = 50$ pF;<br>POD = strong;<br>edge = soft   |
| Rise time | $t_{RA2}$ CC | —      | 150  | ns   | $C_L = 20$ pF;<br>POD = weak                     |
|           |              | —      | 50   | ns   | $C_L = 50$ pF;<br>POD = medium                   |
|           |              | —      | 3.7  | ns   | $C_L = 50$ pF;<br>POD = strong;<br>edge = sharp  |
|           |              | —      | 7.0  | ns   | $C_L = 50$ pF;<br>POD = strong;<br>edge = medium |
|           |              | —      | 16   | ns   | $C_L = 50$ pF;<br>POD = strong;<br>edge = soft   |

**Table 23 HIB\_IO Class\_A1 special Pads**

| Parameter                                       | Symbol            | Values                |                       | Unit | Note / Test Condition                                |
|-------------------------------------------------|-------------------|-----------------------|-----------------------|------|------------------------------------------------------|
|                                                 |                   | Min.                  | Max.                  |      |                                                      |
| Input leakage current                           | $I_{OZHIB}$<br>CC | -500                  | 500                   | nA   | $0\text{ V} \leq V_{IN} \leq V_{BAT}$                |
| Input high voltage                              | $V_{IHIB}$<br>SR  | $0.6 \times V_{BAT}$  | $V_{BAT} + 0.3$       | V    | max. 3.6 V                                           |
| Input low voltage                               | $V_{ILIB}$<br>SR  | -0.3                  | $0.36 \times V_{BAT}$ | V    |                                                      |
| Input Hysteresis for HIB_IO pins <sup>1)</sup>  | $HYSHIB$<br>CC    | $0.1 \times V_{BAT}$  | –                     | V    | $V_{BAT} \geq 3.13\text{ V}$                         |
|                                                 |                   | $0.06 \times V_{BAT}$ | –                     | V    | $V_{BAT} < 3.13\text{ V}$                            |
| Output high voltage, POD <sup>1)</sup> = medium | $V_{OHIB}$<br>CC  | $V_{BAT} - 0.4$       | –                     | V    | $I_{OH} \geq -1.4\text{ mA}$                         |
| Output low voltage                              | $V_{OLIB}$<br>CC  | –                     | 0.4                   | V    | $I_{OL} \leq 2\text{ mA}$                            |
| Fall time                                       | $t_{FHIB}$ CC     | –                     | 50                    | ns   | $V_{BAT} \geq 3.13\text{ V}$<br>$C_L = 50\text{ pF}$ |
|                                                 |                   | –                     | 100                   | ns   | $V_{BAT} < 3.13\text{ V}$<br>$C_L = 50\text{ pF}$    |
| Rise time                                       | $t_{RHIB}$ CC     | –                     | 50                    | ns   | $V_{BAT} \geq 3.13\text{ V}$<br>$C_L = 50\text{ pF}$ |
|                                                 |                   | –                     | 100                   | ns   | $V_{BAT} < 3.13\text{ V}$<br>$C_L = 50\text{ pF}$    |

1) Hysteresis is implemented to avoid metastable states and switching due to internal ground bounce. It can not be guaranteed that it suppresses switching due to external system noise.

### 3.2.2 Analog to Digital Converters (VADC)

*Note: These parameters are not subject to production test, but verified by design and/or characterization.*

**Table 24 VADC Parameters** (Operating Conditions apply)

| Parameter                                                                    | Symbol                   | Values           |      |                       | Unit | Note / Test Condition                                 |
|------------------------------------------------------------------------------|--------------------------|------------------|------|-----------------------|------|-------------------------------------------------------|
|                                                                              |                          | Min.             | Typ. | Max.                  |      |                                                       |
| Analog reference voltage <sup>5)</sup>                                       | $V_{AREF}$ SR            | $V_{AGND} + 1$   | –    | $V_{DDA} + 0.05^{1)}$ | V    |                                                       |
| Analog reference ground <sup>5)</sup>                                        | $V_{AGND}$ SR            | $V_{SSM} - 0.05$ | –    | $V_{AREF} - 1$        | V    |                                                       |
| Analog reference voltage range <sup>2)5)</sup>                               | $V_{AREF} - V_{AGND}$ SR | 1                | –    | $V_{DDA} + 0.1$       | V    |                                                       |
| Analog input voltage                                                         | $V_{AIN}$ SR             | $V_{AGND}$       | –    | $V_{DDA}$             | V    |                                                       |
| Input leakage at analog inputs <sup>3)</sup>                                 | $I_{OZ1}$ CC             | -100             | –    | 200                   | nA   | $0.03 \times V_{DDA} < V_{AIN} < 0.97 \times V_{DDA}$ |
|                                                                              |                          | -500             | –    | 100                   | nA   | $0 \text{ V} \leq V_{AIN} \leq 0.03 \times V_{DDA}$   |
|                                                                              |                          | -100             | –    | 500                   | nA   | $0.97 \times V_{DDA} \leq V_{AIN} \leq V_{DDA}$       |
| Input leakage current at VAREF                                               | $I_{OZ2}$ CC             | -1               | –    | 1                     | μA   | $0 \text{ V} \leq V_{AREF} \leq V_{DDA}$              |
| Input leakage current at VAGND                                               | $I_{OZ3}$ CC             | -1               | –    | 1                     | μA   | $0 \text{ V} \leq V_{AGND} \leq V_{DDA}$              |
| Internal ADC clock                                                           | $f_{ADCI}$ CC            | 2                | –    | 36                    | MHz  | $V_{DDA} = 3.3 \text{ V}$                             |
| Switched capacitance at the analog voltage inputs <sup>4)</sup>              | $C_{AINSW}$ CC           | –                | 4    | 6.5                   | pF   |                                                       |
| Total capacitance of an analog input                                         | $C_{AINTOT}$ CC          | –                | 12   | 20                    | pF   |                                                       |
| Switched capacitance at the positive reference voltage input <sup>5)6)</sup> | $C_{AREFSW}$ CC          | –                | 15   | 30                    | pF   |                                                       |
| Total capacitance of the voltage reference inputs <sup>5)</sup>              | $C_{AREFTOT}$ CC         | –                | 20   | 40                    | pF   |                                                       |

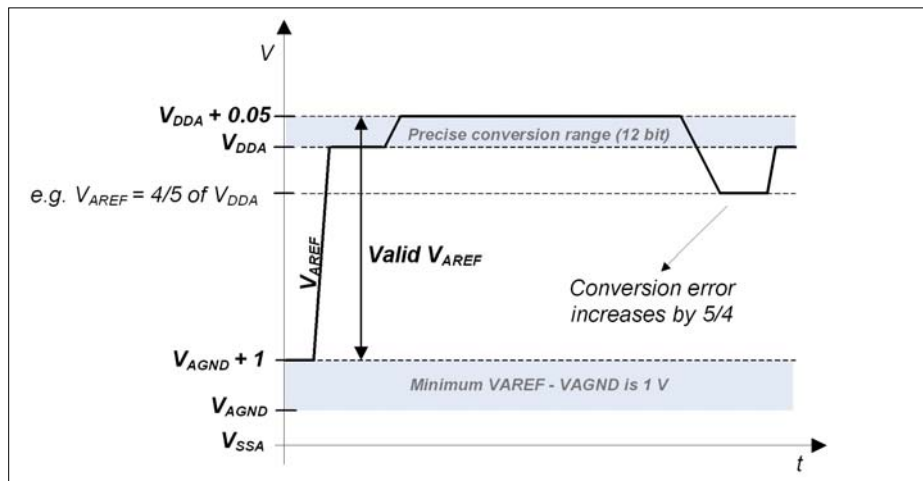
**Electrical Parameters**
**Table 24 VADC Parameters** (Operating Conditions apply)

| Parameter                                                          | Symbol           | Values |      |                     | Unit | Note / Test Condition                                                                  |
|--------------------------------------------------------------------|------------------|--------|------|---------------------|------|----------------------------------------------------------------------------------------|
|                                                                    |                  | Min.   | Typ. | Max.                |      |                                                                                        |
| Total Unadjusted Error                                             | $TUE_{CC}$       | -4     | —    | 4                   | LSB  | 12-bit resolution;<br>$V_{DDA} = 3.3\text{ V}$ ;<br>$V_{AREF} = V_{DDA}$ <sup>7)</sup> |
| Differential Non-Linearity Error <sup>8)</sup>                     | $EA_{DNL_{CC}}$  | -3     | —    | 3                   | LSB  |                                                                                        |
| Gain Error <sup>8)</sup>                                           | $EA_{GAIN_{CC}}$ | -4     | —    | 4                   | LSB  |                                                                                        |
| Integral Non-Linearity <sup>8)</sup>                               | $EA_{INL_{CC}}$  | -3     | —    | 3                   | LSB  |                                                                                        |
| Offset Error <sup>8)</sup>                                         | $EA_{OFF_{CC}}$  | -4     | —    | 4                   | LSB  |                                                                                        |
| RMS Noise <sup>9)</sup>                                            | $EN_{RMS_{CC}}$  | —      | 1    | 2 <sup>10)11)</sup> | LSB  |                                                                                        |
| Worst case ADC $V_{DDA}$ power supply current per active converter | $I_{DDAA_{CC}}$  | —      | 1.5  | 2                   | mA   | during conversion<br>$V_{DDP} = 3.6\text{ V}$ ,<br>$T_J = 150\text{ °C}$               |
| Charge consumption on $V_{AREF}$ per conversion <sup>5)</sup>      | $Q_{CONV_{CC}}$  | —      | 30   | —                   | pC   | $0\text{ V} \leq V_{AREF} \leq V_{DDA}$ <sup>12)</sup>                                 |
| ON resistance of the analog input path                             | $R_{AIN_{CC}}$   | —      | 600  | 1 200               | Ohm  |                                                                                        |
| ON resistance for the ADC test (pull down for AIN7)                | $R_{AIN7T_{CC}}$ | 180    | 550  | 900                 | Ohm  |                                                                                        |
| Resistance of the reference voltage input path                     | $R_{AREF_{CC}}$  | —      | 700  | 1 700               | Ohm  |                                                                                        |

- 1) A running conversion may become imprecise in case the normal conditions are violated (voltage overshoot).
- 2) If the analog reference voltage is below  $V_{DDA}$ , then the ADC converter errors increase. If the reference voltage is reduced by the factor  $k$  ( $k < 1$ ),  $TUE$ ,  $DNL$ ,  $INL$ , Gain, and Offset errors increase also by the factor  $1/k$ .
- 3) The leakage current definition is a continuous function, as shown in figure ADCx Analog Inputs Leakage. The numerical values defined determine the characteristic points of the given continuous linear approximation - they do not define step function (see [Figure 12](#)).
- 4) The sampling capacity of the conversion C-network is pre-charged to  $V_{AREF}/2$  before the sampling moment. Because of the parasitic elements, the voltage measured at  $AINx$  can deviate from  $V_{AREF}/2$ .
- 5) Applies to  $AINx$ , when used as alternate reference input.
- 6) This represents an equivalent switched capacitance. This capacitance is not switched to the reference voltage at once. Instead, smaller capacitances are successively switched to the reference voltage.
- 7) For 10-bit conversions, the errors are reduced to 1/4; for 8-bit conversions, the errors are reduced to 1/16. Never less than  $\pm 1$  LSB.
- 8) The sum of  $DNL/INL/GAIN/OFF$  errors does not exceed the related total unadjusted error  $TUE$ .

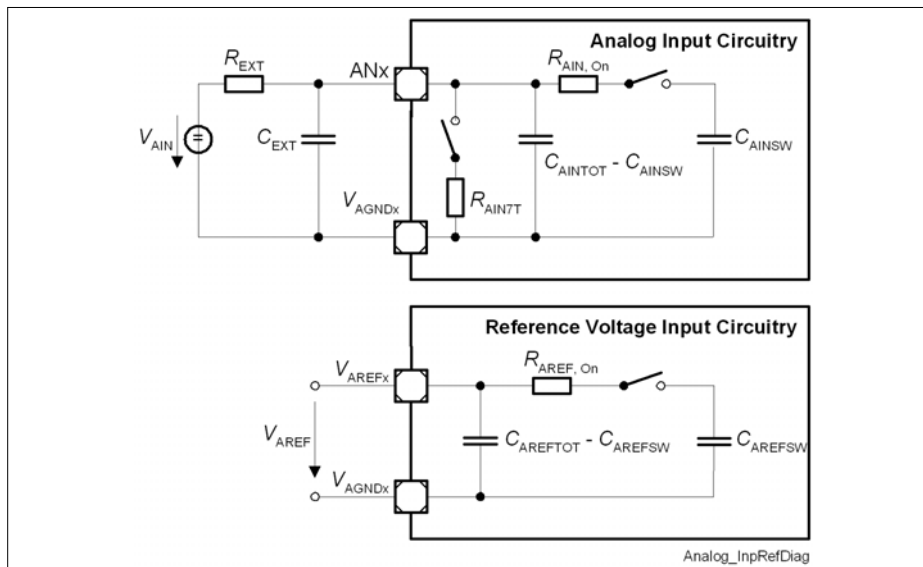
## Electrical Parameters

- 9) This parameter is valid for soldered devices and requires careful analog board design.
- 10) Resulting worst case combined error is arithmetic combination of TUE and  $EN_{RMS}$ .
- 11) Value is defined for one sigma Gauss distribution.
- 12) The resulting current for a conversion can be calculated with  $I_{AREF} = Q_{CONV} / t_c$ .  
The fastest 12-bit post-calibrated conversion of  $t_c = 459$  ns results in a typical average current of  $I_{AREF} = 65.4$   $\mu$ A.

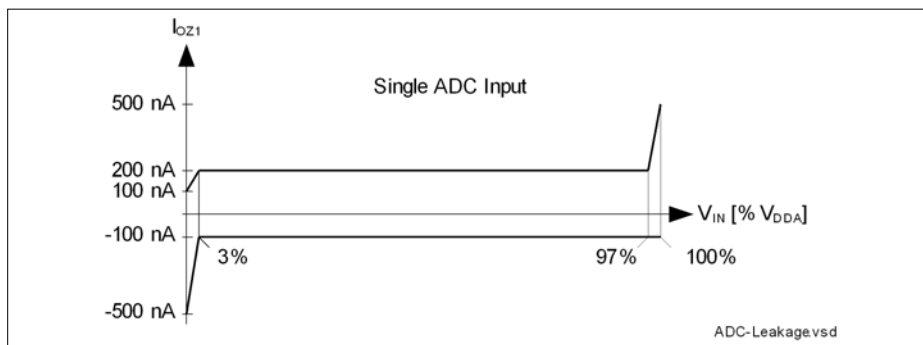


**Figure 10 VADC Reference Voltage Range**

The power-up calibration of the VADC requires a maximum number of  $4\,352 f_{ADC1}$  cycles.



**Figure 11 VADC Input Circuits**



**Figure 12 VADC Analog Input Leakage Current**

## Conversion Time

**Table 25 Conversion Time** (Operating Conditions apply)

| Parameter       | Symbol   | Values                                                       | Unit    | Note                                                                                          |
|-----------------|----------|--------------------------------------------------------------|---------|-----------------------------------------------------------------------------------------------|
| Conversion time | $t_C$ CC | $2 \times T_{ADC} + (2 + N + STC + PC + DM) \times T_{ADCI}$ | $\mu s$ | N = 8, 10, 12 for N-bit conversion<br>$T_{ADC} = 1 / f_{PERIPH}$<br>$T_{ADCI} = 1 / f_{ADCI}$ |

- STC defines additional clock cycles to extend the sample time
- PC adds two cycles if post-calibration is enabled
- DM adds one cycle for an extended conversion time of the MSB

## Conversion Time Examples

System assumptions:

$f_{ADC} = 144 \text{ MHz}$  i.e.  $t_{ADC} = 6.9 \text{ ns}$ , DIVA = 3,  $f_{ADCI} = 36 \text{ MHz}$  i.e.  $t_{ADCI} = 27.8 \text{ ns}$

According to the given formulas the following minimum conversion times can be achieved (STC = 0, DM = 0):

12-bit post-calibrated conversion (PC = 2):

$$t_{CN12C} = (2 + 12 + 2) \times t_{ADCI} + 2 \times t_{ADC} = 16 \times 27.8 \text{ ns} + 2 \times 6.9 \text{ ns} = 459 \text{ ns}$$

12-bit uncalibrated conversion:

$$t_{CN12} = (2 + 12) \times t_{ADCI} + 2 \times t_{ADC} = 14 \times 27.8 \text{ ns} + 2 \times 6.9 \text{ ns} = 403 \text{ ns}$$

10-bit uncalibrated conversion:

$$t_{CN10} = (2 + 10) \times t_{ADCI} + 2 \times t_{ADC} = 12 \times 27.8 \text{ ns} + 2 \times 6.9 \text{ ns} = 348 \text{ ns}$$

8-bit uncalibrated:

$$t_{CN8} = (2 + 8) \times t_{ADCI} + 2 \times t_{ADC} = 10 \times 27.8 \text{ ns} + 2 \times 6.9 \text{ ns} = 292 \text{ ns}$$

**Electrical Parameters**
**3.2.3 Digital to Analog Converters (DAC)**

*Note: These parameters are not subject to production test, but verified by design and/or characterization.*

**Table 26 DAC Parameters (Operating Conditions apply)**

| Parameter                  | Symbol            | Values |           |      | Unit       | Note / Test Condition                                                     |
|----------------------------|-------------------|--------|-----------|------|------------|---------------------------------------------------------------------------|
|                            |                   | Min.   | Typ.      | Max. |            |                                                                           |
| RMS supply current         | $I_{DD}$ CC       | –      | 2.5       | 4    | mA         | per active DAC channel, without load currents of DAC outputs              |
| Resolution                 | $RES$ CC          | –      | 12        | –    | Bit        |                                                                           |
| Update rate                | $f_{URATE\_A}$ CC | –      |           | 2    | Msample/s  | data rate, where DAC can follow 64 LSB code jumps to $\pm 1$ LSB accuracy |
| Update rate                | $f_{URATE\_F}$ CC | –      |           | 5    | Msample/s  | data rate, where DAC can follow 64 LSB code jumps to $\pm 4$ LSB accuracy |
| Settling time              | $t_{SETTLE}$ CC   | –      | 1         | 2    | $\mu$ s    | at full scale jump, output voltage reaches target value $\pm 20$ LSB      |
| Slew rate                  | $SR$ CC           | 2      | 5         | –    | V/ $\mu$ s |                                                                           |
| Minimum output voltage     | $V_{OUT\_MIN}$ CC | –      | 0.3       | –    | V          | code value unsigned: 000 <sub>H</sub> ; signed: 800 <sub>H</sub>          |
| Maximum output voltage     | $V_{OUT\_MAX}$ CC | –      | 2.5       | –    | V          | code value unsigned: FFF <sub>H</sub> ; signed: 7FF <sub>H</sub>          |
| Integral non-linearity     | $INL$ CC          | -5.5   | $\pm 2.5$ | 5.5  | LSB        | $R_L \geq 5$ kOhm, $C_L \leq 50$ pF                                       |
| Differential non-linearity | $DNL$ CC          | -2     | $\pm 1$   | 2    | LSB        | $R_L \geq 5$ kOhm, $C_L \leq 50$ pF                                       |
| Offset error               | $ED_{OFF}$ CC     |        | $\pm 20$  |      | mV         |                                                                           |

**Electrical Parameters**
**Table 26 DAC Parameters** (Operating Conditions apply) (cont'd)

| Parameter                      | Symbol               | Values |      |      | Unit | Note / Test Condition                                  |
|--------------------------------|----------------------|--------|------|------|------|--------------------------------------------------------|
|                                |                      | Min.   | Typ. | Max. |      |                                                        |
| Gain error                     | $ED_{G\_IN}$ CC      | -6.5   | -1.5 | 3    | %    |                                                        |
| Startup time                   | $t_{STARTUP}$ CC     | –      | 15   | 30   | μs   | time from output enabling till code valid $\pm 16$ LSB |
| 3dB Bandwidth of Output Buffer | $f_{C1}$ CC          | 2.5    | 5    | –    | MHz  | verified by design                                     |
| Output sourcing current        | $I_{OUT\_SOURCE}$ CC | –      | -30  | –    | mA   |                                                        |
| Output sinking current         | $I_{OUT\_SINK}$ CC   | –      | 0.6  | –    | mA   |                                                        |
| Output resistance              | $R_{OUT}$ CC         | –      | 50   | –    | Ohm  |                                                        |
| Load resistance                | $R_L$ SR             | 5      | –    | –    | kOhm |                                                        |
| Load capacitance               | $C_L$ SR             | –      | –    | 50   | pF   |                                                        |
| Signal-to-Noise Ratio          | $SNR$ CC             | –      | 70   | –    | dB   | examination bandwidth < 25 kHz                         |
| Total Harmonic Distortion      | $THD$ CC             | –      | 70   | –    | dB   | examination bandwidth < 25 kHz                         |
| Power Supply Rejection Ratio   | $PSRR$ CC            | –      | 56   | –    | dB   | to $V_{DDA}$ verified by design                        |

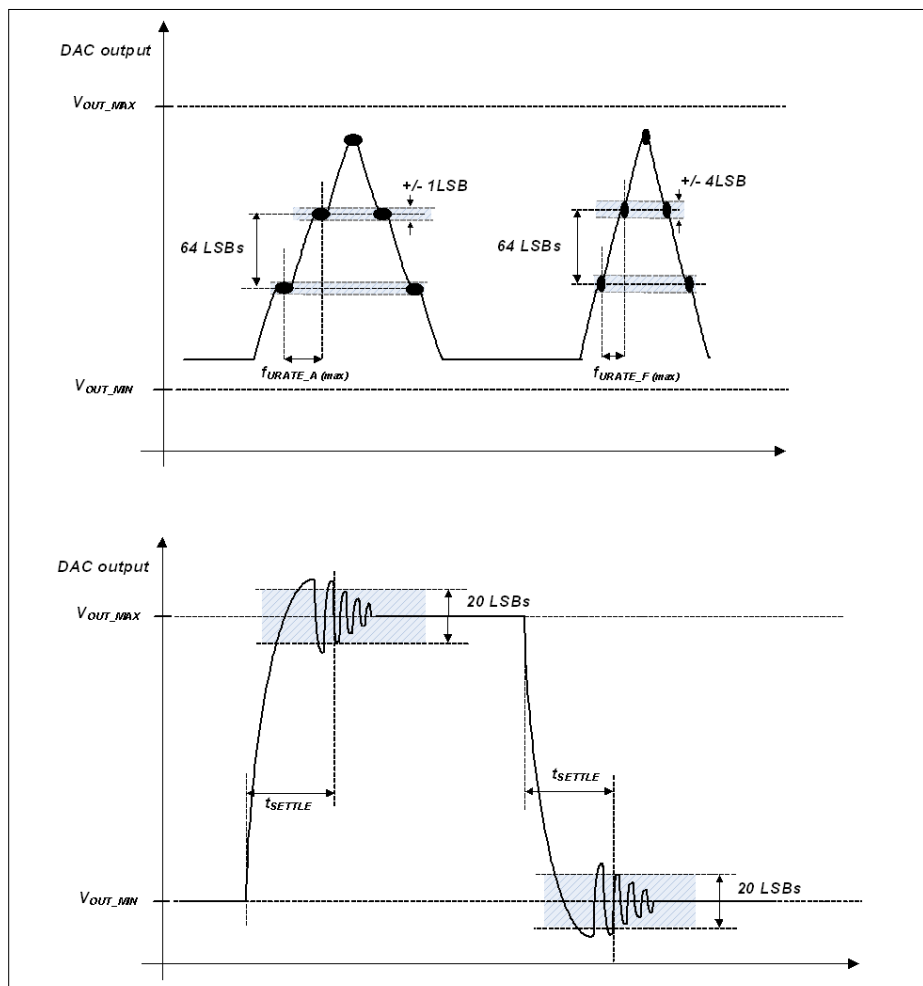
**Conversion Calculation**

Unsigned:

$$DACxDATA = 4095 \times (V_{OUT} - V_{OUT\_MIN}) / (V_{OUT\_MAX} - V_{OUT\_MIN})$$

Signed:

$$DACxDATA = 4095 \times (V_{OUT} - V_{OUT\_MIN}) / (V_{OUT\_MAX} - V_{OUT\_MIN}) - 2048$$



**Figure 13 DAC Conversion Examples**

**Electrical Parameters**

### 3.2.4 Out-of-Range Comparator (ORC)

The Out-of-Range Comparator (ORC) triggers on analog input voltages ( $V_{AIN}$ ) above the analog reference<sup>1)</sup> ( $V_{AREF}$ ) on selected input pins (GxORCy) and generates a service request trigger (GxORCOUTy).

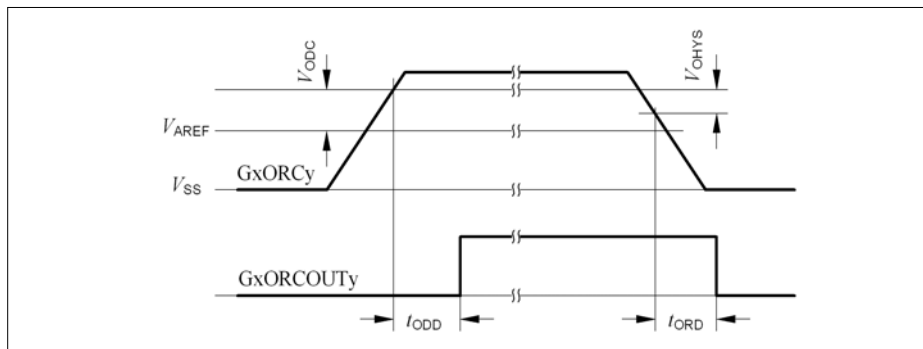
*Note: These parameters are not subject to production test, but verified by design and/or characterization.*

The parameters in **Table 27** apply for the maximum reference voltage  $V_{AREF} = V_{DDA} + 50 \text{ mV}$ .

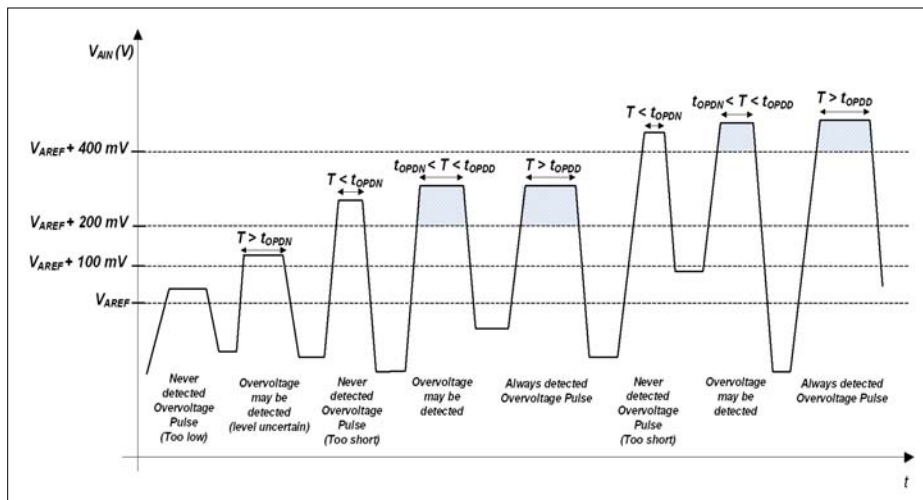
**Table 27 ORC Parameters** (Operating Conditions apply)

| Parameter                                   | Symbol     |    | Values |      |           | Unit | Note / Test Condition                    |
|---------------------------------------------|------------|----|--------|------|-----------|------|------------------------------------------|
|                                             |            |    | Min.   | Typ. | Max.      |      |                                          |
| DC Switching Level                          | $V_{ODC}$  | CC | 100    | 125  | 210       | mV   | $V_{AIN} \geq V_{AREF} + V_{ODC}$        |
| Hysteresis                                  | $V_{OHYS}$ | CC | 50     | –    | $V_{ODC}$ | mV   |                                          |
| Detection Delay of a persistent Overvoltage | $t_{ODD}$  | CC | 50     | –    | 450       | ns   | $V_{AIN} \geq V_{AREF} + 210 \text{ mV}$ |
|                                             |            |    | 45     | –    | 105       | ns   | $V_{AIN} \geq V_{AREF} + 400 \text{ mV}$ |
| Always detected Overvoltage Pulse           | $t_{OPDD}$ | CC | 440    | –    | –         | ns   | $V_{AIN} \geq V_{AREF} + 210 \text{ mV}$ |
|                                             |            |    | 90     | –    | –         | ns   | $V_{AIN} \geq V_{AREF} + 400 \text{ mV}$ |
| Never detected Overvoltage Pulse            | $t_{OPDN}$ | CC | –      | –    | 45        | ns   | $V_{AIN} \geq V_{AREF} + 210 \text{ mV}$ |
|                                             |            |    | –      | –    | 30        | ns   | $V_{AIN} \geq V_{AREF} + 400 \text{ mV}$ |
| Release Delay                               | $t_{ORD}$  | CC | 65     | –    | 105       | ns   | $V_{AIN} \leq V_{AREF}$                  |
| Enable Delay                                | $t_{OED}$  | CC | –      | 100  | 200       | ns   |                                          |

1) Always the standard VADC reference, alternate references do not apply to the ORC.



**Figure 14 GxORCOUTy Trigger Generation**



**Figure 15 ORC Detection Ranges**

### 3.2.5 Die Temperature Sensor

The Die Temperature Sensor (DTS) measures the junction temperature  $T_J$ .

*Note: These parameters are not subject to production test, but verified by design and/or characterization.*

**Table 28 Die Temperature Sensor Parameters**

| Parameter                                         | Symbol             | Values |      |      | Unit | Note / Test Condition                                                 |
|---------------------------------------------------|--------------------|--------|------|------|------|-----------------------------------------------------------------------|
|                                                   |                    | Min.   | Typ. | Max. |      |                                                                       |
| Temperature sensor range                          | $T_{SR}$ SR        | -40    | –    | 150  | °C   |                                                                       |
| Linearity Error<br>(to the below defined formula) | $\Delta T_{LE}$ CC | –      | ±1   | –    | °C   | per $\Delta T_J \leq 30$ °C                                           |
| Offset Error                                      | $\Delta T_{OE}$ CC | –      | ±6   | –    | °C   | $\Delta T_{OE} = T_J - T_{DTS}$<br>$V_{DDP} \leq 3.3$ V <sup>1)</sup> |
| Measurement time                                  | $t_M$ CC           | –      | –    | 100  | µs   |                                                                       |
| Start-up time after reset<br>inactive             | $t_{TSST}$ SR      | –      | –    | 10   | µs   |                                                                       |

1) At  $V_{DDP\_max} = 3.63$  V the typical offset error increases by an additional  $\Delta T_{OE} = \pm 1$  °C.

The following formula calculates the temperature measured by the DTS in [°C] from the RESULT bit field of the DTSSTAT register.

$$\text{Temperature } T_{DTS} = (\text{RESULT} - 605) / 2.05 \text{ [°C]}$$

This formula and the values defined in **Table 28** apply with the following calibration values:

- DTSCON.BGTRIM =  $8_H$
- DTSCON.REFTRIM =  $4_H$

### 3.2.6 USB OTG Interface DC Characteristics

The Universal Serial Bus (USB) Interface is compliant to the USB Rev. 2.0 Specification and the OTG Specification Rev. 1.3. High-Speed Mode is not supported.

*Note: These parameters are not subject to production test, but verified by design and/or characterization.*

**Table 29 USB OTG VBUS and ID Parameters** (Operating Conditions apply)

| Parameter                        | Symbol            | Values |      |      | Unit | Note / Test Condition                                                    |
|----------------------------------|-------------------|--------|------|------|------|--------------------------------------------------------------------------|
|                                  |                   | Min.   | Typ. | Max. |      |                                                                          |
| VBUS input voltage range         | $V_{IN}$ CC       | 0.0    | –    | 5.25 | V    |                                                                          |
| A-device VBUS valid threshold    | $V_{B1}$ CC       | 4.4    | –    | –    | V    |                                                                          |
| A-device session valid threshold | $V_{B2}$ CC       | 0.8    | –    | 2.0  | V    |                                                                          |
| B-device session valid threshold | $V_{B3}$ CC       | 0.8    | –    | 4.0  | V    |                                                                          |
| B-device session end threshold   | $V_{B4}$ CC       | 0.2    | –    | 0.8  | V    |                                                                          |
| VBUS input resistance to ground  | $R_{VBUS\_IN}$ CC | 40     | –    | 100  | kOhm |                                                                          |
| B-device VBUS pull-up resistor   | $R_{VBUS\_PU}$ CC | 281    | –    | –    | Ohm  | Pull-up voltage = 3.0 V                                                  |
| B-device VBUS pull-down resistor | $R_{VBUS\_PD}$ CC | 656    | –    | –    | Ohm  |                                                                          |
| USB.ID pull-up resistor          | $R_{UID\_PU}$ CC  | 14     | –    | 25   | kOhm |                                                                          |
| VBUS input current               | $I_{VBUS\_IN}$ CC | –      | –    | 150  | μA   | $0\text{ V} \leq V_{IN} \leq 5.25\text{ V}$ :<br>$T_{AVG} = 1\text{ ms}$ |

**Electrical Parameters**
**Table 30 USB OTG Data Line (USB\_DP, USB\_DM) Parameters** (Operating Conditions apply)

| Parameter                                     | Symbol    |    | Values |      |       | Unit | Note / Test Condition                 |
|-----------------------------------------------|-----------|----|--------|------|-------|------|---------------------------------------|
|                                               |           |    | Min.   | Typ. | Max.  |      |                                       |
| Input low voltage                             | $V_{IL}$  | SR | –      | –    | 0.8   | V    |                                       |
| Input high voltage (driven)                   | $V_{IH}$  | SR | 2.0    | –    | –     | V    |                                       |
| Input high voltage (floating) <sup>1)</sup>   | $V_{IHZ}$ | SR | 2.7    | –    | 3.6   | V    |                                       |
| Differential input sensitivity                | $V_{DIS}$ | CC | 0.2    | –    | –     | V    |                                       |
| Differential common mode range                | $V_{CM}$  | CC | 0.8    | –    | 2.5   | V    |                                       |
| Output low voltage                            | $V_{OL}$  | CC | 0.0    | –    | 0.3   | V    | 1.5 kOhm pull-up to 3.6 V             |
| Output high voltage                           | $V_{OH}$  | CC | 2.8    | –    | 3.6   | V    | 15 kOhm pull-down to 0 V              |
| DP pull-up resistor (idle bus)                | $R_{PUI}$ | CC | 900    | –    | 1 575 | Ohm  |                                       |
| DP pull-up resistor (upstream port receiving) | $R_{PUA}$ | CC | 1 425  | –    | 3 090 | Ohm  |                                       |
| DP, DM pull-down resistor                     | $R_{PD}$  | CC | 14.25  | –    | 24.8  | kOhm |                                       |
| Input impedance DP, DM                        | $Z_{INP}$ | CC | 300    | –    | –     | kOhm | $0\text{ V} \leq V_{IN} \leq V_{DDP}$ |
| Driver output resistance DP, DM               | $Z_{DRV}$ | CC | 28     | –    | 44    | Ohm  |                                       |

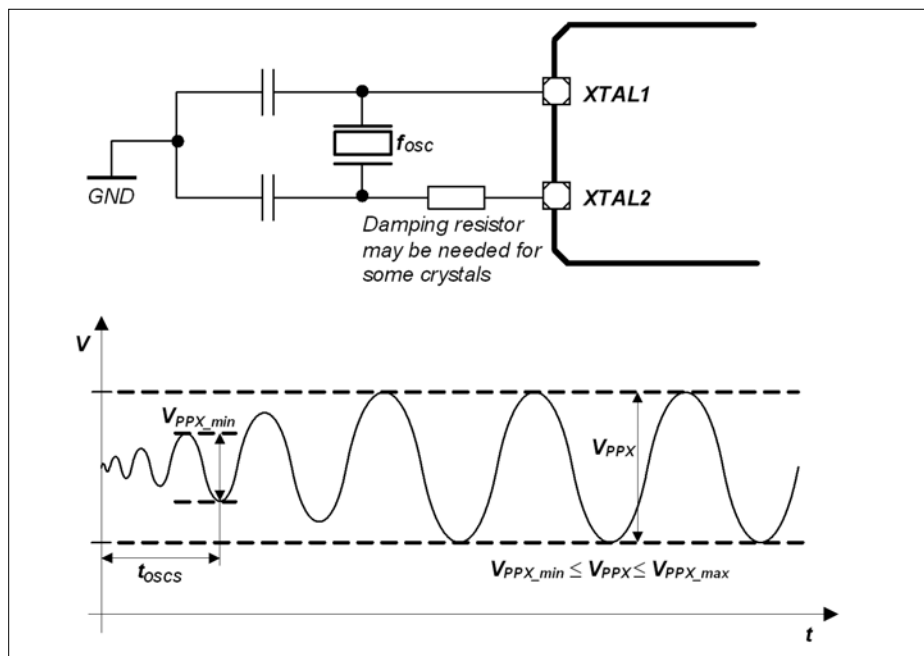
1) Measured at A-connector with 1.5 kOhm  $\pm$  5% to 3.3 V  $\pm$  0.3 V connected to USB\_DP or USB\_DM and at B-connector with 15 kOhm  $\pm$  5% to ground connected to USB\_DP and USB\_DM.

### 3.2.7 Oscillator Pins

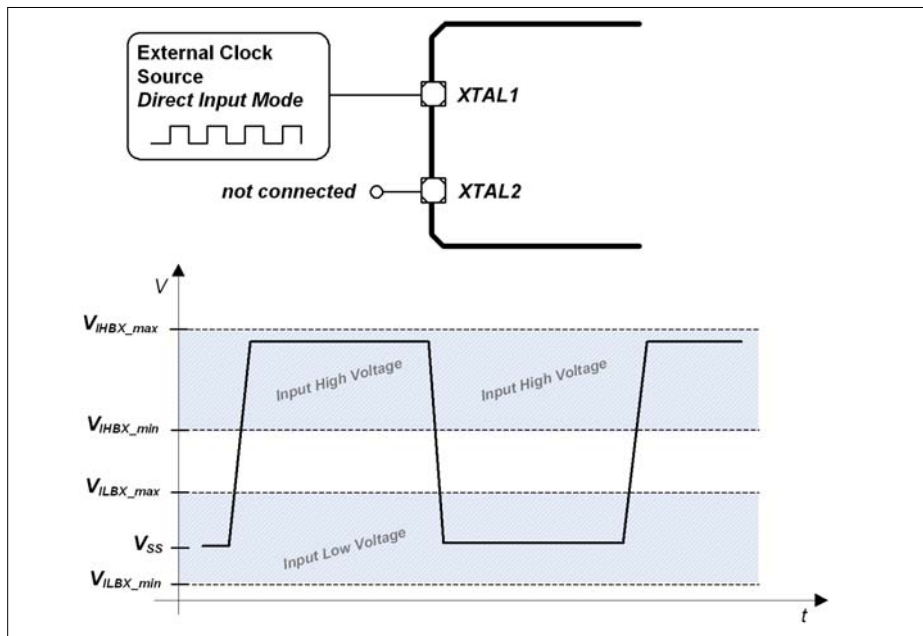
*Note: It is strongly recommended to measure the oscillation allowance (negative resistance) in the final target system (layout) to determine the optimal parameters for the oscillator operation. Please refer to the limits specified by the crystal or ceramic resonator supplier.*

*Note: These parameters are not subject to production test, but verified by design and/or characterization.*

The oscillator pins can be operated with an external crystal (see [Figure 16](#)) or in direct input mode (see [Figure 17](#)).



**Figure 16 Oscillator in Crystal Mode**



**Figure 17**    **Oscillator in Direct Input Mode**

**Table 31 OSC\_XTAL Parameters**

| Parameter                                               | Symbol               | Values                      |      |                        | Unit | Note / Test Condition                                                         |
|---------------------------------------------------------|----------------------|-----------------------------|------|------------------------|------|-------------------------------------------------------------------------------|
|                                                         |                      | Min.                        | Typ. | Max.                   |      |                                                                               |
| Input frequency                                         | $f_{\text{OSC}}$ SR  | 4                           | –    | 40                     | MHz  | Direct Input Mode selected                                                    |
|                                                         |                      | 4                           | –    | 25                     | MHz  | External Crystal Mode selected                                                |
| Oscillator start-up time <sup>1)2)</sup>                | $t_{\text{OSCS}}$ CC | –                           | –    | 10                     | ms   |                                                                               |
| Input voltage at XTAL1                                  | $V_{\text{IX}}$ SR   | -0.5                        | –    | $V_{\text{DDP}} + 0.5$ | V    |                                                                               |
| Input amplitude (peak-to-peak) at XTAL1 <sup>2)3)</sup> | $V_{\text{PPX}}$ SR  | $0.4 \times V_{\text{DDP}}$ | –    | $V_{\text{DDP}} + 1.0$ | V    |                                                                               |
| Input high voltage at XTAL1 <sup>4)</sup>               | $V_{\text{IHBX}}$ SR | 1.0                         | –    | $V_{\text{DDP}} + 0.5$ | V    |                                                                               |
| Input low voltage at XTAL1 <sup>4)</sup>                | $V_{\text{ILBX}}$ SR | -0.5                        | –    | 0.4                    | V    |                                                                               |
| Input leakage current at XTAL1                          | $I_{\text{ILX1}}$ CC | -100                        | –    | 100                    | nA   | Oscillator power down<br>$0 \text{ V} \leq V_{\text{IX}} \leq V_{\text{DDP}}$ |

1)  $t_{\text{OSCS}}$  is defined from the moment the oscillator is enabled with SCU\_OSCHPCTRL.MODE until the oscillations reach an amplitude at XTAL1 of  $0.4 \times V_{\text{DDP}}$ .

2) The external oscillator circuitry must be optimized by the customer and checked for negative resistance and amplitude as recommended and specified by crystal suppliers.

3) If the shaper unit is enabled and not bypassed.

4) If the shaper unit is bypassed, dedicated DC-thresholds have to be met.

**Table 32 RTC\_XTAL Parameters**

| Parameter                                                   | Symbol        | Values                |        |                       | Unit | Note / Test Condition                                           |
|-------------------------------------------------------------|---------------|-----------------------|--------|-----------------------|------|-----------------------------------------------------------------|
|                                                             |               | Min.                  | Typ.   | Max.                  |      |                                                                 |
| Input frequency                                             | $f_{OSC}$ SR  | –                     | 32.768 | –                     | kHz  |                                                                 |
| Oscillator start-up time <sup>1)2)3)</sup>                  | $t_{OSCS}$ CC | –                     | –      | 5                     | s    |                                                                 |
| Input voltage at RTC_XTAL1                                  | $V_{IX}$ SR   | -0.3                  | –      | $V_{BAT} + 0.3$       | V    |                                                                 |
| Input amplitude (peak-to-peak) at RTC_XTAL1 <sup>2)4)</sup> | $V_{PPX}$ SR  | 0.4                   | –      | –                     | V    |                                                                 |
| Input high voltage at RTC_XTAL1 <sup>5)</sup>               | $V_{IHBX}$ SR | $0.6 \times V_{BAT}$  | –      | $V_{BAT} + 0.3$       | V    |                                                                 |
| Input low voltage at RTC_XTAL1 <sup>5)</sup>                | $V_{ILBX}$ SR | -0.3                  | –      | $0.36 \times V_{BAT}$ | V    |                                                                 |
| Input Hysteresis for RTC_XTAL1 <sup>5)6)</sup>              | $V_{HYSX}$ CC | $0.1 \times V_{BAT}$  | –      | –                     | V    | $3.0 \text{ V} \leq V_{BAT} < 3.6 \text{ V}$                    |
|                                                             |               | $0.03 \times V_{BAT}$ | –      | –                     | V    | $V_{BAT} < 3.0 \text{ V}$                                       |
| Input leakage current at RTC_XTAL1                          | $I_{ILX1}$ CC | -100                  | –      | 100                   | nA   | Oscillator power down<br>$0 \text{ V} \leq V_{IX} \leq V_{BAT}$ |

- $t_{OSCS}$  is defined from the moment the oscillator is enabled by the user with SCU\_OSCULCTRL.MODE until the oscillations reach an amplitude at RTC\_XTAL1 of 400 mV.
- The external oscillator circuitry must be optimized by the customer and checked for negative resistance and amplitude as recommended and specified by crystal suppliers.
- For a reliable start of the oscillation in crystal mode it is required that  $V_{BAT} \geq 3.0 \text{ V}$ . A running oscillation is maintained across the full  $V_{BAT}$  voltage range.
- If the shaper unit is enabled and not bypassed.
- If the shaper unit is bypassed, dedicated DC-thresholds have to be met.
- Hysteresis is implemented to avoid metastable states and switching due to internal ground bounce. It can not be guaranteed that it suppresses switching due to external system noise.

### 3.2.8 Power Supply Current

The total power supply current defined below consists of a leakage and a switching component.

Application relevant values are typically lower than those given in the following tables, and depend on the customer's system operating conditions (e.g. thermal connection or used application configurations).

*Note: These parameters are not subject to production test, but verified by design and/or characterization.*

If not stated otherwise, the operating conditions for the parameters in the following table are:

$$V_{DDP} = 3.3 \text{ V}, T_A = 25 \text{ }^{\circ}\text{C}$$

**Table 33 Power Supply Parameters**

| Parameter                                                                                                              | Symbol        | Values |      |      | Unit | Note / Test Condition |
|------------------------------------------------------------------------------------------------------------------------|---------------|--------|------|------|------|-----------------------|
|                                                                                                                        |               | Min.   | Typ. | Max. |      |                       |
| Active supply current <sup>1)11)</sup><br>Peripherals enabled<br>Frequency:<br>$f_{CPU} / f_{PERIPH} / f_{CCU}$ in MHz | $I_{DDPA}$ CC | –      | 135  | –    | mA   | 144 / 144 / 144       |
|                                                                                                                        |               | –      | 125  | –    |      | 144 / 72 / 72         |
|                                                                                                                        |               | –      | 97   | –    |      | 72 / 72 / 144         |
|                                                                                                                        |               | –      | 80   | –    |      | 24 / 24 / 24          |
|                                                                                                                        |               | –      | 68   | –    |      | 1 / 1 / 1             |
| Active supply current<br>Code execution from RAM<br>Flash in Sleep mode                                                | $I_{DDPA}$ CC | –      | 108  | –    | mA   | 144 / 144 / 144       |
|                                                                                                                        |               | –      | 98   | –    |      | 144 / 72 / 72         |
| Active supply current <sup>2)</sup><br>Peripherals disabled<br>Frequency:<br>$f_{CPU} / f_{PERIPH} / f_{CCU}$ in MHz   | $I_{DDPA}$ CC | –      | 86   | –    | mA   | 144 / 144 / 144       |
|                                                                                                                        |               | –      | 85   | –    |      | 144 / 72 / 72         |
|                                                                                                                        |               | –      | 70   | –    |      | 72 / 72 / 144         |
|                                                                                                                        |               | –      | 55   | –    |      | 24 / 24 / 24          |
|                                                                                                                        |               | –      | 50   | –    |      | 1 / 1 / 1             |
| Sleep supply current <sup>3)</sup><br>Peripherals enabled<br>Frequency:<br>$f_{CPU} / f_{PERIPH} / f_{CCU}$ in MHz     | $I_{DDPS}$ CC | –      | 127  | –    | mA   | 144 / 144 / 144       |
|                                                                                                                        |               | –      | 115  | –    |      | 144 / 72 / 72         |
|                                                                                                                        |               | –      | 93   | –    |      | 72 / 72 / 144         |
|                                                                                                                        |               | –      | 57   | –    |      | 24 / 24 / 24          |
|                                                                                                                        |               | –      | 47   | –    |      | 1 / 1 / 1             |
|                                                                                                                        |               | –      | 48   | –    |      | 100 / 100 / 100       |
| $f_{CPU} / f_{PERIPH} / f_{CCU}$ in kHz                                                                                |               |        |      |      |      |                       |

**Electrical Parameters**
**Table 33 Power Supply Parameters**

| Parameter                                                                                                                                                                                                     | Symbol              | Values |      |                    | Unit    | Note / Test Condition                |
|---------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|---------------------|--------|------|--------------------|---------|--------------------------------------|
|                                                                                                                                                                                                               |                     | Min.   | Typ. | Max.               |         |                                      |
| Sleep supply current <sup>4)</sup><br>Peripherals disabled<br>Frequency:<br>$f_{CPU} / f_{PERIPH} / f_{CCU}$ in MHz                                                                                           | $I_{DDPS}$ CC       | –      | 77   | –                  | mA      | 144 / 144 / 144                      |
|                                                                                                                                                                                                               |                     | –      | 76   | –                  |         | 144 / 72 / 72                        |
|                                                                                                                                                                                                               |                     | –      | 65   | –                  |         | 72 / 72 / 144                        |
|                                                                                                                                                                                                               |                     | –      | 53   | –                  |         | 24 / 24 / 24                         |
|                                                                                                                                                                                                               |                     | –      | 46   | –                  |         | 1 / 1 / 1                            |
|                                                                                                                                                                                                               |                     | –      | 47   | –                  |         | 100 / 100 / 100                      |
| $f_{CPU} / f_{PERIPH} / f_{CCU}$ in kHz<br>Deep Sleep supply current <sup>5)</sup><br>Flash in Sleep mode<br>Frequency:<br>$f_{CPU} / f_{PERIPH} / f_{CCU}$ in MHz<br>$f_{CPU} / f_{PERIPH} / f_{CCU}$ in kHz | $I_{DDPD}$ CC       | –      | 11   | –                  | mA      | 24 / 24 / 24                         |
|                                                                                                                                                                                                               |                     | –      | 7.0  | –                  |         | 4 / 4 / 4                            |
|                                                                                                                                                                                                               |                     | –      | 6.6  | –                  |         | 1 / 1 / 1                            |
|                                                                                                                                                                                                               |                     | –      | 7.6  | –                  |         | 100 / 100 / 100 <sup>6)</sup>        |
| Hibernate supply current<br>RTC on <sup>7)</sup>                                                                                                                                                              | $I_{DDPH}$ CC       | –      | 8.7  | –                  | $\mu$ A | $V_{BAT} = 3.3$ V                    |
|                                                                                                                                                                                                               |                     | –      | 6.5  | –                  |         | $V_{BAT} = 2.4$ V                    |
|                                                                                                                                                                                                               |                     | –      | 5.7  | –                  |         | $V_{BAT} = 2.0$ V                    |
| Hibernate supply current<br>RTC off <sup>8)</sup>                                                                                                                                                             | $I_{DDPH}$ CC       | –      | 8.0  | –                  | $\mu$ A | $V_{BAT} = 3.3$ V                    |
|                                                                                                                                                                                                               |                     | –      | 6.0  | –                  |         | $V_{BAT} = 2.4$ V                    |
|                                                                                                                                                                                                               |                     | –      | 5.0  | –                  |         | $V_{BAT} = 2.0$ V                    |
| Hibernate off <sup>9)</sup>                                                                                                                                                                                   | $I_{DDPH}$ CC       | –      | 4.4  | –                  | $\mu$ A | $V_{BAT} = 3.3$ V                    |
|                                                                                                                                                                                                               |                     | –      | 3.5  | –                  |         | $V_{BAT} = 2.4$ V                    |
|                                                                                                                                                                                                               |                     | –      | 3.1  | –                  |         | $V_{BAT} = 2.0$ V                    |
| Worst case active supply current <sup>10)</sup>                                                                                                                                                               | $I_{DDPA}$ CC       | –      | –    | 250 <sup>11)</sup> | mA      | $V_{DDP} = 3.6$ V,<br>$T_J = 150$ °C |
| $V_{DDA}$ power supply current                                                                                                                                                                                | $I_{DDA}$ CC        | –      | –    | – <sup>12)</sup>   | mA      |                                      |
| $I_{DDP}$ current at PORST Low                                                                                                                                                                                | $I_{DDP\_PORST}$ CC | –      | 5    | 10                 | mA      | $V_{DDP} = 3.3$ V,<br>$T_J = 25$ °C  |
|                                                                                                                                                                                                               |                     | –      | 13   | 55                 | mA      | $V_{DDP} = 3.6$ V,<br>$T_J = 150$ °C |
| Power Dissipation                                                                                                                                                                                             | $P_{DISS}$ CC       | –      | –    | 1.4                | W       | $V_{DDP} = 3.6$ V,<br>$T_J = 150$ °C |

**Electrical Parameters**

**Table 33 Power Supply Parameters**

| Parameter                                   | Symbol       | Values |      |      | Unit   | Note / Test Condition                                                            |
|---------------------------------------------|--------------|--------|------|------|--------|----------------------------------------------------------------------------------|
|                                             |              | Min.   | Typ. | Max. |        |                                                                                  |
| Wake-up time from Sleep to Active mode      | $t_{SSA}$ CC | —      | 6    | —    | cycles |                                                                                  |
| Wake-up time from Deep Sleep to Active mode |              | —      | —    | —    | ms     | Defined by the wake-up of the Flash module, see <b>“Flash Memory Parameters”</b> |
| Wake-up time from Hibernate mode            |              | —      | —    | —    | ms     | Wake-up via power-on reset event, see <b>“Power-Up and Supply Monitoring”</b>    |

- 1) CPU executing code from Flash, all peripherals idle.
- 2) CPU executing code from Flash.
- 3) CPU in sleep, all peripherals idle, Flash in Active mode.
- 4) CPU in sleep, Flash in Active mode.
- 5) CPU in sleep, peripherals disabled, after wake-up code execution from RAM.
- 6) To wake-up the Flash from its Sleep mode,  $f_{CPU} \geq 1$  MHz is required.
- 7) OSC\_ULP operating with external crystal on RTC\_XTAL
- 8) OSC\_ULP off, Hibernate domain operating with OSC\_SI clock
- 9)  $V_{BAT}$  supplied, but Hibernate domain not started; for example state after factory assembly
- 10) Test Power Loop:  $f_{SYS} = 144$  MHz, CPU executing benchmark code from Flash, all CCUs in 100kHz timer mode, all ADC groups in continuous conversion mode, USICs as SPI in internal loop-back mode, CAN in 500kHz internal loop-back mode, interrupt triggered DMA block transfers to parity protected RAMs and FCE, DTS measurements and FPU calculations.  
The power consumption of each customer application will most probably be lower than this value, but must be evaluated separately.
- 11)  $I_{DDP}$  decreases typically by approximately 5 mA when  $f_{SYS}$  decreases by 10 MHz, at constant  $T_J$
- 12) Sum of currents of all active converters (ADC and DAC)

**Peripheral Idle Currents**

Default test conditions:

- $f_{\text{sys}}$  and derived clocks at 144 MHz
- $V_{\text{DDP}} = 3.3 \text{ V}$ ,  $T_a = 25^\circ \text{C}$
- all peripherals are held in reset (see the PRSTAT registers in the Reset Control Unit of the SCU)
- the peripheral clocks are disabled (see CGATSTAT registers in the Clock Control Unit of the SCU)
- no I/O activity

The given values are a result of differential measurements with asserted and deasserted peripheral reset as well as disabled and enabled clock of the peripheral under test.

The tested peripheral is left in the state after the peripheral reset is deasserted, no further initialisation or configuration is done. E.g. no timer is running in the CCUs, no communication active in the USICs, etc.

**Table 34 Peripheral Idle Currents**

| Parameter                                                                       | Symbol              | Values |            |      | Unit | Note / Test Condition |
|---------------------------------------------------------------------------------|---------------------|--------|------------|------|------|-----------------------|
|                                                                                 |                     | Min.   | Typ.       | Max. |      |                       |
| PORTS<br>FCE<br>WDT                                                             | $I_{\text{PER CC}}$ | –      | $\leq 0.3$ | –    | mA   |                       |
| MultiCAN<br>ERU<br>LEDTSCU0<br>ETH<br>CCU4x <sup>1)</sup> , CCU8x <sup>1)</sup> |                     | –      | $\leq 1.0$ | –    |      |                       |
| DAC (digital) <sup>2)</sup>                                                     |                     | –      | 1.3        | –    |      |                       |
| USICx<br>SDMMC                                                                  |                     | –      | 3.0        | –    |      |                       |
| VADC (digital) <sup>2)</sup>                                                    |                     | –      | 4.5        | –    |      |                       |
| DMA0, USB, EtherCAT                                                             |                     | –      | 6.0        | –    |      |                       |

1) Enabling the  $f_{\text{CCU}}$  clock for the CCU4x/CCU8x modules adds approximately  $I_{\text{PER}} = 4.8 \text{ mA}$ , disregarding which and how many of those peripherals are enabled.

2) The current consumption of the analog components are given in the dedicated Data Sheet sections of the respective peripheral.

### 3.2.9 Flash Memory Parameters

*Note: These parameters are not subject to production test, but verified by design and/or characterization.*

**Table 35 Flash Memory Parameters**

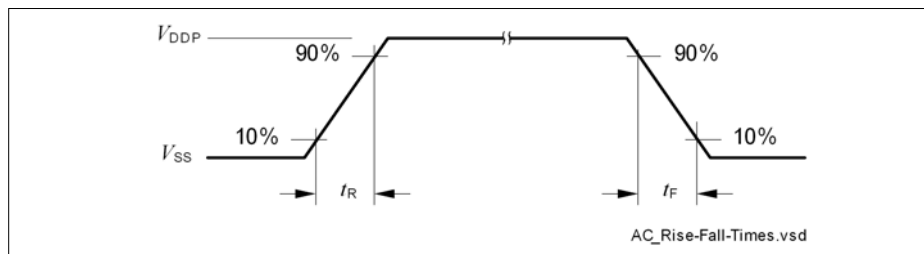
| Parameter                                                           | Symbol                 | Values |      |      | Unit   | Note / Test Condition                                                             |
|---------------------------------------------------------------------|------------------------|--------|------|------|--------|-----------------------------------------------------------------------------------|
|                                                                     |                        | Min.   | Typ. | Max. |        |                                                                                   |
| Erase Time per 256 Kbyte Sector                                     | $t_{ERP}$ CC           | –      | 5    | 5.5  | s      |                                                                                   |
| Erase Time per 64 Kbyte Sector                                      | $t_{ERP}$ CC           | –      | 1.2  | 1.4  | s      |                                                                                   |
| Erase Time per 16 Kbyte Logical Sector                              | $t_{ERP}$ CC           | –      | 0.3  | 0.4  | s      |                                                                                   |
| Program time per page <sup>1)</sup>                                 | $t_{PRP}$ CC           | –      | 5.5  | 11   | ms     |                                                                                   |
| Erase suspend delay                                                 | $t_{FL\_ErSusp}$ CC    | –      | –    | 15   | ms     |                                                                                   |
| Wait time after margin change                                       | $t_{FL\_MarginDel}$ CC | 10     | –    | –    | μs     |                                                                                   |
| Wake-up time                                                        | $t_{WU}$ CC            | –      | –    | 270  | μs     |                                                                                   |
| Read access time                                                    | $t_a$ CC               | 22     | –    | –    | ns     | For operation with $1/f_{CPU} < t_a$ wait states must be configured <sup>2)</sup> |
| Data Retention Time, Physical Sector <sup>3)4)</sup>                | $t_{RET}$ CC           | 20     | –    | –    | years  | Max. 1000 erase/program cycles                                                    |
| Data Retention Time, Logical Sector <sup>3)4)</sup>                 | $t_{RETL}$ CC          | 20     | –    | –    | years  | Max. 100 erase/program cycles                                                     |
| Data Retention Time, User Configuration Block (UCB) <sup>3)4)</sup> | $t_{RTU}$ CC           | 20     | –    | –    | years  | Max. 4 erase/program cycles per UCB                                               |
| Endurance on 64 Kbyte Physical Sector PS4                           | $N_{EPS4}$ CC          | 10000  | –    | –    | cycles | Cycling distributed over life time <sup>5)</sup>                                  |

**Electrical Parameters**

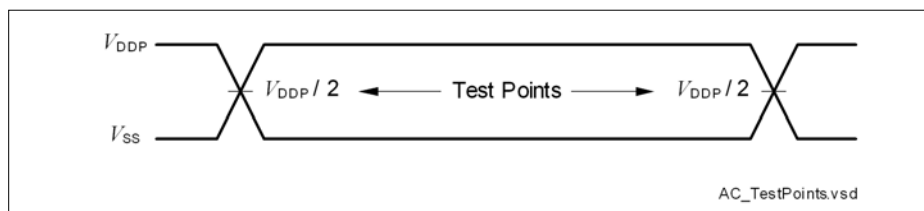
- 1) In case the Program Verify feature detects weak bits, these bits will be programmed once more. The reprogramming takes an additional time of 5.5 ms.
- 2) The following formula applies to the wait state configuration:  $FCON.WSPFLASH \times (1 / f_{CPU}) \geq t_a$ .
- 3) Storage and inactive time included.
- 4) Values given are valid for an average weighted junction temperature of  $T_J = 110^\circ\text{C}$ .
- 5) Only valid with robust EEPROM emulation algorithm, equally cycling the logical sectors. For more details see the Reference Manual.

### 3.3 AC Parameters

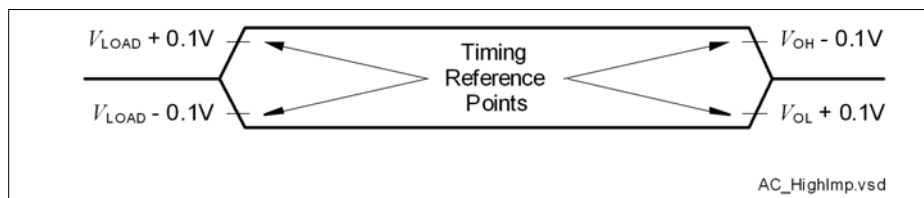
#### 3.3.1 Testing Waveforms



**Figure 18 Rise/Fall Time Parameters**



**Figure 19 Testing Waveform, Output Delay**

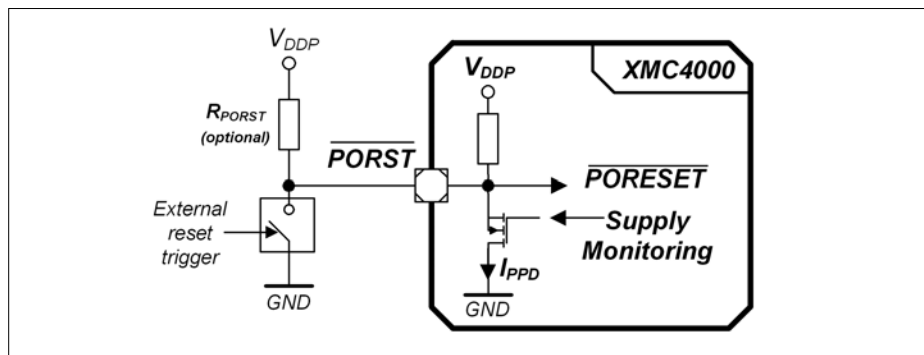


**Figure 20 Testing Waveform, Output High Impedance**

### 3.3.2 Power-Up and Supply Monitoring

$\overline{\text{PORST}}$  is always asserted when  $V_{\text{DDP}}$  and/or  $V_{\text{DDC}}$  violate the respective thresholds.

*Note: These parameters are not subject to production test, but verified by design and/or characterization.*



**Figure 21** **PORST Circuit**

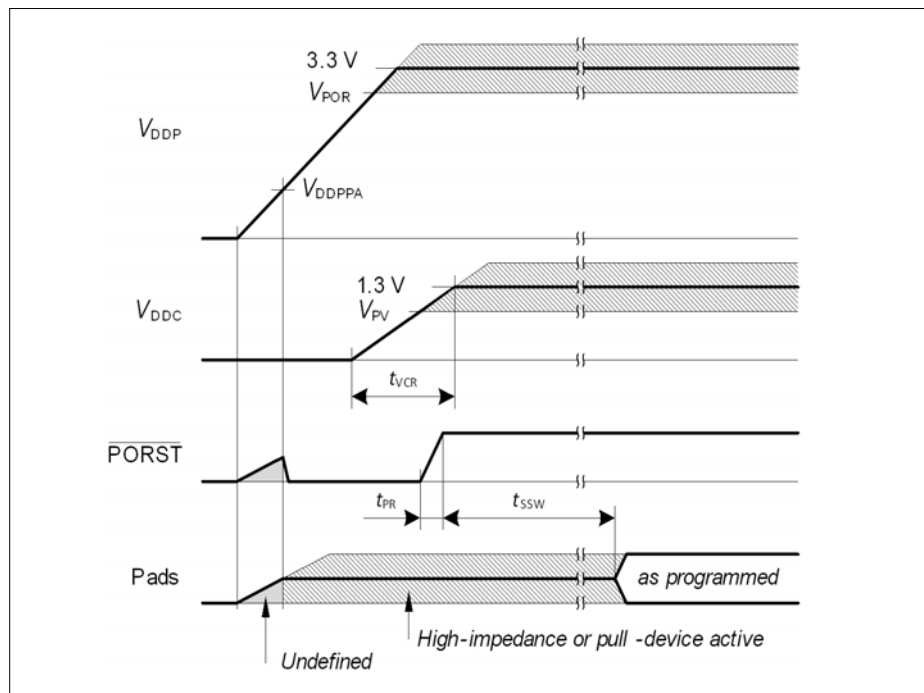
**Table 36** **Supply Monitoring Parameters**

| Parameter                                                       | Symbol                | Values             |      |                    | Unit          | Note / Test Condition                                                                                   |
|-----------------------------------------------------------------|-----------------------|--------------------|------|--------------------|---------------|---------------------------------------------------------------------------------------------------------|
|                                                                 |                       | Min.               | Typ. | Max.               |               |                                                                                                         |
| Digital supply voltage reset threshold                          | $V_{\text{POR}}$ CC   | 2.79 <sup>1)</sup> | –    | 3.05 <sup>2)</sup> | V             | 3)                                                                                                      |
| Core supply voltage reset threshold                             | $V_{\text{PV}}$ CC    | –                  | –    | 1.17               | V             |                                                                                                         |
| $V_{\text{DDP}}$ voltage to ensure defined pad states           | $V_{\text{DDPPA}}$ CC | –                  | 1.0  | –                  | V             |                                                                                                         |
| $\overline{\text{PORST}}$ rise time                             | $t_{\text{PR}}$ SR    | –                  | –    | 2                  | $\mu\text{s}$ | 4)                                                                                                      |
| Startup time from power-on reset with code execution from Flash | $t_{\text{SSW}}$ CC   | –                  | 2.5  | 3.5                | ms            | Time to the first user code instruction                                                                 |
| $V_{\text{DDC}}$ ramp up time                                   | $t_{\text{VCR}}$ CC   | –                  | 550  | –                  | $\mu\text{s}$ | Ramp up after power-on or after a reset triggered by a violation of $V_{\text{POR}}$ or $V_{\text{PV}}$ |

1) Minimum threshold for reset assertion.

## Electrical Parameters

- 2) Maximum threshold for reset deassertion.
- 3) The  $V_{DDP}$  monitoring has a typical hysteresis of  $V_{PORHYS} = 180 \text{ mV}$ .
- 4) If  $t_{PR}$  is not met, low spikes on  $\overline{\text{PORST}}$  may be seen during start up (e.g. reset pulses generated by the supply monitoring due to a slow ramping  $V_{DDP}$ ).



**Figure 22 Power-Up Behavior**

**Electrical Parameters**
**3.3.3 Power Sequencing**

While starting up and shutting down as well as when switching power modes of the system it is important to limit the current load steps. A typical cause for such load steps is changing the CPU frequency  $f_{\text{CPU}}$ . Load steps exceeding the below defined values may cause a power on reset triggered by the supply monitor.

*Note: These parameters are not subject to production test, but verified by design and/or characterization.*

**Table 37 Power Sequencing Parameters**

| Parameter                                                  | Symbol                     | Values |      |           | Unit          | Note / Test Condition                                                   |
|------------------------------------------------------------|----------------------------|--------|------|-----------|---------------|-------------------------------------------------------------------------|
|                                                            |                            | Min.   | Typ. | Max.      |               |                                                                         |
| Positive Load Step Current                                 | $\Delta I_{\text{PLS}}$ SR | -      | -    | 50        | mA            | Load increase on $V_{\text{DDP}}$<br>$\Delta t \leq 10 \text{ ns}$      |
| Negative Load Step Current                                 | $\Delta I_{\text{NLS}}$ SR | -      | -    | 150       | mA            | Load decrease on $V_{\text{DDP}}$<br>$\Delta t \leq 10 \text{ ns}$      |
| $V_{\text{DDC}}$ Voltage Over- / Undershoot from Load Step | $\Delta V_{\text{LS}}$ CC  | -      | -    | $\pm 100$ | mV            | For maximum positive or negative load step                              |
| Positive Load Step Settling Time                           | $t_{\text{PLSS}}$ SR       | 50     | -    | -         | $\mu\text{s}$ |                                                                         |
| Negative Load Step Settling Time                           | $t_{\text{NLSS}}$ SR       | 100    | -    | -         | $\mu\text{s}$ |                                                                         |
| External Buffer Capacitor on $V_{\text{DDC}}$              | $C_{\text{EXT}}$ SR        | -      | 10   | -         | $\mu\text{F}$ | In addition $C = 100 \text{ nF}$ capacitor on each $V_{\text{DDC}}$ pin |

**Positive Load Step Examples**

System assumptions:

$f_{\text{CPU}} = f_{\text{SYS}}$ , target frequency  $f_{\text{CPU}} = 144 \text{ MHz}$ , main PLL  $f_{\text{VCO}} = 288 \text{ MHz}$ , stepping done by K2 divider,  $t_{\text{PLSS}}$  between individual steps:

24 MHz - 48 MHz - 72 MHz - 96 MHz - 144 MHz (K2 steps 12 - 6 - 4 - 3 - 2)

24 MHz - 48 MHz - 96 MHz - 144 MHz (K2 steps 12 - 6 - 3 - 2)

24 MHz - 72 MHz - 144 MHz (K2 steps 12 - 4 - 2)

**Electrical Parameters**
**3.3.4 Phase Locked Loop (PLL) Characteristics**

*Note: These parameters are not subject to production test, but verified by design and/or characterization.*

**Main and USB PLL**
**Table 38 PLL Parameters**

| Parameter                | Symbol           | Values |      |      | Unit | Note / Test Condition                                           |
|--------------------------|------------------|--------|------|------|------|-----------------------------------------------------------------|
|                          |                  | Min.   | Typ. | Max. |      |                                                                 |
| Accumulated Jitter       | $D_P$ CC         | –      | –    | ±5   | ns   | accumulated over 300 cycles<br>$f_{SYS} = 144$ MHz              |
| Duty Cycle <sup>1)</sup> | $D_{DC}$ CC      | 46     | 50   | 54   | %    | Low pulse to total period, assuming an ideal input clock source |
| PLL base frequency       | $f_{PLLBASE}$ CC | 30     | –    | 140  | MHz  |                                                                 |
| VCO input frequency      | $f_{REF}$ CC     | 4      | –    | 16   | MHz  |                                                                 |
| VCO frequency range      | $f_{VCO}$ CC     | 260    | –    | 520  | MHz  |                                                                 |
| PLL lock-in time         | $t_L$ CC         | –      | –    | 400  | μs   |                                                                 |

1) 50% for even K2 divider values,  $50 \pm (10/K2)$  for odd K2 divider values.

### 3.3.5 Internal Clock Source Characteristics

*Note: These parameters are not subject to production test, but verified by design and/or characterization.*

#### Fast Internal Clock Source

**Table 39 Fast Internal Clock Parameters**

| Parameter         | Symbol                     | Values |      |      | Unit          | Note / Test Condition                                                                                  |
|-------------------|----------------------------|--------|------|------|---------------|--------------------------------------------------------------------------------------------------------|
|                   |                            | Min.   | Typ. | Max. |               |                                                                                                        |
| Nominal frequency | $f_{\text{OFINC}}$ CC      | –      | 36.5 | –    | MHz           | not calibrated                                                                                         |
|                   |                            | –      | 24   | –    | MHz           | calibrated                                                                                             |
| Accuracy          | $\Delta f_{\text{OFI}}$ CC | -0.5   | –    | 0.5  | %             | automatic calibration <sup>1)2)</sup>                                                                  |
|                   |                            | -15    | –    | 15   | %             | factory calibration, $V_{\text{DDP}} = 3.3 \text{ V}$                                                  |
|                   |                            | -25    | –    | 25   | %             | no calibration, $V_{\text{DDP}} = 3.3 \text{ V}$                                                       |
|                   |                            | -7     | –    | 7    | %             | Variation over voltage range <sup>3)</sup><br>$3.13 \text{ V} \leq V_{\text{DDP}} \leq 3.63 \text{ V}$ |
| Start-up time     | $t_{\text{OFIS}}$ CC       | –      | 50   | –    | $\mu\text{s}$ |                                                                                                        |

1) Error in addition to the accuracy of the reference clock.

2) Automatic calibration compensates variations of the temperature and in the  $V_{\text{DDP}}$  supply voltage.

3) Deviations from the nominal  $V_{\text{DDP}}$  voltage induce an additional error to the uncalibrated and/or factory calibrated oscillator frequency.

**Electrical Parameters**

**Slow Internal Clock Source**

**Table 40 Slow Internal Clock Parameters**

| Parameter         | Symbol                     | Values |        |      | Unit          | Note / Test Condition                                                                                                            |
|-------------------|----------------------------|--------|--------|------|---------------|----------------------------------------------------------------------------------------------------------------------------------|
|                   |                            | Min.   | Typ.   | Max. |               |                                                                                                                                  |
| Nominal frequency | $f_{\text{OSI}}$ CC        | –      | 32.768 | –    | kHz           |                                                                                                                                  |
| Accuracy          | $\Delta f_{\text{OSI}}$ CC | -4     | –      | 4    | %             | $V_{\text{BAT}} = \text{const.}$<br>$0\text{ }^{\circ}\text{C} \leq T_{\text{A}} \leq 85\text{ }^{\circ}\text{C}$                |
|                   |                            | -5     | –      | 5    | %             | $V_{\text{BAT}} = \text{const.}$<br>$T_{\text{A}} < 0\text{ }^{\circ}\text{C}$ or<br>$T_{\text{A}} > 85\text{ }^{\circ}\text{C}$ |
|                   |                            | -5     | –      | 5    | %             | $2.4\text{ V} \leq V_{\text{BAT}},$<br>$T_{\text{A}} = 25\text{ }^{\circ}\text{C}$                                               |
|                   |                            | -10    | –      | 10   | %             | $1.95\text{ V} \leq V_{\text{BAT}} < 2.4\text{ V},$<br>$T_{\text{A}} = 25\text{ }^{\circ}\text{C}$                               |
| Start-up time     | $t_{\text{OSIS}}$ CC       | –      | 50     | –    | $\mu\text{s}$ |                                                                                                                                  |

### 3.3.6 JTAG Interface Timing

The following parameters are applicable for communication through the JTAG debug interface. The JTAG module is fully compliant with IEEE1149.1-2000.

*Note: These parameters are not subject to production test, but verified by design and/or characterization.*

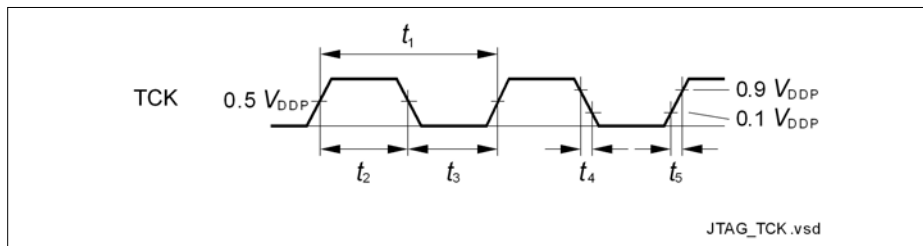
*Note: Operating conditions apply.*

**Table 41 JTAG Interface Timing Parameters**

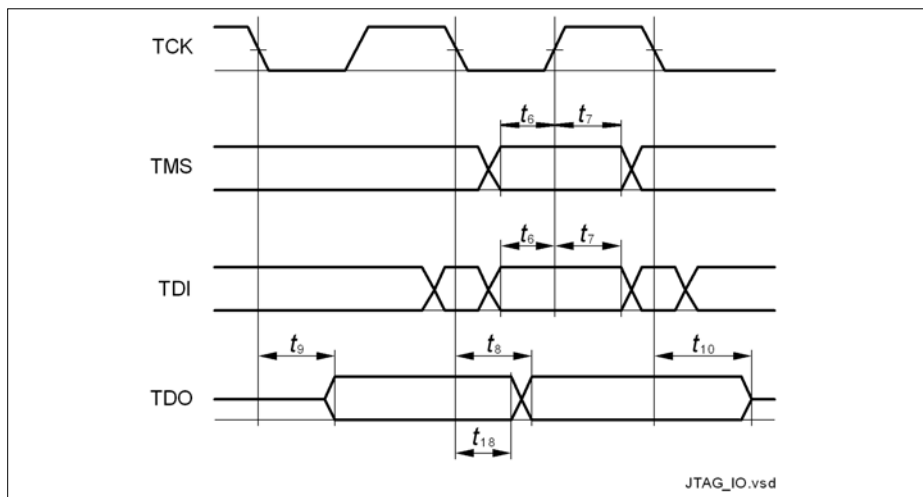
| Parameter                                                          | Symbol      | Values |      |      | Unit | Note / Test Condition |
|--------------------------------------------------------------------|-------------|--------|------|------|------|-----------------------|
|                                                                    |             | Min.   | Typ. | Max. |      |                       |
| TCK clock period                                                   | $t_1$ SR    | 25     | —    | —    | ns   |                       |
| TCK high time                                                      | $t_2$ SR    | 10     | —    | —    | ns   |                       |
| TCK low time                                                       | $t_3$ SR    | 10     | —    | —    | ns   |                       |
| TCK clock rise time                                                | $t_4$ SR    | —      | —    | 4    | ns   |                       |
| TCK clock fall time                                                | $t_5$ SR    | —      | —    | 4    | ns   |                       |
| TDI/TMS setup to TCK rising edge                                   | $t_6$ SR    | 6      | —    | —    | ns   |                       |
| TDI/TMS hold after TCK rising edge                                 | $t_7$ SR    | 6      | —    | —    | ns   |                       |
| TDO valid after TCK falling edge <sup>1)</sup> (propagation delay) | $t_8$ CC    | —      | —    | 13   | ns   | $C_L = 50$ pF         |
|                                                                    |             | 3      | —    | —    | ns   | $C_L = 20$ pF         |
| TDO hold after TCK falling edge <sup>1)</sup>                      | $t_{18}$ CC | 2      | —    | —    | ns   |                       |
| TDO high imped. to valid from TCK falling edge <sup>1)2)</sup>     | $t_9$ CC    | —      | —    | 14   | ns   | $C_L = 50$ pF         |
| TDO valid to high imped. from TCK falling edge <sup>1)</sup>       | $t_{10}$ CC | —      | —    | 13.5 | ns   | $C_L = 50$ pF         |

1) The falling edge on TCK is used to generate the TDO timing.

2) The setup time for TDO is given implicitly by the TCK cycle time.



**Figure 23 Test Clock Timing (TCK)**



**Figure 24 JTAG Timing**

### 3.3.7 Serial Wire Debug Port (SW-DP) Timing

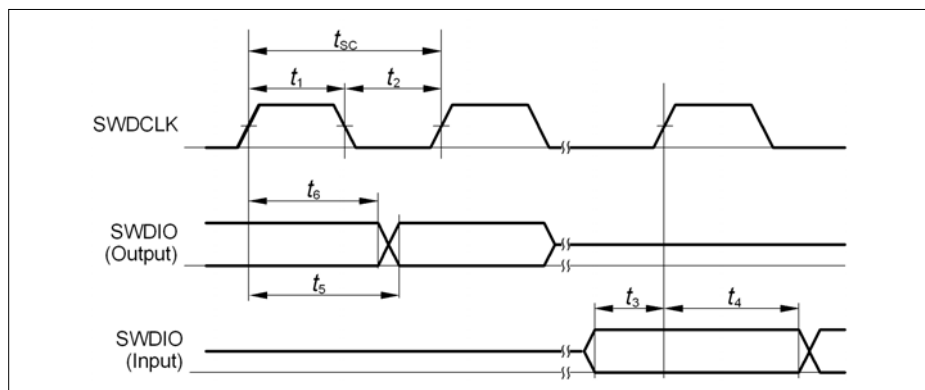
The following parameters are applicable for communication through the SW-DP interface.

*Note: These parameters are not subject to production test, but verified by design and/or characterization.*

*Note: Operating conditions apply.*

**Table 42 SWD Interface Timing Parameters** (Operating Conditions apply)

| Parameter                                        | Symbol   |    | Values |      |        | Unit | Note / Test Condition |
|--------------------------------------------------|----------|----|--------|------|--------|------|-----------------------|
|                                                  |          |    | Min.   | Typ. | Max.   |      |                       |
| SWDCLK clock period                              | $t_{SC}$ | SR | 25     | —    | —      | ns   | $C_L = 30 \text{ pF}$ |
|                                                  |          |    | 40     | —    | —      | ns   | $C_L = 50 \text{ pF}$ |
| SWDCLK high time                                 | $t_1$    | SR | 10     | —    | 500000 | ns   |                       |
| SWDCLK low time                                  | $t_2$    | SR | 10     | —    | 500000 | ns   |                       |
| SWDIO input setup to SWDCLK rising edge          | $t_3$    | SR | 6      | —    | —      | ns   |                       |
| SWDIO input hold after SWDCLK rising edge        | $t_4$    | SR | 6      | —    | —      | ns   |                       |
| SWDIO output valid time after SWDCLK rising edge | $t_5$    | CC | —      | —    | 17     | ns   | $C_L = 50 \text{ pF}$ |
|                                                  |          |    | —      | —    | 13     | ns   | $C_L = 30 \text{ pF}$ |
| SWDIO output hold time from SWDCLK rising edge   | $t_6$    | CC | 3      | —    | —      | ns   |                       |



**Figure 25 SWD Timing**

### 3.3.8 Peripheral Timing

#### 3.3.8.1 Synchronous Serial Interface (USIC SSC) Timing

The following parameters are applicable for a USIC channel operated in SSC mode.

*Note: These parameters are not subject to production test, but verified by design and/or characterization.*

**Table 43 USIC SSC Master Mode Timing**

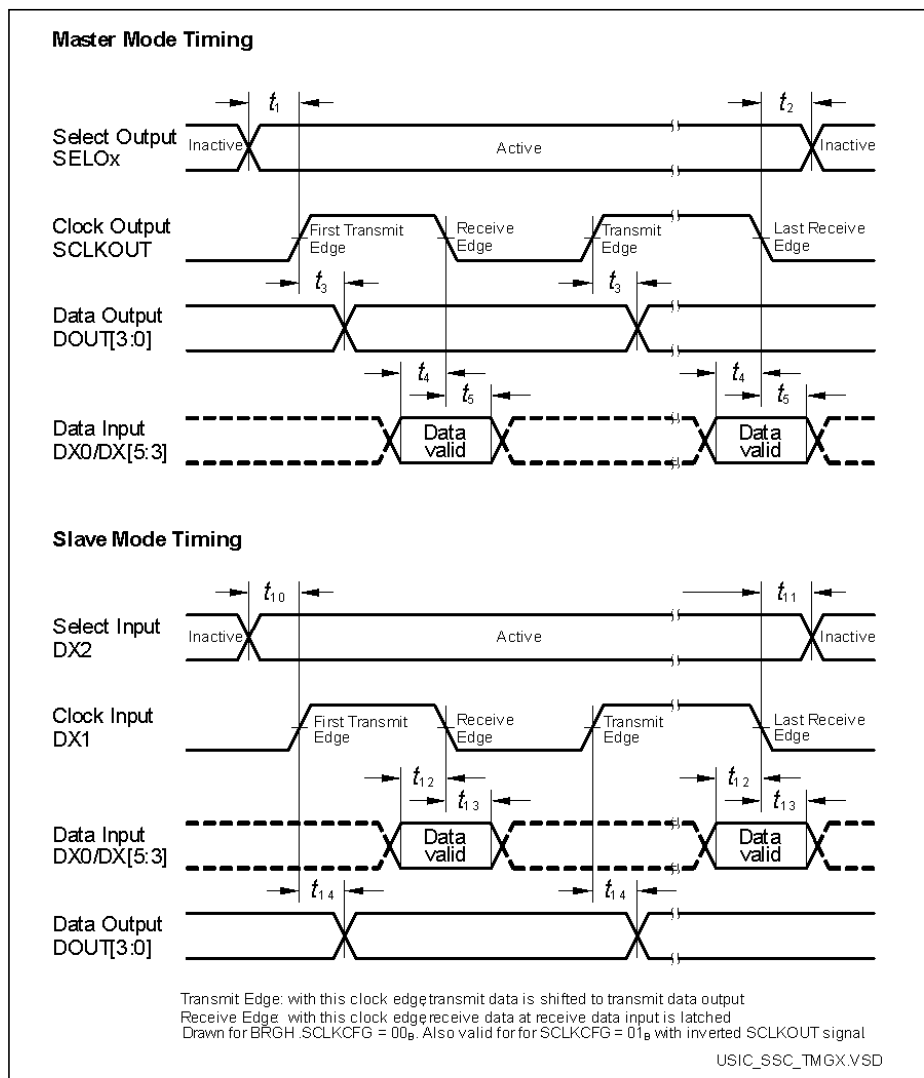
| Parameter                                                         | Symbol       | Values              |      |      | Unit | Note / Test Condition |
|-------------------------------------------------------------------|--------------|---------------------|------|------|------|-----------------------|
|                                                                   |              | Min.                | Typ. | Max. |      |                       |
| SCLKOUT master clock period                                       | $t_{CLK}$ CC | 33.3                | –    | –    | ns   |                       |
| Slave select output SELO active to first SCLKOUT transmit edge    | $t_1$ CC     | $t_{PB} - 6.5^{1)}$ | –    | –    | ns   |                       |
| Slave select output SELO inactive after last SCLKOUT receive edge | $t_2$ CC     | $t_{PB} - 8.5^{1)}$ | –    | –    | ns   |                       |
| Data output DOUT[3:0] valid time                                  | $t_3$ CC     | -6                  | –    | 8    | ns   |                       |
| Receive data input DX0/DX[5:3] setup time to SCLKOUT receive edge | $t_4$ SR     | 23                  | –    | –    | ns   |                       |
| Data input DX0/DX[5:3] hold time from SCLKOUT receive edge        | $t_5$ SR     | 1                   | –    | –    | ns   |                       |

1)  $t_{PB} = 1 / f_{PB}$

**Table 44 USIC SSC Slave Mode Timing**

| Parameter                                                                           | Symbol       | Values |      |      | Unit | Note / Test Condition |
|-------------------------------------------------------------------------------------|--------------|--------|------|------|------|-----------------------|
|                                                                                     |              | Min.   | Typ. | Max. |      |                       |
| DX1 slave clock period                                                              | $t_{CLK}$ SR | 66.6   | –    | –    | ns   |                       |
| Select input DX2 setup to first clock input DX1 transmit edge <sup>1)</sup>         | $t_{10}$ SR  | 3      | –    | –    | ns   |                       |
| Select input DX2 hold after last clock input DX1 receive edge <sup>1)</sup>         | $t_{11}$ SR  | 4      | –    | –    | ns   |                       |
| Receive data input DX0/DX[5:3] setup time to shift clock receive edge <sup>1)</sup> | $t_{12}$ SR  | 6      | –    | –    | ns   |                       |
| Data input DX0/DX[5:3] hold time from clock input DX1 receive edge <sup>1)</sup>    | $t_{13}$ SR  | 4      | –    | –    | ns   |                       |
| Data output DOUT[3:0] valid time                                                    | $t_{14}$ CC  | 0      | –    | 24   | ns   |                       |

1) This input timing is valid for asynchronous input signal handling of slave select input, shift clock input, and receive data input (bits DXnCR.DSEN = 0).



**Figure 26 USIC - SSC Master/Slave Mode Timing**

*Note: This timing diagram shows a standard configuration, for which the slave select signal is low-active, and the serial clock signal is not shifted and not inverted.*

### 3.3.8.2 Inter-IC (IIC) Interface Timing

The following parameters are applicable for a USIC channel operated in IIC mode.

*Note: These parameters are not subject to production test, but verified by design and/or characterization.*

**Table 45 USIC IIC Standard Mode Timing<sup>1)</sup>**

| Parameter                                        | Symbol            | Values |      |      | Unit | Note / Test Condition |
|--------------------------------------------------|-------------------|--------|------|------|------|-----------------------|
|                                                  |                   | Min.   | Typ. | Max. |      |                       |
| Fall time of both SDA and SCL                    | $t_1$<br>CC/SR    | -      | -    | 300  | ns   |                       |
| Rise time of both SDA and SCL                    | $t_2$<br>CC/SR    | -      | -    | 1000 | ns   |                       |
| Data hold time                                   | $t_3$<br>CC/SR    | 0      | -    | -    | μs   |                       |
| Data set-up time                                 | $t_4$<br>CC/SR    | 250    | -    | -    | ns   |                       |
| LOW period of SCL clock                          | $t_5$<br>CC/SR    | 4.7    | -    | -    | μs   |                       |
| HIGH period of SCL clock                         | $t_6$<br>CC/SR    | 4.0    | -    | -    | μs   |                       |
| Hold time for (repeated) START condition         | $t_7$<br>CC/SR    | 4.0    | -    | -    | μs   |                       |
| Set-up time for repeated START condition         | $t_8$<br>CC/SR    | 4.7    | -    | -    | μs   |                       |
| Set-up time for STOP condition                   | $t_9$<br>CC/SR    | 4.0    | -    | -    | μs   |                       |
| Bus free time between a STOP and START condition | $t_{10}$<br>CC/SR | 4.7    | -    | -    | μs   |                       |
| Capacitive load for each bus line                | $C_b$ SR          | -      | -    | 400  | pF   |                       |

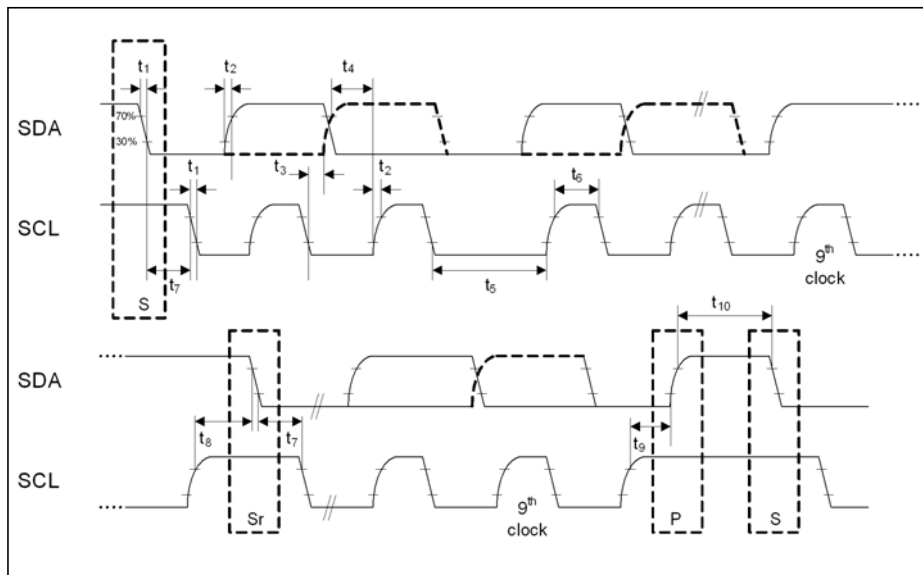
1) Due to the wired-AND configuration of an IIC bus system, the port drivers of the SCL and SDA signal lines need to operate in open-drain mode. The high level on these lines must be held by an external pull-up device, approximately 10 kOhm for operation at 100 kbit/s, approximately 2 kOhm for operation at 400 kbit/s.

**Table 46 USIC IIC Fast Mode Timing<sup>1)</sup>**

| Parameter                                        | Symbol            | Values                                   |      |      | Unit | Note / Test Condition |
|--------------------------------------------------|-------------------|------------------------------------------|------|------|------|-----------------------|
|                                                  |                   | Min.                                     | Typ. | Max. |      |                       |
| Fall time of both SDA and SCL                    | $t_1$<br>CC/SR    | 20 +<br>$0.1 \cdot C_b$<br><sup>2)</sup> | -    | 300  | ns   |                       |
| Rise time of both SDA and SCL                    | $t_2$<br>CC/SR    | 20 +<br>$0.1 \cdot C_b$<br><sup>2)</sup> | -    | 300  | ns   |                       |
| Data hold time                                   | $t_3$<br>CC/SR    | 0                                        | -    | -    | μs   |                       |
| Data set-up time                                 | $t_4$<br>CC/SR    | 100                                      | -    | -    | ns   |                       |
| LOW period of SCL clock                          | $t_5$<br>CC/SR    | 1.3                                      | -    | -    | μs   |                       |
| HIGH period of SCL clock                         | $t_6$<br>CC/SR    | 0.6                                      | -    | -    | μs   |                       |
| Hold time for (repeated) START condition         | $t_7$<br>CC/SR    | 0.6                                      | -    | -    | μs   |                       |
| Set-up time for repeated START condition         | $t_8$<br>CC/SR    | 0.6                                      | -    | -    | μs   |                       |
| Set-up time for STOP condition                   | $t_9$<br>CC/SR    | 0.6                                      | -    | -    | μs   |                       |
| Bus free time between a STOP and START condition | $t_{10}$<br>CC/SR | 1.3                                      | -    | -    | μs   |                       |
| Capacitive load for each bus line                | $C_b$ SR          | -                                        | -    | 400  | pF   |                       |

1) Due to the wired-AND configuration of an IIC bus system, the port drivers of the SCL and SDA signal lines need to operate in open-drain mode. The high level on these lines must be held by an external pull-up device, approximately 10 kOhm for operation at 100 kbit/s, approximately 2 kOhm for operation at 400 kbit/s.

2)  $C_b$  refers to the total capacitance of one bus line in pF.



**Figure 27 USIC IIC Stand and Fast Mode Timing**

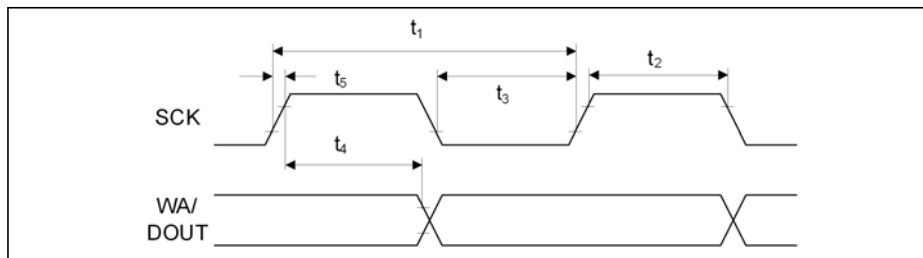
### 3.3.8.3 Inter-IC Sound (IIS) Interface Timing

The following parameters are applicable for a USIC channel operated in IIS mode.

*Note: These parameters are not subject to production test, but verified by design and/or characterization.*

**Table 47 USIC IIS Master Transmitter Timing**

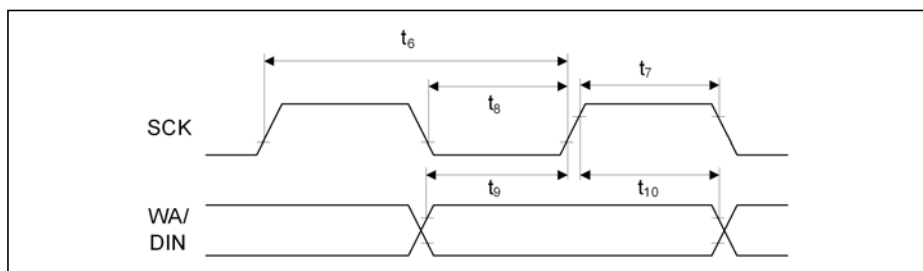
| Parameter       | Symbol   | Values                 |      |                        | Unit | Note / Test Condition |
|-----------------|----------|------------------------|------|------------------------|------|-----------------------|
|                 |          | Min.                   | Typ. | Max.                   |      |                       |
| Clock period    | $t_1$ CC | 33.3                   | —    | —                      | ns   |                       |
| Clock high time | $t_2$ CC | $0.35 \times t_{1min}$ | —    | —                      | ns   |                       |
| Clock low time  | $t_3$ CC | $0.35 \times t_{1min}$ | —    | —                      | ns   |                       |
| Hold time       | $t_4$ CC | 0                      | —    | —                      | ns   |                       |
| Clock rise time | $t_5$ CC | —                      | —    | $0.15 \times t_{1min}$ | ns   |                       |



**Figure 28 USIC IIS Master Transmitter Timing**

**Table 48 USIC IIS Slave Receiver Timing**

| Parameter       | Symbol      | Values                 |      |      | Unit | Note / Test Condition |
|-----------------|-------------|------------------------|------|------|------|-----------------------|
|                 |             | Min.                   | Typ. | Max. |      |                       |
| Clock period    | $t_6$ SR    | 66.6                   | —    | —    | ns   |                       |
| Clock high time | $t_7$ SR    | $0.35 \times t_{6min}$ | —    | —    | ns   |                       |
| Clock low time  | $t_8$ SR    | $0.35 \times t_{6min}$ | —    | —    | ns   |                       |
| Set-up time     | $t_9$ SR    | $0.2 \times t_{6min}$  | —    | —    | ns   |                       |
| Hold time       | $t_{10}$ SR | 0                      | —    | —    | ns   |                       |



**Figure 29 USIC IIS Slave Receiver Timing**

### 3.3.8.4 SDMMC Interface Timing

*Note: These parameters are not subject to production test, but verified by design and/or characterization.*

*Note: Operating Conditions apply, total external capacitive load  $C_L = 40$  pF.*

#### AC Timing Specifications (Full-Speed Mode)

**Table 49 SDMMC Timing for Full-Speed Mode**

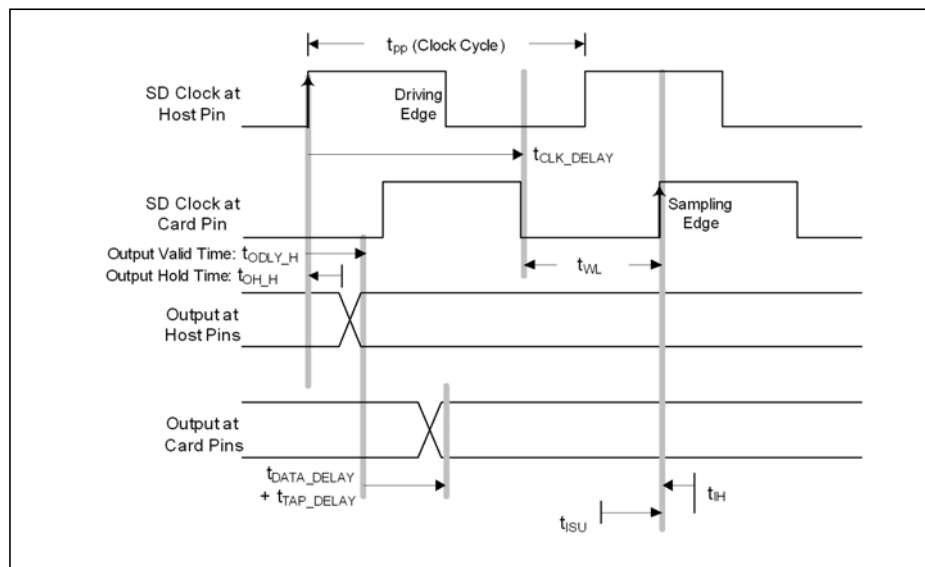
| Parameter                                                  | Symbol        |    | Values |      | Unit | Note/ Test Condition |
|------------------------------------------------------------|---------------|----|--------|------|------|----------------------|
|                                                            |               |    | Min.   | Max. |      |                      |
| Clock frequency in full speed transfer mode ( $1/t_{pp}$ ) | $f_{pp}$      | CC | 0      | 24   | MHz  |                      |
| Clock cycle in full speed transfer mode                    | $t_{pp}$      | CC | 40     | –    | ns   |                      |
| Clock low time                                             | $t_{WL}$      | CC | 10     | –    | ns   |                      |
| Clock high time                                            | $t_{WH}$      | CC | 10     | –    | ns   |                      |
| Clock rise time                                            | $t_{TLH}$     | CC | –      | 10   | ns   |                      |
| Clock fall time                                            | $t_{THL}$     | CC | –      | 10   | ns   |                      |
| Inputs setup to clock rising edge                          | $t_{ISU\_F}$  | SR | 2      | –    | ns   |                      |
| Inputs hold after clock rising edge                        | $t_{IH\_F}$   | SR | 2      | –    | ns   |                      |
| Outputs valid time in full speed mode                      | $t_{ODLY\_F}$ | CC | –      | 10   | ns   |                      |
| Outputs hold time in full speed mode                       | $t_{OH\_F}$   | CC | 0      | –    | ns   |                      |

**Table 50 SD Card Bus Timing for Full-Speed Mode<sup>1)</sup>**

| Parameter                 | Symbol     | Values |      | Unit | Note/ Test Condition |
|---------------------------|------------|--------|------|------|----------------------|
|                           |            | Min.   | Max. |      |                      |
| SD card input setup time  | $t_{ISU}$  | 5      | —    | ns   |                      |
| SD card input hold time   | $t_{IH}$   | 5      | —    | ns   |                      |
| SD card output valid time | $t_{ODLY}$ | —      | 14   | ns   |                      |
| SD card output hold time  | $t_{OH}$   | 0      | —    | ns   |                      |

1) Reference card timing values for calculation examples. Not subject to production test and not characterized.

### Full-Speed Output Path (Write)



**Figure 30 Full-Speed Output Path**

### Full-Speed Write Meeting Setup (Maximum Delay)

The following equations show how to calculate the allowed skew range between the SD\_CLK and SD\_DAT/CMD signals on the PCB.

No clock delay:

$$t_{ODLY\_F} + t_{DATA\_DELAY} + t_{TAP\_DELAY} + t_{ISU} < t_{WL} \quad (1)$$

With clock delay:

$$t_{ODLY\_F} + t_{DATA\_DELAY} + t_{TAP\_DELAY} + t_{ISU} < t_{WL} + t_{CLK\_DELAY} \quad (2)$$

$$t_{DATA\_DELAY} + t_{TAP\_DELAY} + t_{WL} < t_{PP} + t_{CLK\_DELAY} - t_{ISU} - t_{ODLY\_F} \quad (3)$$

$$t_{DATA\_DELAY} + t_{TAP\_DELAY} + 20 < 40 + t_{CLK\_DELAY} - 5 - 10$$

$$t_{DATA\_DELAY} < 5 + t_{CLK\_DELAY} - t_{TAP\_DELAY}$$

The data can be delayed versus clock up to 5 ns in ideal case of  $t_{WL} = 20$  ns.

### Full-Speed Write Meeting Hold (Minimum Delay)

The following equations show how to calculate the allowed skew range between the SD\_CLK and SD\_DAT/CMD signals on the PCB.

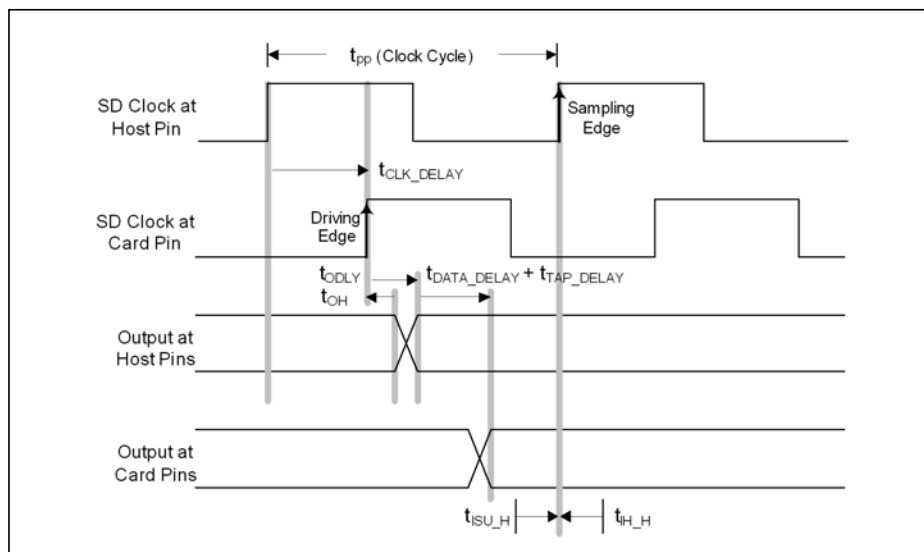
$$t_{CLK\_DELAY} < t_{WL} + t_{OH\_F} + t_{DATA\_DELAY} + t_{TAP\_DELAY} - t_{IH} \quad (4)$$

$$t_{CLK\_DELAY} < 20 + t_{DATA\_DELAY} + t_{TAP\_DELAY} - 5$$

$$t_{DATA\_DELAY} < 15 + t_{CLK\_DELAY} + t_{TAP\_DELAY}$$

The clock can be delayed versus data up to 18.2 ns (external delay line) in ideal case of  $t_{WL} = 20$  ns, with maximum  $t_{TAP\_DELAY} = 3.2$  ns programmed.

### Full-Speed Input Path (Read)



**Figure 31 Full-Speed Input Path**

### Full-Speed Read Meeting Setup (Maximum Delay)

The following equations show how to calculate the allowed combined propagation delay range of the SD\_CLK and SD\_DAT/CMD signals on the PCB.

(5)

$$t_{CLK\_DELAY} + t_{DATA\_DELAY} + t_{TAP\_DELAY} + t_{ODLY} + t_{ISU\_F} < 0.5 \times t_{pp}$$

$$t_{CLK\_DELAY} + t_{DATA\_DELAY} < 0.5 \times t_{pp} - t_{ODLY} - t_{ISU\_F} - t_{TAP\_DELAY}$$

$$t_{CLK\_DELAY} + t_{DATA\_DELAY} < 20 - 14 - 2 - t_{TAP\_DELAY}$$

$$t_{CLK\_DELAY} + t_{DATA\_DELAY} < 4 - t_{TAP\_DELAY}$$

The data + clock delay can be up to 4 ns for a 40 ns clock cycle.

**Electrical Parameters**
**Full-Speed Read Meeting Hold (Minimum Delay)**

The following equations show how to calculate the allowed combined propagation delay range of the SD\_CLK and SD\_DAT/CMD signals on the PCB.

(6)

$$t_{\text{CLK\_DELAY}} + t_{\text{OH}} + t_{\text{DATA\_DELAY}} + t_{\text{TAP\_DELAY}} > t_{\text{IH\_F}}$$

$$t_{\text{CLK\_DELAY}} + t_{\text{DATA\_DELAY}} > t_{\text{IH\_F}} - t_{\text{OH}} - t_{\text{TAP\_DELAY}}$$

$$t_{\text{CLK\_DELAY}} + t_{\text{DATA\_DELAY}} > 2 - t_{\text{TAP\_DELAY}}$$

The data + clock delay must be greater than 2 ns if  $t_{\text{TAP\_DELAY}}$  is not used.

If the  $t_{\text{TAP\_DELAY}}$  is programmed to at least 2 ns, the data + clock delay must be greater than 0 ns (or less). This is always fulfilled.

**AC Timing Specifications (High-Speed Mode)**
**Table 51 SDMMC Timing for High-Speed Mode**

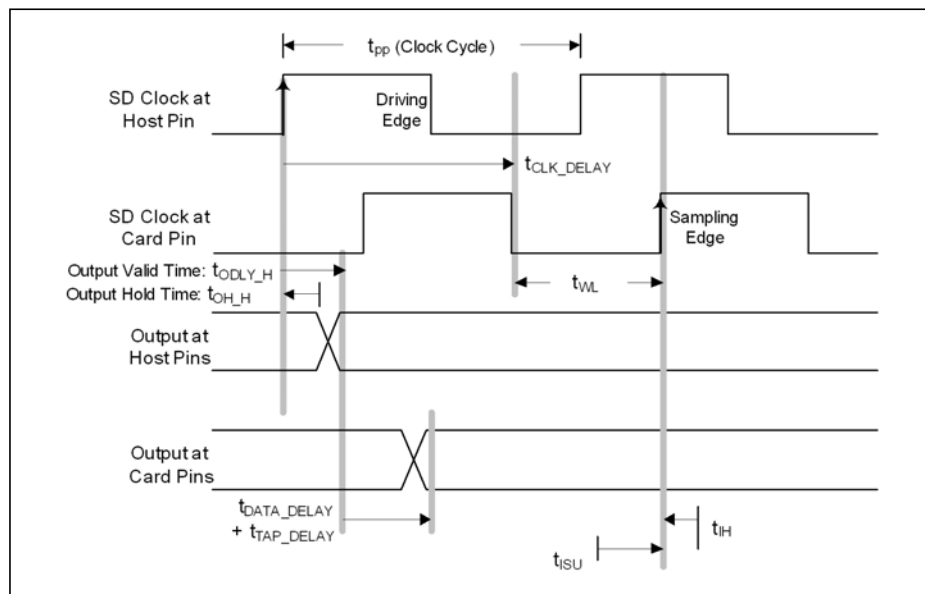
| Parameter                                                         | Symbol               |    | Values |      | Unit | Note/ Test Condition |
|-------------------------------------------------------------------|----------------------|----|--------|------|------|----------------------|
|                                                                   |                      |    | Min.   | Max. |      |                      |
| Clock frequency in high speed transfer mode ( $1/t_{\text{pp}}$ ) | $f_{\text{pp}}$      | CC | 0      | 48   | MHz  |                      |
| Clock cycle in high speed transfer mode                           | $t_{\text{pp}}$      | CC | 20     | —    | ns   |                      |
| Clock low time                                                    | $t_{\text{WL}}$      | CC | 7      | —    | ns   |                      |
| Clock high time                                                   | $t_{\text{WH}}$      | CC | 7      | —    | ns   |                      |
| Clock rise time                                                   | $t_{\text{TLH}}$     | CC | —      | 3    | ns   |                      |
| Clock fall time                                                   | $t_{\text{THL}}$     | CC | —      | 3    | ns   |                      |
| Inputs setup to clock rising edge                                 | $t_{\text{ISU\_H}}$  | SR | 2      | —    | ns   |                      |
| Inputs hold after clock rising edge                               | $t_{\text{IH\_H}}$   | SR | 2      | —    | ns   |                      |
| Outputs valid time in high speed mode                             | $t_{\text{ODLY\_H}}$ | CC | —      | 14   | ns   |                      |
| Outputs hold time in high speed mode                              | $t_{\text{OH\_H}}$   | CC | 2      | —    | ns   |                      |

**Table 52 SD Card Bus Timing for High-Speed Mode<sup>1)</sup>**

| Parameter                 | Symbol     | Values |      | Unit | Note/ Test Condition |
|---------------------------|------------|--------|------|------|----------------------|
|                           |            | Min.   | Max. |      |                      |
| SD card input setup time  | $t_{ISU}$  | 6      | —    | ns   |                      |
| SD card input hold time   | $t_{IH}$   | 2      | —    | ns   |                      |
| SD card output valid time | $t_{ODLY}$ | —      | 14   | ns   |                      |
| SD card output hold time  | $t_{OH}$   | 2.5    | —    | ns   |                      |

1) Reference card timing values for calculation examples. Not subject to production test and not characterized.

### High-Speed Output Path (Write)



**Figure 32 High-Speed Output Path**

### High-Speed Write Meeting Setup (Maximum Delay)

The following equations show how to calculate the allowed skew range between the SD\_CLK and SD\_DAT/CMD signals on the PCB.

No clock delay:

$$t_{ODLY\_H} + t_{DATA\_DELAY} + t_{TAP\_DELAY} + t_{ISU} < t_{WL} \quad (7)$$

With clock delay:

$$t_{ODLY\_H} + t_{DATA\_DELAY} + t_{TAP\_DELAY} + t_{ISU} < t_{WL} + t_{CLK\_DELAY} \quad (8)$$

$$t_{DATA\_DELAY} + t_{TAP\_DELAY} - t_{CLK\_DELAY} < t_{WL} - t_{ISU} - t_{ODLY\_H} \quad (9)$$

$$t_{DATA\_DELAY} - t_{CLK\_DELAY} < t_{WL} - t_{ISU} - t_{ODLY\_H} - t_{TAP\_DELAY}$$

$$t_{DATA\_DELAY} - t_{CLK\_DELAY} < 10 - 6 - 14 - t_{TAP\_DELAY}$$

$$t_{DATA\_DELAY} - t_{CLK\_DELAY} < -10 - t_{TAP\_DELAY}$$

The data delay is less than the clock delay by at least 10 ns in the ideal case where  $t_{WL} = 10$  ns.

### High-Speed Write Meeting Hold (Minimum Delay)

The following equations show how to calculate the allowed skew range between the SD\_CLK and SD\_DAT/CMD signals on the PCB.

$$t_{CLK\_DELAY} < t_{WL} + t_{OH\_H} + t_{DATA\_DELAY} + t_{TAP\_DELAY} - t_{IH} \quad (10)$$

$$t_{CLK\_DELAY} - t_{DATA\_DELAY} < t_{WL} + t_{OH\_H} + t_{TAP\_DELAY} - t_{IH}$$

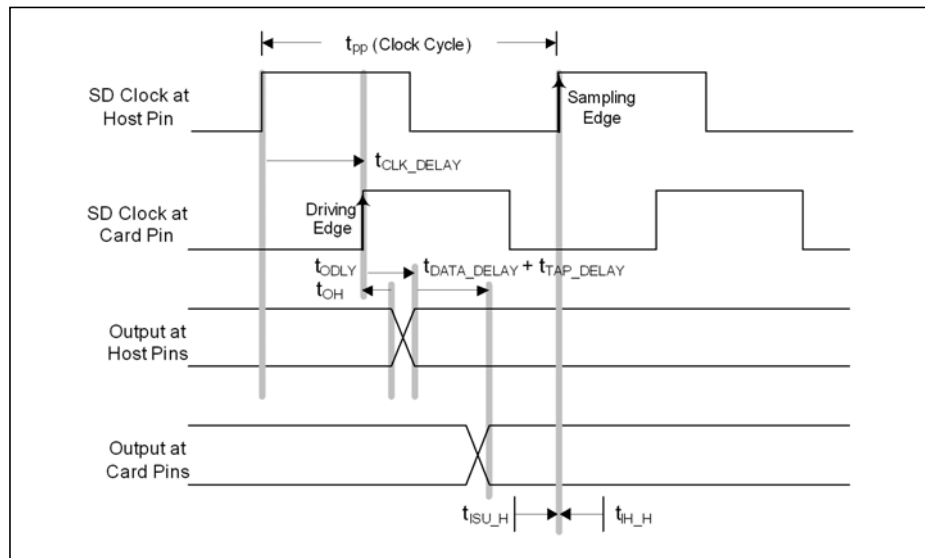
$$t_{CLK\_DELAY} - t_{DATA\_DELAY} < 10 + 2 + t_{TAP\_DELAY} - 2$$

$$t_{CLK\_DELAY} - t_{DATA\_DELAY} < 10 + t_{TAP\_DELAY}$$

## Electrical Parameters

The clock can be delayed versus data up to 13.2 ns (external delay line) in ideal case of  $t_{WL} = 10$  ns, with maximum  $t_{TAP\_DELAY} = 3.2$  ns programmed.

### High-Speed Input Path (Read)



**Figure 33 High-Speed Input Path**

### High-Speed Read Meeting Setup (Maximum Delay)

The following equations show how to calculate the allowed combined propagation delay range of the SD\_CLK and SD\_DAT/CMD signals on the PCB.

(11)

$$t_{CLK\_DELAY} + t_{DATA\_DELAY} + t_{TAP\_DELAY} + t_{ODLY} + t_{ISU\_H} < t_{pp}$$

$$t_{CLK\_DELAY} + t_{DATA\_DELAY} < t_{pp} - t_{ODLY} - t_{ISU\_H} - t_{TAP\_DELAY}$$

$$t_{CLK\_DELAY} + t_{DATA\_DELAY} < 20 - 14 - 2 - t_{TAP\_DELAY}$$

$$t_{CLK\_DELAY} + t_{DATA\_DELAY} < 4 - t_{TAP\_DELAY}$$

The data + clock delay can be up to 4 ns for a 20 ns clock cycle.

## Electrical Parameters

### High-Speed Read Meeting Hold (Minimum Delay)

The following equations show how to calculate the allowed combined propagation delay range of the SD\_CLK and SD\_DAT/CMD signals on the PCB.

(12)

$$t_{CLK\_DELAY} + t_{OH} + t_{DATA\_DELAY} + t_{TAP\_DELAY} > t_{IH\_H}$$

$$t_{CLK\_DELAY} + t_{DATA\_DELAY} > t_{IH\_H} - t_{OH} - t_{TAP\_DELAY}$$

$$t_{CLK\_DELAY} + t_{DATA\_DELAY} > 2 - 2.5 - t_{TAP\_DELAY}$$

$$t_{CLK\_DELAY} + t_{DATA\_DELAY} > -0.5 - t_{TAP\_DELAY}$$

The data + clock delay must be greater than -0.5 ns for a 20 ns clock cycle. This is always fulfilled.

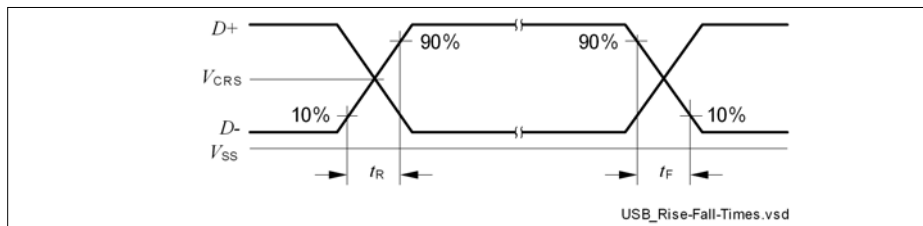
### 3.3.9 USB Interface Characteristics

The Universal Serial Bus (USB) Interface is compliant to the USB Rev. 2.0 Specification and the OTG Specification Rev. 1.3. High-Speed Mode is not supported.

*Note: These parameters are not subject to production test, but verified by design and/or characterization.*

**Table 53**      **USB Timing Parameters** (operating conditions apply)

| Parameter               | Symbol       | Values |      |        | Unit | Note / Test Condition |
|-------------------------|--------------|--------|------|--------|------|-----------------------|
|                         |              | Min.   | Typ. | Max.   |      |                       |
| Rise time               | $t_R$ CC     | 4      | —    | 20     | ns   | $C_L = 50$ pF         |
| Fall time               | $t_F$ CC     | 4      | —    | 20     | ns   | $C_L = 50$ pF         |
| Rise/Fall time matching | $t_R/t_F$ CC | 90     | —    | 111.11 | %    | $C_L = 50$ pF         |
| Crossover voltage       | $V_{CRS}$ CC | 1.3    | —    | 2.0    | V    | $C_L = 50$ pF         |



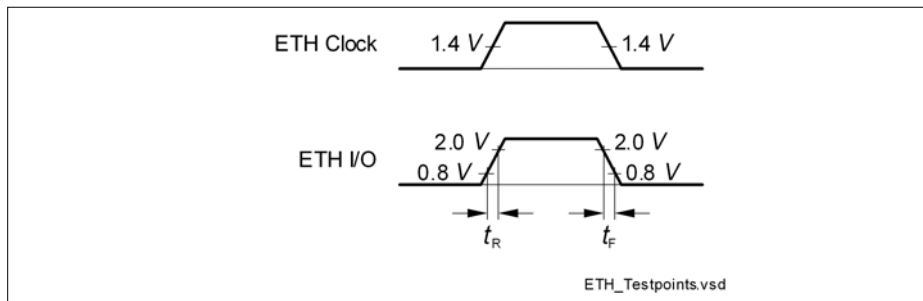
**Figure 34 USB Signal Timing**

### 3.3.10 Ethernet Interface (ETH) Characteristics

For proper operation of the Ethernet Interface it is required that  $f_{SYS} \geq 100$  MHz.

*Note: These parameters are not subject to production test, but verified by design and/or characterization.*

#### 3.3.10.1 ETH Measurement Reference Points

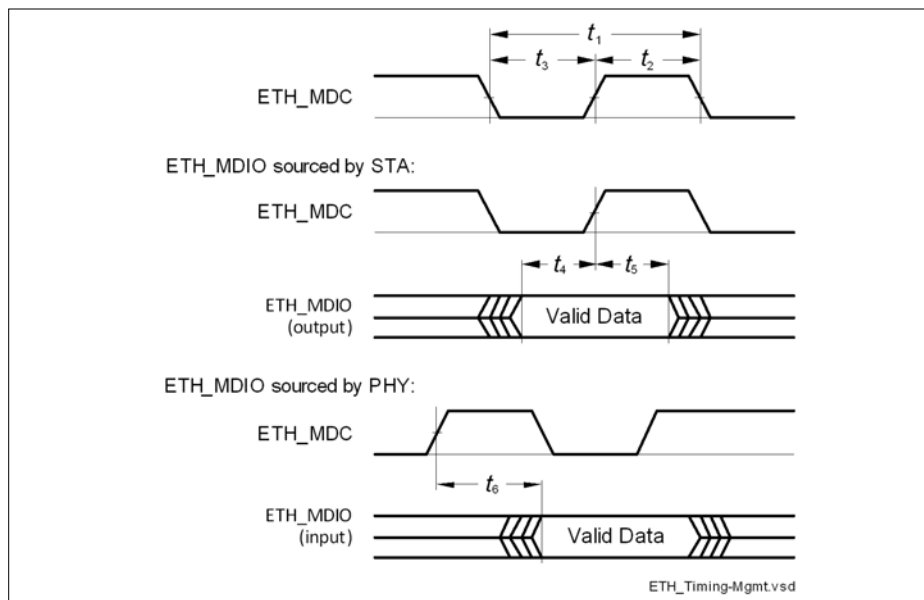


**Figure 35 ETH Measurement Reference Points**

### 3.3.10.2 ETH Management Signal Parameters (ETH\_MDC, ETH\_MDIO)

**Table 54 ETH Management Signal Timing Parameters**

| Parameter                    | Symbol |    | Values |      |      | Unit | Note / Test Condition |
|------------------------------|--------|----|--------|------|------|------|-----------------------|
|                              |        |    | Min.   | Typ. | Max. |      |                       |
| ETH_MDC period               | $t_1$  | CC | 400    | —    | —    | ns   | $C_L = 25 \text{ pF}$ |
| ETH_MDC high time            | $t_2$  | CC | 160    | —    | —    | ns   |                       |
| ETH_MDC low time             | $t_3$  | CC | 160    | —    | —    | ns   |                       |
| ETH_MDIO setup time (output) | $t_4$  | CC | 10     | —    | —    | ns   |                       |
| ETH_MDIO hold time (output)  | $t_5$  | CC | 10     | —    | —    | ns   |                       |
| ETH_MDIO data valid (input)  | $t_6$  | SR | 0      | —    | 300  | ns   |                       |



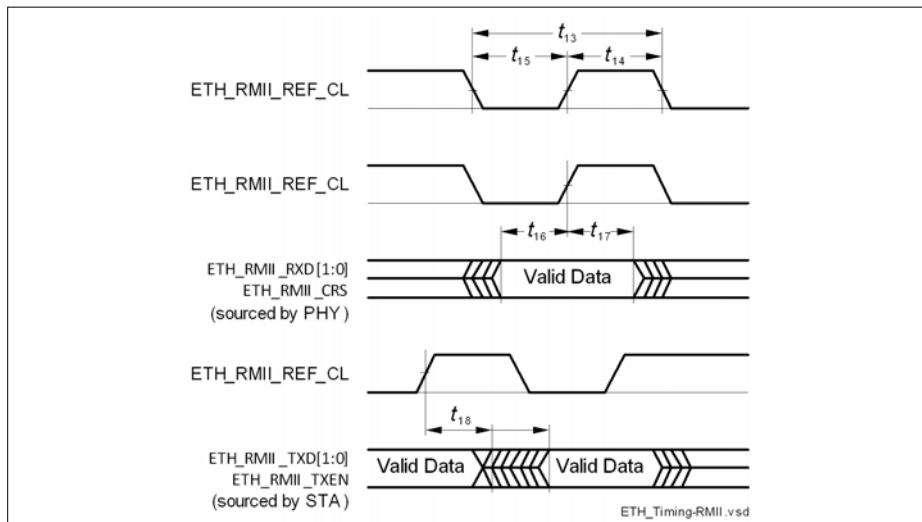
**Figure 36 ETH Management Signal Timing**

### 3.3.10.3 ETH RMII Parameters

In the following, the parameters of the RMII (Reduced Media Independent Interface) are described.

**Table 55 ETH RMII Signal Timing Parameters**

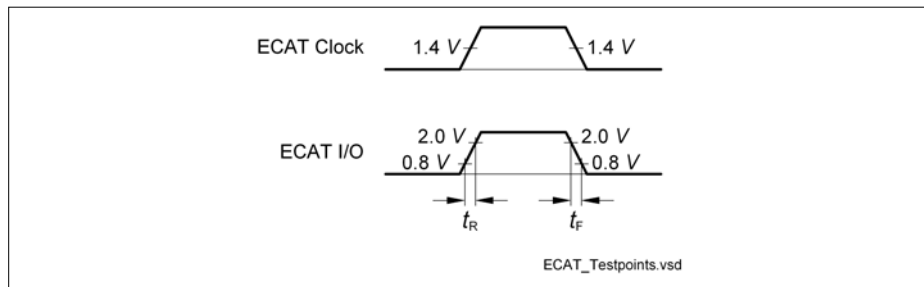
| Parameter                                   | Symbol   |    | Values |      |      | Unit | Note / Test Condition          |
|---------------------------------------------|----------|----|--------|------|------|------|--------------------------------|
|                                             |          |    | Min.   | Typ. | Max. |      |                                |
| ETH_RMII_REF_CL clock period                | $t_{13}$ | SR | 20     | –    | –    | ns   | $C_L = 25 \text{ pF}$ ; 50 ppm |
| ETH_RMII_REF_CL clock high time             | $t_{14}$ | SR | 7      | –    | 13   | ns   | $C_L = 25 \text{ pF}$          |
| ETH_RMII_REF_CL clock low time              | $t_{15}$ | SR | 7      | –    | 13   | ns   |                                |
| ETH_RMII_RXD[1:0], ETH_RMII_CRS setup time  | $t_{16}$ | SR | 4      | –    | –    | ns   |                                |
| ETH_RMII_RXD[1:0], ETH_RMII_CRS hold time   | $t_{17}$ | SR | 2      | –    | –    | ns   |                                |
| ETH_RMII_TXD[1:0], ETH_RMII_TXEN data valid | $t_{18}$ | CC | 4      | –    | 15   | ns   |                                |



**Figure 37 ETH RMII Signal Timing**

### 3.3.11 EtherCAT (ECAT) Characteristics

#### 3.3.11.1 ECAT Measurement Reference Points

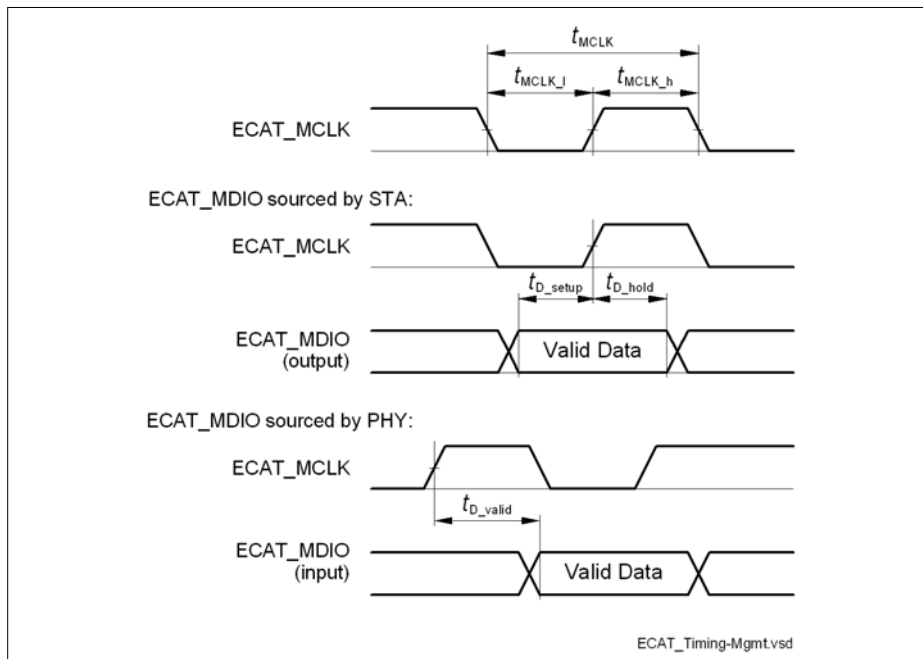


**Figure 38** Measurement Reference Points

#### 3.3.11.2 ETH Management Signal Parameters (MCLK, MDIO)

**Table 56** ECAT Management Signal Timing Parameters

| Parameter                     | Symbol                    | Values |      |      | Unit | Note / Test Condition                                 |
|-------------------------------|---------------------------|--------|------|------|------|-------------------------------------------------------|
|                               |                           | Min.   | Typ. | Max. |      |                                                       |
| ECAT_MCLK period              | $t_{\text{MCLK}}$<br>CC   | —      | 400  | —    | ns   | IEEE802.3 requirement (2.5 MHz) $C_L = 25 \text{ pF}$ |
| ECAT_MCLK high time           | $t_{\text{MCLK}_h}$<br>CC | 160    | —    | —    | ns   |                                                       |
| ECAT_MCLK low time            | $t_{\text{MCLK}_l}$<br>CC | 160    | —    | —    | ns   |                                                       |
| ECAT_MDIO setup time (output) | $t_{D\_setup}$<br>CC      | 10     | —    | —    | ns   |                                                       |
| ECAT_MDIO hold time (output)  | $t_{D\_hold}$<br>CC       | 10     | —    | —    | ns   |                                                       |
| ECAT_MDIO data valid (input)  | $t_{D\_valid}$<br>SR      | 0      | —    | 300  | ns   |                                                       |



**Figure 39 ECAT Management Signal Timing**

### 3.3.11.3 MII Timing TX Characteristics

**Table 57 ETH MII TX Signal Timing Parameters**

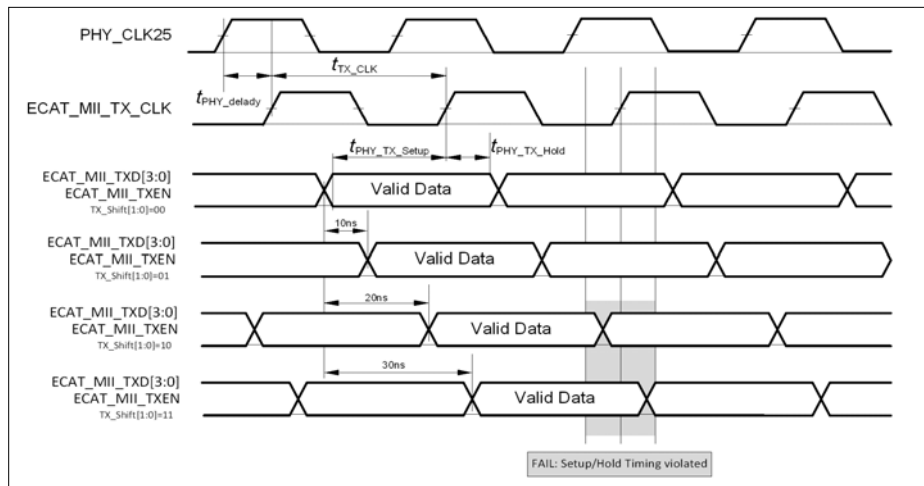
| Parameter                                                             | Symbol                 | Values |      |      | Unit | Note / Test Condition |
|-----------------------------------------------------------------------|------------------------|--------|------|------|------|-----------------------|
|                                                                       |                        | Min.   | Typ. | Max. |      |                       |
| PHY_CLK25, TX_CLK period                                              | $t_{TX\_CLK}$<br>SR    | —      | 40   | —    | ns   |                       |
| Delay between PHY clock source PHY_CLK25 and TX_CLK output of the PHY | $t_{PHY\_delay}$<br>SR | —      | —    | —    | ns   | PHY dependent         |

**Electrical Parameters**

**Table 57 ETH MII TX Signal Timing Parameters (cont'd)**

| Parameter                                                         | Symbol                | Values |      |      | Unit | Note / Test Condition                        |
|-------------------------------------------------------------------|-----------------------|--------|------|------|------|----------------------------------------------|
|                                                                   |                       | Min.   | Typ. | Max. |      |                                              |
| PHY setup requirement:<br>TXEN/TXD[3:0] with respect<br>to TX_CLK | $t_{TX\_setup}$<br>SR | 15     | —    | 0    | ns   | PHY dependent<br>IEEE802.3 limit<br>is 15 ns |
| PHY hold requirement:<br>TXEN/TXD[3:0] with respect<br>to TX_CLK  | $t_{TX\_hold}$<br>CC  | 0      | —    | 25   | ns   | PHY dependent<br>IEEE802.3 limit<br>is 0 ns  |

*Note: ECAT0\_CONPx.TX\_SHIFT can be adjusted by displaying TX\_CLK of a PHY and TXEN/TXD[3:0] on an oscilloscope. TXEN/TXD[3:0] is allowed to change between 0 ns and 25 ns after a rising edge of TX\_CLK (according to IEEE802.3 – check your PHY's documentation). Configure TX\_SHIFT so that TXEN/TXD[3:0] change near the middle of this range. It is sufficient to check just one of the TXEN/TXD[3:0] signals, because they are nearly generated at the same time.*

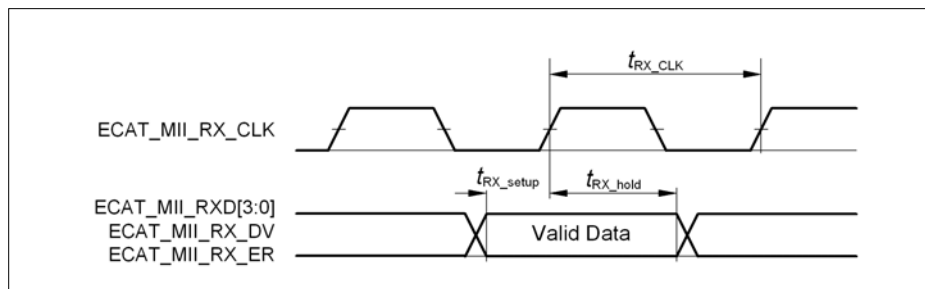


**Figure 40 MII TX Characteristics**

### 3.3.11.4 MII Timing RX Characteristics

**Table 58 ETH MII RX Signal Timing Parameters**

| Parameter                                                     | Symbol                | Values |      |      | Unit | Note / Test Condition                              |
|---------------------------------------------------------------|-----------------------|--------|------|------|------|----------------------------------------------------|
|                                                               |                       | Min.   | Typ. | Max. |      |                                                    |
| RX_CLK period                                                 | $t_{RX\_CLK}$<br>SR   | —      | 40   | —    | ns   | $C_L = 25\text{ pF}$ ,<br>IEEE802.3<br>requirement |
| RX_DV/RX_DV/RXD[3:0]<br>valid before rising<br>edge of RX_CLK | $t_{RX\_setup}$<br>SR | 10     | —    | —    | ns   |                                                    |
| RX_DV/RX_DV/RXD[3:0]<br>valid after rising<br>edge of RX_CLK  | $t_{RX\_hold}$<br>SR  | 10     | —    | —    | ns   |                                                    |



**Figure 41 MII RX characteristics**

### 3.3.11.5 Sync/Latch Timings

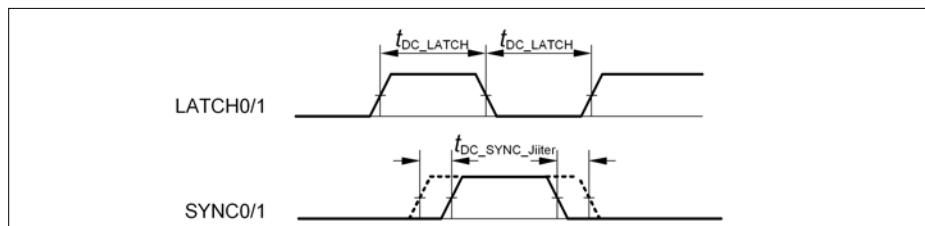
**Table 59 Sync/Latch Timings**

| Parameter | Symbol                       | Values               |      |                      | Unit | Note / Test Condition |
|-----------|------------------------------|----------------------|------|----------------------|------|-----------------------|
|           |                              | Min.                 | Typ. | Max.                 |      |                       |
| SYNC0/1   | $t_{DC\_SYNC\_SR}$<br>Jitter | —                    | —    | 11 + m <sup>1)</sup> | ns   |                       |
| LATCH0/1  | $t_{DC\_LATCH\_SR}$          | 12 + n <sup>2)</sup> | —    | —                    | ns   |                       |

1) additional delay form logic and pad, number is added after characterization

2) additional shaping delay, number is added after characterization

*Note: SYNC0/1 pulse length are initially loaded by EEPROM content ADR 0x0002. The actual used value can be read back from Register DC\_PULSE\_LEN.*



**Figure 42 Sync/Latch Timings**

## 4 Package and Reliability

The XMC4300 is a member of the XMC4000 Family of microcontrollers. It is also compatible to a certain extent with members of similar families or subfamilies.

Each package is optimized for the device it houses. Therefore, there may be slight differences between packages of the same pin-count but for different device types. In particular, the size of the Exposed Die Pad may vary.

If different device types are considered or planned for an application, it must be ensured that the board layout fits all packages under consideration.

### 4.1 Package Parameters

**Table 60** provides the thermal characteristics of the packages used in XMC4300.

**Table 60 Thermal Characteristics of the Packages**

| Parameter                                                              | Symbol                 | Limit Values |                  | Unit | Package Types                                                |
|------------------------------------------------------------------------|------------------------|--------------|------------------|------|--------------------------------------------------------------|
|                                                                        |                        | Min.         | Max.             |      |                                                              |
| Exposed Die Pad dimensions including U-Groove                          | $E_x \times E_y$<br>CC | -            | $7.0 \times 7.0$ | mm   | PG-LQFP-100-25                                               |
| Exposed Die Pad dimensions excluding U-Groove                          | $A_x \times A_y$<br>CC | -            | $6.2 \times 6.2$ | mm   | PG-LQFP-100-25                                               |
| Exposed Die Pad dimensions                                             | -                      | -            | $7.0 \times 7.0$ | mm   | PG-LQFP-100-29                                               |
| Thermal resistance<br>Junction-Ambient<br>$T_J \leq 150^\circ\text{C}$ | $R_{\Theta JA}$<br>CC  | -            | 22.5             | K/W  | PG-LQFP-100-25 <sup>1)</sup><br>PG-LQFP-100-29 <sup>1)</sup> |

1) Device mounted on a 4-layer JEDEC board (JESD 51-7) with thermal vias; exposed pad soldered.

*Note: For electrical reasons, it is required to connect the exposed pad to the board ground  $V_{SS}$ , independent of EMC and thermal requirements.*

#### **4.1.1 Thermal Considerations**

When operating the XMC4300 in a system, the total heat generated in the chip must be dissipated to the ambient environment to prevent overheating and the resulting thermal damage.

The maximum heat that can be dissipated depends on the package and its integration into the target board. The “Thermal resistance  $R_{\Theta JA}$ ” quantifies these parameters. The power dissipation must be limited so that the average junction temperature does not exceed 150 °C.

The difference between junction temperature and ambient temperature is determined by  $\Delta T = (P_{INT} + P_{IOSTAT} + P_{IODYN}) \times R_{\Theta JA}$

The internal power consumption is defined as

$$P_{INT} = V_{DDP} \times I_{DDP} \text{ (switching current and leakage current).}$$

The static external power consumption caused by the output drivers is defined as

$$P_{IOSTAT} = \Sigma((V_{DDP} - V_{OH}) \times I_{OH}) + \Sigma(V_{OL} \times I_{OL})$$

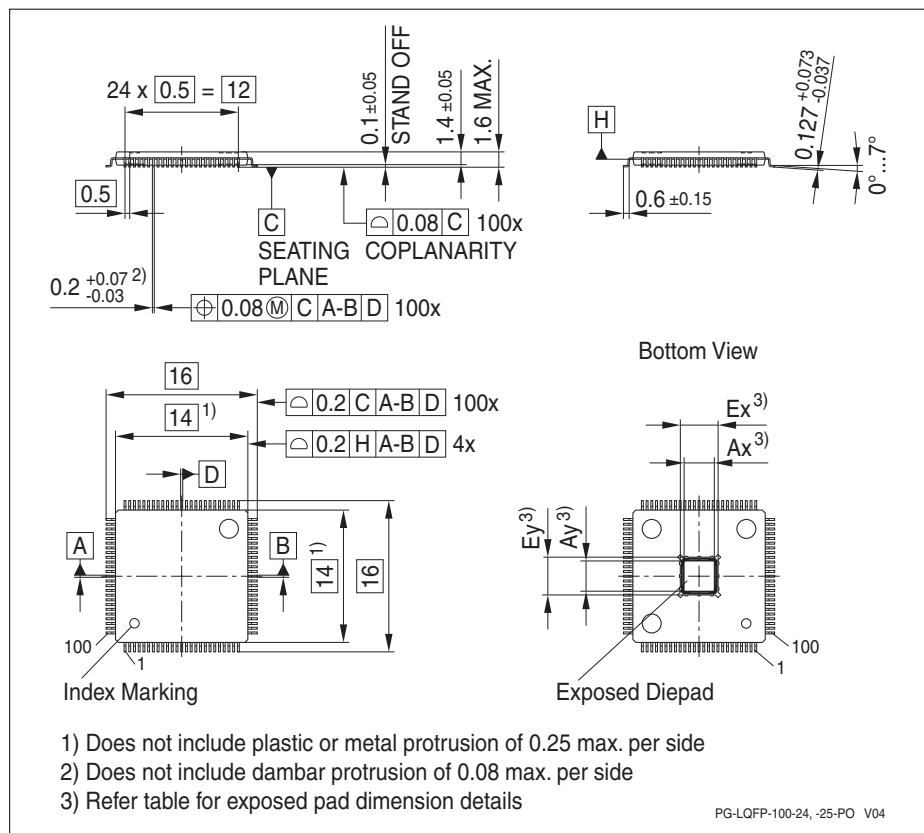
The dynamic external power consumption caused by the output drivers ( $P_{IODYN}$ ) depends on the capacitive load connected to the respective pins and their switching frequencies.

If the total power dissipation for a given system configuration exceeds the defined limit, countermeasures must be taken to ensure proper system operation:

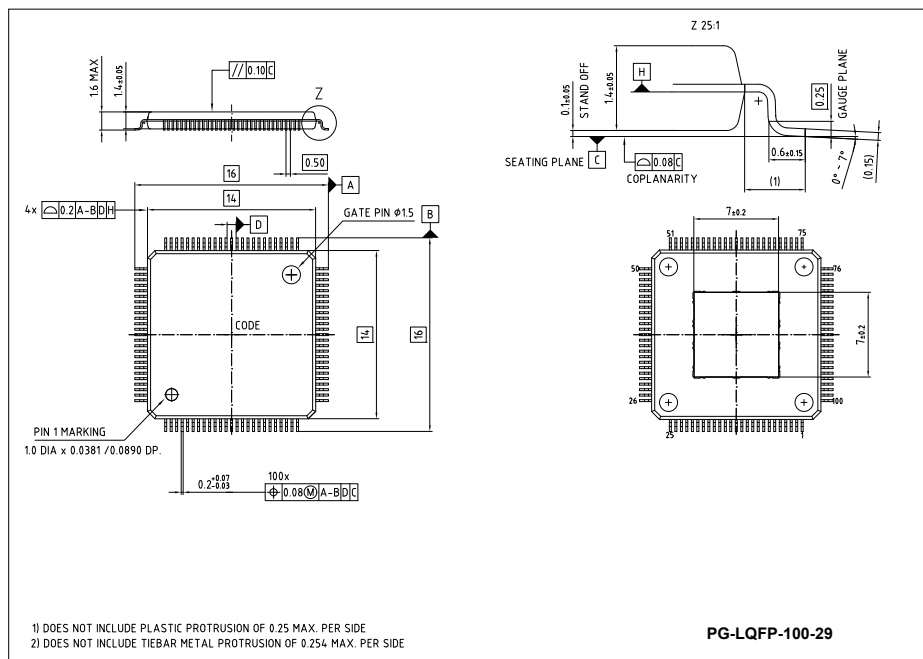
- Reduce  $V_{DDP}$ , if possible in the system
- Reduce the system frequency
- Reduce the number of output pins
- Reduce the load on active output drivers

## 4.2 Package Outlines

The exposed die pad dimensions are listed in **Table 60**.



**Figure 43 PG-LQFP-100-25 (Plastic Green Low Profile Quad Flat Package)**



**Figure 44** PG-LQFP-100-29 (Plastic Green Low Profile Quad Flat Package)

All dimensions in mm.

You can find complete information about Infineon packages, packing and marking in our Infineon Internet Page "Packages": <http://www.infineon.com/packages>

## 5 Quality Declarations

The qualification of the XMC4300 is executed according to the JEDEC standard JESD471.

*Note: For automotive applications refer to the Infineon automotive microcontrollers.*

**Table 61 Quality Parameters**

| Parameter                                                  | Symbol       | Values |      |       | Unit             | Note / Test Condition                                 |
|------------------------------------------------------------|--------------|--------|------|-------|------------------|-------------------------------------------------------|
|                                                            |              | Min.   | Typ. | Max.  |                  |                                                       |
| Operation lifetime                                         | $t_{OP}$ CC  | 20     | –    | –     | a                | $T_J \leq 109^\circ\text{C}$ ,<br>device permanent on |
| ESD susceptibility according to Human Body Model (HBM)     | $V_{HBM}$ SR | –      | –    | 3 000 | V                | EIA/JESD22-A114-B                                     |
| ESD susceptibility according to Charged Device Model (CDM) | $V_{CDM}$ SR | –      | –    | 1 000 | V                | Conforming to JESD22-C101-C                           |
| Moisture sensitivity level                                 | $MSL$ CC     | –      | –    | 3     | –                | JEDEC J-STD-020D                                      |
| Soldering temperature                                      | $T_{SDR}$ SR | –      | –    | 260   | $^\circ\text{C}$ | Profile according to JEDEC J-STD-020D                 |

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